## MPC5676R Microcontroller Data Sheet

On-chip modules available within the family include the following features:

- Two identical dual issue, 32-bit CPU core complexes (e200z7), each with
- Power Architecture embedded specification compliance
- Instruction set enhancement allowing variable length encoding (VLE), optional encoding of mixed 16-bit and 32-bit instructions, for code size footprint reduction
- Signal processing extension (SPE) instruction support for digital signal processing (DSP)
- Single-precision floating point operations (FPU)
- 16 KB I-Cache and 16 KB D-Cache
- Hardware cache coherency between cores
- 16 Hardware semaphores
- 3 channel CRC module
- 6MB on-chip flash
- Supports read during program and erase operations, and multiple blocks allowing EEPROM emulation
- 384 KB on-chip general-purpose SRAM including 48 KB of standby RAM
- Two multi-channel direct memory access controllers (eDMA)
- 64 channels per eDMA
- Dual core Interrupt controller (INTC)
- Phase-locked loop with FM modulation (FMPLL)
- Crossbar switch architecture for concurrent access to peripherals, flash, or RAM from multiple bus masters
- External Bus Interface (EBI) for calibration and application development
- System integration unit (SIU) with error correction status module (ECSM)
- Four protected port output pins (PPO)
- Boot assist module (BAM) supports serial bootload via CAN or SCI
- Three second-generation enhanced time processor units (eTPU2)

- Up to 96 eTPU2 channels (32 channels per eTPU2)
- total of 36 KB code RAM
- total of 9 KB parameter RAM
- Enhanced modular input output system supporting 32 unified channels (eMIOS) with each channel capable of single action, double action, pulse width modulation (PWM) and modulus counter operation
- Two enhanced queued analog-to-digital converter (eQADC) modules with
- two separate analog converters per eQADC module
- support for a total of 64 analog input pins, expandable to 176 inputs with off-chip multiplexers
- one absolute reference ADC channel
- interface to twelve hardware decimation filters
- enhanced ‘Tap’ command to route any conversion to two separate decimation filters
- Temperature sensor
- Five deserial serial peripheral interface (DSPI) modules
- Three enhanced serial communication interface (eSCI) modules
- Four controller area network (FlexCAN) modules
- Dual-channel FlexRay controller
- Nexus development interface (NDI) per IEEE-ISTO 5001-2003 standard, with some support for 2010 standard.
- Device and board test support per Joint Test Action Group (JTAG) (IEEE 1149.1)
- On-chip voltage regulator controller regulates supply voltage down to 1.2 V for core logic
- Self Test capability



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## 1 Ordering Information

### 1.1 Orderable Parts

Figure 1 and Table 1describe and list the orderable part numbers for the MPC5676R.


Temperature Range $\mathrm{M}=-40^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$

Package Identifier
VU = 416 TEPBGA Pb-Free VY = 516 TEPBGA Pb-Free

Operating Frequency
$1=2 \times 180 \mathrm{MHz}$
Tape and Reel Status
$\mathrm{R}=$ Tape and reel (blank) = Trays

Qualification Status
$\mathrm{P}=$ Pre qualification
$M=$ Fully spec. qualified, general market flow $S$ = Fully spec. qualified, automotive flow

Figure 1. MPC5676R Orderable Part Number Description
Table 1. Orderable Part Numbers

| NXP Part Number ${ }^{1}$ | Package Description | Speed (MHz) ${ }^{2}$ |  | Operating Temperature ${ }^{3}$ |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Nominal | $\operatorname{Max}^{4}\left(\mathrm{f}_{\mathrm{MAX}}\right)$ | $\operatorname{Min}\left(\mathrm{T}_{\mathrm{L}}\right)$ | $\operatorname{Max}\left(\mathrm{T}_{\mathrm{H}}\right)$ |
| SPC5676RDK2MVU1R | MPC5676R 416 package Lead-free (Pb-free) | 180 | 184 | $-40^{\circ} \mathrm{C}$ | $125{ }^{\circ} \mathrm{C}$ |
| SPC5676RDK2MVY1R | MPC5676R 516 package Lead-free (Pb-free) | 180 | 184 | $-40^{\circ} \mathrm{C}$ | $125{ }^{\circ} \mathrm{C}$ |

1 All packaged devices are PPC5676R, rather than MPC5676R or SPC5676R, until product qualifications are complete. The unpackaged device prefix is PCC, rather than SCC, until product qualification is complete. Not all configurations are available in the PPC parts.
2 For the operating mode frequency of various blocks on the device, see Table 28.
3 The lowest ambient operating temperature is referenced by $T_{L}$; the highest ambient operating temperature is referenced by $T_{H}$.
4 Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM). 180 MHz parts allow for 180 MHz system clock $+2 \%$ FM.

## MPC5676R Blocks

## 2 MPC5676R Blocks

### 2.1 Block Diagram

The following figure shows a top-level block diagram of the MPC5676R. The purpose of the block diagram is to show the general interconnection of functional modules through the crossbar switch and from the Dual Interrupt Controller, and provide an indication of the modules that connect to external pins. For clarity, the following modules are omitted from the diagram: PMU, SWT, STM, PIT, ECSM, DTS, and CRC.


LEGEND

```
ADC - Analog to Digital Convertor
AMux - Analog Pin Multiplexer
D-Cache - Data Cache
DECFILT - Decimation Filter
DSPI - Deserial/Serial Peripheral Interface
EBI - External Bus Interface
eDMA2 - Enhanced Direct Memory Access controller version 2
eMIOS - Enhanced Modular I/O System
eQADC - Enhanced Queued Analog to Digital Converter
eSCI - Enhanced Serial Communications Interface
eTPU2 - Enhanced Time Processing Unit version 2
FlexCAN-Flexible Controller Area Network controller
FMPLL - Frequency Modulated Phase Lock Loop clock generator
```

I-Cache - Instruction Cache
IRC - Internal RC Oscillator
JTAG - Joint Test Action Group controller
MMU - Memory Management Unit
MPU - Memory Protection Unit
PPO - Protected Port Output
S/B - Stand-by
SIUA - System Integration Unit A
SIUB - System Integration Unit B
SPE - Signal Processing Engine
SRAM - Static RAM
STCU - Self Test Control Unit
VLE - Variable Length instruction Encoding

Figure 2. MPC5676R Block Diagram

## 3 Pin Assignments

### 3.1 416-ball TEPBGA Pin Assignments

Figure 3 shows the 416-ball TEPBGA pin assignments.

## CAUTION

This ball map is preliminary and subject to change. Do not use it for board design.


Figure 3. MPC5676R 416-ball TEPBGA (full diagram)

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## Pin Assignments

### 3.2 516-ball TEPBGA Pin Assignments

Figure 4 shows the 516-ball TEPBGA pin assignments.


Figure 4. MPC5676R 516-ball TEPBGA (full diagram)

### 3.3 Pin Muxing and Reset States

See Appendix A, Signal Properties and Muxing, for a listing and description of the pin functions and properties.

## 4 Electrical Characteristics

This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications for the MPC5676R.
The electrical specifications are preliminary and are from previous designs, design simulations, or initial evaluation. These specifications may not be fully tested or guaranteed at this early stage of the product life cycle, however for production silicon these specifications will be met. Finalized specifications will be published after complete characterization and device qualifications have been completed.

### 4.1 Maximum Ratings

## Table 2. Absolute Maximum Ratings ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max ${ }^{2}$ | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | 1.2 V Core Supply Voltage ${ }^{3}$ | $V_{\text {DD }}$ | -0.3 | $1.65{ }^{4}$ | V |
| 2 | SRAM Standby Voltage | $V_{\text {STBY }}$ | -0.3 | 5.5 ${ }^{\text {5,6 }}$ | V |
| 3 | Clock Synthesizer Voltage | $V_{\text {DDSYN }}$ | -0.3 | $4.5{ }^{6,7}$ | V |
| 4 | I/O Supply Voltage (I/O buffers and predrivers) | $V_{\text {DD33 }}$ | -0.3 | $4.5{ }^{6,7}$ | V |
| 5 | Analog Supply Voltage (reference to $\mathrm{V}_{\text {SSA }}{ }^{8}$ ) | $V_{\text {DDA }}{ }^{9}$ | -0.3 | $5.5^{5,6}$ | V |
| 6 | I/O Supply Voltage (fast I/O pads) | $\mathrm{V}_{\text {DDE }}$ | -0.3 | $4.5{ }^{6}$ | V |
| 7 | I/O Supply Voltage (medium I/O pads) | $V_{\text {DDEH }}$ | -0.3 | $5.5^{5,6}$ | V |
| 8 | Voltage Regulator Input Supply Voltage | $V_{\text {DDREG }}$ | -0.3 | $5.5^{5,6}$ | V |
| 9 | Analog Reference High Voltage (reference to $\mathrm{V}_{\mathrm{RL}}{ }^{10}$ ) | $\mathrm{V}_{\mathrm{RH}}{ }^{11}$ | -0.3 | $5.5^{5,6}$ | V |
| 10 | $\mathrm{V}_{\text {SS }}$ to $\mathrm{V}_{\text {SSA }}{ }^{8}$ Differential Voltage | $V_{S S}-V_{S S A}$ | -0.1 | 0.1 | V |
| 11 | $\mathrm{V}_{\text {REF }}$ Differential Voltage | $\mathrm{V}_{\mathrm{RH}}-\mathrm{V}_{\mathrm{RL}}$ | -0.3 | $5.5^{5,6}$ | V |
| 12 | $\mathrm{V}_{\mathrm{RL}}$ to $\mathrm{V}_{\text {SSA }}$ Differential Voltage | $\mathrm{V}_{\mathrm{RL}}-\mathrm{V}_{\mathrm{SSA}}$ | -0.3 | 0.3 | V |
| 13 | $\mathrm{V}_{\text {DD33 }}$ to $\mathrm{V}_{\text {DDSYN }}$ Differential Voltage | $\mathrm{V}_{\text {DD33 }}-\mathrm{V}_{\text {DDSYN }}$ | -0.1 | 0.1 | V |
| 14 | $\mathrm{V}_{\text {SSSYN }}$ to $\mathrm{V}_{\text {SS }}$ Differential Voltage | $\mathrm{V}_{\text {SSSYN }}-\mathrm{V}_{\text {SS }}$ | -0.1 | 0.1 | V |
| 15 | Maximum Digital Input Current ${ }^{12}$ (per pin, applies to all digital pins) | $\mathrm{I}_{\text {MAXD }}$ | $-3^{13}$ | $3^{13}$ | mA |
| 16 | Maximum Analog Input Current ${ }^{14}$ (per pin, applies to all analog pins) | $I_{\text {MAXA }}$ | $-3^{9,13}$ | $3^{9,13}$ | mA |

## Electrical Characteristics

Table 2. Absolute Maximum Ratings ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | Min | Max ${ }^{2}$ | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 17 | Maximum Operating Temperature Range ${ }^{15}$ - Die Junction Temperature | TJ | -40.0 | 150.0 | ${ }^{\circ} \mathrm{C}$ |
| 18 | Storage Temperature Range | $\mathrm{T}_{\text {stg }}$ | -55.0 | 150.0 | ${ }^{\circ} \mathrm{C}$ |
| 19 | Maximum Solder Temperature ${ }^{16}$ Pb -free package SnPb package | $\mathrm{T}_{\text {sdr }}$ | - | $\begin{aligned} & 260.0 \\ & 245.0 \end{aligned}$ | ${ }^{\circ} \mathrm{C}$ |
| 20 | Moisture Sensitivity Level ${ }^{17}$ | MSL | - | 3 | - |

1 Functional operating conditions are given in the DC electrical specifications. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the listed maxima may affect device reliability or cause permanent damage to the device.
2 Absolute maximum voltages are currently maximum burn-in voltages. Absolute maximum specifications for device stress have not yet been determined.
$31.2 \mathrm{~V} \pm 10 \%$ for proper operation. This parameter is specified at a maximum junction temperature of $150^{\circ} \mathrm{C}$.
42.0 V for 10 hours cumulative time, $1.2 \mathrm{~V}+10 \%$ for time remaining.
${ }^{5} 6.4 \mathrm{~V}$ for 10 hours cumulative time, $5.0 \mathrm{~V}+10 \%$ for time remaining.
6 Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.
74.5 V for 10 hours cumulative time, $3.3 \mathrm{~V}+10 \%$ for time remaining.

8 MPC5676R has two analog power supply pins on the pinout: VDDA_A and VDDA_B.
9 MPC5676R has two analog ground supply pins on the pinout: VSSA_A and VSSA_B.
${ }^{10}$ MPC5676R has two analog low reference voltage pins on the pinout: VRL_A and VRL_B.
${ }^{11}$ MPC5676R has two analog high reference voltage pins on the pinout: VRH_A and VRH_B.
${ }^{12}$ Total injection current for all pins must not exceed 25 mA at maximum operating voltage.
${ }^{13}$ Injection current of $\pm 5 \mathrm{~mA}$ allowed for limited duration for analog (ADC) pads and digital 5 V pads. The maximum accumulated time at this current shall be 60 hours. This includes an assumption of a 5.25 V maximum analog or $\mathrm{V}_{\text {DDEH }}$ supply when under this stress condition.
${ }^{14}$ Total injection current for all analog input pins must not exceed 15 mA .
${ }^{15}$ Lifetime operation at these specification limits is not guaranteed.
${ }^{16}$ Solder profile per CDF-AEC-Q100.
${ }^{17}$ Moisture sensitivity per JEDEC test method A112.

### 4.2 Thermal Characteristics

Table 3. Thermal Characteristics, 416-pin TEPBGA Package ${ }^{1}$

| Characteristic | Symbol | Value | Unit |
| :--- | :---: | :---: | :---: |
| Junction to Ambient ${ }^{2,3}$ Natural Convection (Single layer board) | $\mathrm{R}_{\theta \mathrm{JA}}$ | 24 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Ambient ${ }^{2,4}$ Natural Convection (Four layer board 2s2p) | $\mathrm{R}_{\theta \mathrm{JAA}}$ | 16 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Ambient (@200 ft./min., Single layer board) | $\mathrm{R}_{\theta \mathrm{JMA}}$ | 18 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

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Table 3. Thermal Characteristics, 416-pin TEPBGA Package ${ }^{1}$ (continued)

| Characteristic | Symbol | Value | Unit |
| :---: | :---: | :---: | :---: |
| Junction to Ambient (@200 ft./min., Four layer board 2s2p) | $\mathrm{R}_{\text {өJMA }}$ | 13 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Board ${ }^{5}$ | $\mathrm{R}_{\theta \mathrm{JB}}$ | 8 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Case ${ }^{6}$ | $\mathrm{R}_{\text {өJC }}$ | 4 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Package Top ${ }^{7}$ Natural Convection | $\Psi_{J T}$ | 3 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

1 Thermal characteristics are targets based on simulation that are subject to change per device characterization.
2 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
3 Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.
4 Per JEDEC JESD51-6 with the board horizontal.
5 Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
6 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.
7 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

Table 4. Thermal Characteristics, 516-pin TEPBGA Package ${ }^{1}$

| Characteristic | Symbol | Value | Unit |
| :--- | :---: | :---: | :---: |
| Junction to Ambient ${ }^{2,3}$ Natural Convection (Single layer board) | $\mathrm{R}_{\theta \mathrm{JAA}}$ | 24 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Ambient ${ }^{2,4}$ Natural Convection (Four layer board 2s2p) | $\mathrm{R}_{\theta \mathrm{JA}}$ | 17 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Ambient (@200 ft./min., Single layer board) | $\mathrm{R}_{\theta \mathrm{JMA}}$ | 19 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Ambient (@200 ft./min., Four layer board 2s2p) | $\mathrm{R}_{\theta \mathrm{JMA}}$ | 14 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Board ${ }^{5}$ | $\mathrm{R}_{\theta \mathrm{JB}}$ | 9 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Case ${ }^{6}$ | $\mathrm{R}_{\theta \mathrm{JCC}}$ | 5 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction to Package Top $^{7}$ Natural Convection | $\Psi_{\text {JT }}$ | 2 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

1 Thermal characteristics are targets based on simulation that are subject to change per device characterization.
2 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
3 Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.
4 Per JEDEC JESD51-6 with the board horizontal.
5 Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
6 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

## Electrical Characteristics

7 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

### 4.2.1 General Notes for Specifications at Maximum Junction Temperature

An estimation of the chip junction temperature, $\mathrm{T}_{\mathrm{J}}$, can be obtained from the equation:

$$
\begin{equation*}
T_{J}=T_{A}+\left(R_{\theta J A} * P_{D}\right) \tag{Eqn. 1}
\end{equation*}
$$

where:
$\mathrm{T}_{\mathrm{A}}=$ ambient temperature for the package $\left({ }^{\circ} \mathrm{C}\right)$
$R_{\theta J A}=$ junction to ambient thermal resistance ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
$\mathrm{P}_{\mathrm{D}}=$ power dissipation in the package $(\mathrm{W})$
The junction to ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. Unfortunately, there are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. For packages such as the TEPBGA, these values can be different by a factor of two. Which value is closer to the application depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$
\begin{equation*}
\mathbf{R}_{\theta \mathrm{JA}}=\mathbf{R}_{\theta \mathrm{JC}}+\mathbf{R}_{\theta \mathrm{CA}} \tag{Eqn. 2}
\end{equation*}
$$

where:
$\mathrm{R}_{\theta \mathrm{JA}}=$ junction to ambient thermal resistance ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
$\mathrm{R}_{\theta \mathrm{JC}}=$ junction to case thermal resistance $\left({ }^{\circ} \mathrm{C} / \mathrm{W}\right)$
$\mathrm{R}_{\theta \mathrm{CA}}=$ case to ambient thermal resistance ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
$\mathrm{R}_{\theta \mathrm{JC}}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance, $\mathrm{R}_{\theta \mathrm{CA}}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device.

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter ( $\Psi_{\mathrm{JT}}$ ) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$
\begin{equation*}
\mathrm{T}_{\mathrm{J}}=\mathrm{T}_{\mathrm{T}}+\left(\Psi_{\mathrm{JT}} \times \mathrm{P}_{\mathrm{D}}\right) \tag{Eqn. 3}
\end{equation*}
$$

where:
$\mathrm{T}_{\mathrm{T}}=$ thermocouple temperature on top of the package ( ${ }^{\circ} \mathrm{C}$ )
$\Psi_{\mathrm{JT}}=$ thermal characterization parameter ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
$\mathrm{P}_{\mathrm{D}}=$ power dissipation in the package (W)
The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type $T$ thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm . of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

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## References:

Semiconductor Equipment and Materials International
3081 Zanker Road
San Jose, CA 95134
(408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the WEB at http://www.jedec.org.

- C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47-54.
- G. Kromann, S. Shidore, and S. Addison, "Thermal Modeling of a PBGA for Air-Cooled Applications," Electronic Packaging and Production, pp. 53-58, March 1998.
- B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212-220.


### 4.3 EMI (Electromagnetic Interference) Characteristics

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions, go to www.nxp.com and perform a keyword search for "radiated emissions." The following tables list the values of the device's radiated emissions operating behaviors.

Table 5. EMC Radiated Emissions Operating Behaviors: 416 BGA

| Symbol | Description | Conditions | $\begin{aligned} & f_{\mathrm{OSC}} \\ & \mathrm{f}_{\mathrm{SYS}} \end{aligned}$ | Frequency band (MHz) | Level (max.) | Unit | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {RE_TEM }}$ | Radiated emissions, electric field and magnetic field | $\begin{gathered} \mathrm{V}_{\mathrm{DD}}=1.2 \mathrm{~V} \\ \mathrm{~V}_{\mathrm{DDE}}=3.3 \mathrm{~V} \\ \mathrm{~V}_{\mathrm{DDEH}}=5 \mathrm{~V} \\ \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C} \\ 416 \mathrm{BGA} \\ \text { EBI off } \\ \text { CLK off } \\ \text { FM off } \end{gathered}$ | $\begin{gathered} 40 \mathrm{MHz} \text { crystal } \\ 180 \mathrm{MHz} \\ \left(\mathrm{f}_{\mathrm{EBI} / \mathrm{CAL}}=46\right. \\ \overline{\mathrm{MHz}} \text { ) } \end{gathered}$ | 0.15-50 | 26 | $\mathrm{dB} \mu \mathrm{V}$ | 1 |
|  |  |  |  | 50-150 | 30 |  |  |
|  |  |  |  | 150-500 | 34 |  |  |
|  |  |  |  | 500-1000 | 30 |  |  |
|  |  |  |  | IEC and SAE level | $1^{2}$ | - | 1,3 |
| $V_{\text {RE_TEM }}$ | Radiated emissions, electric field and magnetic field | $\mathrm{V}_{\mathrm{DD}}=1.2 \mathrm{~V}$ <br> $\mathrm{V}_{\text {DDE }}=3.3 \mathrm{~V}$ <br> $V_{\text {DDEH }}=5 \mathrm{~V}$ <br> $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ <br> 416 BGA <br> EBI off <br> CLK off <br> FM on ${ }^{4}$ | $\begin{gathered} 40 \mathrm{MHz} \text { crystal } \\ 180 \mathrm{MHz} \\ \left(\mathrm{f}_{\text {EBI_CAL }}=46\right. \\ \overline{\mathrm{MHz}}) \end{gathered}$ | 0.15-50 | 24 | $\mathrm{dB} \mu \mathrm{V}$ | 1 |
|  |  |  |  | 50-150 | 25 |  |  |
|  |  |  |  | 150-500 | 25 |  |  |
|  |  |  |  | 500-1000 | 21 |  |  |
|  |  |  |  | IEC and SAE level | $\mathrm{K}^{5}$ | - | 1,3 |

1 Determined according to IEC Standard 61967-2, Measurement of Radiated Emissions-TEM Cell and Wideband TEM Cell Method, and SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits-TEM/Wideband TEM (GTEM) Cell Method.
$2 \mathrm{I}=36 \mathrm{~dB} \mu \mathrm{~V}$
3 Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions-TEM Cell and Wideband TEM Cell Method, and Appendix D of SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits-TEM/Wideband TEM (GTEM) Cell Method.
4 "FM on" = FM depth of $\pm 2 \%$
${ }^{5} \mathrm{~K}=30 \mathrm{~dB} \mu \mathrm{~V}$

## Electrical Characteristics

### 4.4 ESD Characteristics

Table 6. ESD Ratings ${ }^{1,2}$

| Spec | Characteristic | Symbol | Value | Unit |
| :---: | :--- | :---: | :---: | :---: |
| 1 | ESD for Human Body Model (HBM) | $\mathrm{V}_{\mathrm{HBM}}$ | 2000 | V |
| 2 | ESD for Charged Device Model (CDM) | $\mathrm{V}_{\text {CDM }}$ | 750 (corners) <br> 500 (other) | V |

1 All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.
2 A device will be defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing shall be performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

### 4.5 PMC/POR/LVI Electrical Specifications

Table 7. PMC Operating conditions

| Spec | Name | Parameter | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | $V_{\text {DDREG }}$ | Supply voltage VDDREG 5 V nominal ${ }^{1}$ | LDO5V / SMPS5V mode | 4.5 | 5 | 5.5 | V |
| 2 | $\mathrm{V}_{\text {DDREG }}$ | Supply voltage VDDREG 3 V nominal ${ }^{1}$ | LDO3V mode | 3.0 | 3.3 | 3.6 | V |
| 3 | $\mathrm{V}_{\text {DD33 }}$ | Supply voltage VDDSYN / $V_{\text {DD33 }} 3.3 \mathrm{~V}$ nominal ${ }^{2}$ | LDO3V mode | 3.0 | 3.3 | 3.6 | V |
| 4 | $\mathrm{V}_{\mathrm{DD}}$ | Supply voltage VDD 1.2 V nominal ${ }^{3}$ | - | 1.14 | 1.2 | 1.32 | V |

${ }^{1}$ Voltage should be higher than maximum $\mathrm{V}_{\text {LVDREG }}$ to avoid LVD event
${ }^{2}$ Applies to both $\mathrm{V}_{\text {DD33 }}$ (flash supply) and VDDSYN (PLL supply) pads. Voltage should be higher than maximum $\mathrm{V}_{\text {LVD33 }}$ to avoid LVD event
${ }^{3}$ Voltage should be higher than maximum $\mathrm{V}_{\mathrm{LVD12}}$ to avoid LVD event

## NOTE

In the following table, "untrimmed" means "at reset" and "trimmed" means "after reset".
Table 8. PMC Electrical Specifications

| Spec | Name | Symbol | Condition | Min | Typ | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Nominal bandgap reference <br> voltage | $\mathrm{V}_{\mathrm{BG}}$ | - | 0.59 | 0.620 | 0.65 | V |
| 1 a | Bandgap reference voltage <br> during power on reset | - | - | $\mathrm{V}_{\mathrm{BG}}-5 \%$ | $\mathrm{~V}_{\mathrm{BG}}$ | $\mathrm{V}_{\mathrm{BG}}+5 \%$ | V |
| 1 b | Bandgap reference voltage at <br> nominal voltage / nominal <br> temperature after power on <br> reset | - | - | $\mathrm{V}_{\mathrm{BG}}-2 \%$ | $\mathrm{~V}_{\mathrm{BG}}$ | $\mathrm{V}_{\mathrm{BG}}+2 \%$ | V |

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Table 8. PMC Electrical Specifications

| Spec | Name | Symbol | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1c | Bandgap reference voltage / temperature dependence after power on reset | - | - | - | 300 | - | ppm/C |
| 1d | Bandgap reference voltage / voltage dependence ( $\mathrm{V}_{\text {DDREG }}$ ) after power on reset | - | - | - | 1500 | - |  |
| 2 | Nominal VRC regulated 1.2V output VDD ${ }^{1}$ | $\mathrm{V}_{\text {DD120UT }}$ | - | - | 1.2 | - | V |
| 2a | VRC 1.2V output variation at reset (unloaded) ${ }^{2}$ | - | At POR | $\mathrm{V}_{\text {DD12OUT }}-8 \%$ | $\mathrm{V}_{\text {DD12OUT }}$ | $\mathrm{V}_{\text {DD12OUT }}+10 \%$ |  |
| 2b | VRC 1.2 V output variation after reset(REGCTL load max. 20mA, VDD load max. 1A) | - | After POR | $\mathrm{V}_{\text {DD12OUT }}-5 \%$ | $\mathrm{V}_{\text {DD12OUT }}$ | $\mathrm{V}_{\text {DD12OUT }}+10 \%$ |  |
| 2c | Trimming step Vdd1p2 | $\mathrm{V}_{\text {STEPV12 }}$ | - | - | 10 | - | mV |
| 3 | POR rising VDD 1.2V | $\mathrm{V}_{\text {PORC }}$ | - | - | 0.7 | - | V |
| 3 a | POR VDD 1.2V variation | - | - | $\mathrm{V}_{\text {PORC }}-30 \%$ | $\mathrm{V}_{\text {PORC }}$ | $\mathrm{V}_{\text {PORC }}+30 \%$ |  |
| 3b | POR 1.2V hysteresis | - | - | - | 75 | - | mV |
| 4 | Nominal rising LVD $1.2 \mathrm{~V}^{3}$ | $\mathrm{V}_{\text {LVD12 }}$ | - | - | 1.100 | - | V |
| 4 a | LVD 1.2V variation before band gap trim ${ }^{4}$ | - | At POR | $\mathrm{V}_{\text {LVD12 }}-6 \%$ | $\mathrm{V}_{\text {LVD12 }}$ | $\mathrm{V}_{\mathrm{LVD12}}+6 \%$ |  |
| 4b | LVD 1.2V variation after band gap trim ${ }^{4}$ | - | After POR | $\mathrm{V}_{\text {LVD12 }}-3 \%$ | $\mathrm{V}_{\text {LVD12 }}$ | $\mathrm{V}_{\mathrm{LVD12}}+3 \%$ |  |
| 4c | LVD 1.2V Hysteresis | - | - | 15 | 20 | 25 | mV |
| 4d | Trimming step LVD 1.2V | $\mathrm{V}_{\text {LVDSTEP12 }}$ | - | - | 10 | - | mV |
| 5 | VRC 1.2V max DC output current | $\mathrm{I}_{\text {REGCTL }}$ | - | - | - | 20 | mA |
| 6 | Voltage regulator 1.2 V current consumption VDDREG | - | - | - | 3 | - | mA |
| 7 | Nominal Vreg 3.3V output ${ }^{5}$ | $\mathrm{V}_{\text {DD330UT }}$ | - | - | 3.3 | - | V |
| 7a | Vreg 3.3V output variation at reset (unloaded) ${ }^{6}$ | - | At POR | $\mathrm{V}_{\text {DD330UT }}-6 \%$ | $\mathrm{V}_{\text {DD330UT }}$ | $\mathrm{V}_{\text {DD330UT }}+10 \%$ |  |
| 7b | Vreg 3.3V output variation after reset (max. load 60mA) | - | After POR | $\mathrm{V}_{\text {DD33OUT }}-5 \%$ | $\mathrm{V}_{\text {DD330UT }}$ | $\mathrm{V}_{\text {DD33OUT }}+10 \%$ |  |
| 7c | Trimming step VDDSYN | $\mathrm{V}_{\text {STEPV33 }}$ | - | - | 30 | - | mV |
| 8 | Nominal rising LVD 3.3V ${ }^{7}$ | $\mathrm{V}_{\text {LVD33 }}$ | - | - | 2.950 | - | V |
| 8 a | LVD 3.3V variation before band gap trim ${ }^{6}$ | - | At POR | $\mathrm{V}_{\text {LVD } 33}-5 \%$ | $\mathrm{V}_{\text {LVD33 }}$ | $\mathrm{V}_{\text {LVD33 }}+5 \%$ |  |
| 8b | LVD 3.3V variation after bad gap trim ${ }^{6}$ | - | After POR | $\mathrm{V}_{\text {LVD } 33}-3 \%$ | $\mathrm{V}_{\text {LVD33 }}$ | $\mathrm{V}_{\text {LVD } 33}+3 \%$ |  |

## Electrical Characteristics

Table 8. PMC Electrical Specifications

| Spec | Name | Symbol | Condition | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 8 c | LVD 3.3V Hysteresis | - | - | - | 30 | - | mV |
| 8d | Trimming step LVD 3.3V | V ${ }_{\text {LVDSTEP33 }}$ | - | - | 30 | - | mV |
| 9 | Vreg 3.3V minimum peak DC output current supplied by regulator without causing $V_{\text {LVD33 }}{ }^{8}$ | IDD33 | - | 60 | - | - | mA |
| 10 | Voltage regulator 3.3 V current consumption VDDREG ${ }^{9}$ | - | - | - | 2 | - | mA |
| 11 | POR rising on VDDREG | $V_{\text {Porreg }}$ | - | - | 2.00 | - | V |
| 11a | POR VDDREG variation | - | - | $V_{\text {PORREG }}-30 \%$ | VPorreg | $\mathrm{V}_{\text {PORREG }}+30 \%$ |  |
| 11b | POR VDDREG hysteresis | - | - | - | 250 | - | mV |
| 12 | Nominal rising LVD VDDREG | $\mathrm{V}_{\text {LVDREG }}$ | LDO3V / <br> LDO5V <br> mode | - | 2.950 | - | V |
| 12a | LVD VDDREG variation at reset ${ }^{10}$ | - | At POR | $\mathrm{V}_{\text {LVDREG }}-5 \%$ | V LVDREG | $\mathrm{V}_{\text {LVDREG }}+5 \%$ |  |
| 12b | LVD VDDREG variation after reset ${ }^{10}$ | - | After POR | V ${ }_{\text {LVDREG }}$ - 3\% | V LVDREG | $\mathrm{V}_{\text {LVDREG }}+3 \%$ |  |
| 12c | LVD VDDREG Hysteresis | - | $\begin{gathered} \text { LDO3V / } \\ \text { LDO5V } \\ \text { mode } \end{gathered}$ | - | 30 | - | mV |
| 12d | Trimming step LVD VDDREG | V LVDSTEPREG | $\begin{gathered} \text { LDO3V / } \\ \text { LDO5V } \\ \text { mode } \end{gathered}$ | - | 30 | - | mV |
| 13 | Nominal rising LVD VDDREG | V ${ }_{\text {LVDREG }}$ | SMPS5V mode | - | 4.360 | - | V |
| 13a | LVD VDDREG variation at reset ${ }^{10}$ | - | At POR | $\mathrm{V}_{\text {LVDREG }}-5 \%$ | V LVDREG | $\mathrm{V}_{\text {LVDREG }}+5 \%$ |  |
| 13b | LVD VDDREG variation after reset ${ }^{10}$ | - | After POR | V ${ }_{\text {LVDREG }}$ - 3\% | V LVDREG | $\mathrm{V}_{\text {LVDREG }}+3 \%$ |  |
| 14 | SMPS regulator output resistance ${ }^{11}$ | - | - | - | 15 | 25 | Ohm |
| 15 | SMPS regulator clock frequency | - | After POR | 1.0 | 1.5 | - | MHz |
| 16 | SMPS regulator overshoot at start-up ${ }^{12}$ | - | GBD/GBC ${ }^{13}$ | - | 1.32 | 1.4 | V |
| 17 | SMPS maximum output current, as required by $\mathrm{SoC}^{14}$ | - | - | - | 1.0 | - | A |
| 18 | Voltage variation on current step ( $20 \%$ to $80 \%$ of maximum current with 4 usec constant time) ${ }^{14}$ | - | GBD/GBC ${ }^{13}$ | - | - | 0.1 | V |

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1 Nominal internal regulator output voltage is 1.27 V
2 Voltage should be higher than maximum VLVD12 to avoid LVD event
3 ~VDD12OUT *0.87
4 Rising VDD
${ }^{5}$ Nominal internal regulator output voltage is 3.4 V
${ }^{6}$ Rising VDDSYN
7 ~VDD33OUT *0.872
8 VDDSYN
9 Except IDD33
${ }^{10}$ Rising VDDREG
${ }^{11}$ Pull up to VDDREG when high, pull down to VSSREG when low.
${ }^{12}$ Depends on external device, can be as high as 1.6 V for short time ( $<100$ usec each start-up)
${ }^{13}$ GBD — Guaranteed By Design; GBC — Guaranteed by Characterization
${ }^{14}$ Proper external devices required

### 4.5.1 Regulator Example



Figure 5. VRC 1.2 V LDO configuration with external bipolar

## Electrical Characteristics



No VRCCTL capacitor is allowed
Figure 6. VRC 1.2V buck SMPS LDO configuration with external MOS - Schottky diode
Table 9. VRC LDO recommended external devices

| Part Name | Part Type | Nominal | Description |
| :---: | :---: | :---: | :---: |
| NJD2873 <br> Beta ( Bf ) <br> Vbe <br> Vce | NPN <br> Capacitor | $6 \times 4.7$ uF-20 V | ON Semiconductor TM <br> From 60 to 550 <br> From 0.4 V to 1.0 V <br> From 0.2 V to 0.6 V depends on package / power <br> Ceramic low ESR—One for each VDD pin |
|  | Capacitor | $6 \times 0.1$ uF-20 V | Ceramic -One capacitor for each VDD pin |
|  | Capacitor | 20 uF | Supply decoupling cap (close to bipolar collector) |
|  | Capacitor | 2.2 uF | Snubber cap, required with NJD2873 (on bipolar base) |
|  | Resistor | $12 \Omega$ | Optional ESR for snubber cap |

Table 10. VRC SMPS recommended external devices

| Part Name | Part Type | Nominal | Description |
| :---: | :---: | :---: | :---: |
| IR7353 <br> SS8P3L <br> Vf <br> SI3460 or equivalent <br> Vth <br> Ids <br> Vds <br> Rdson <br> Cg <br> Turn on / off delay <br> Rise time | HS nMOS + Schottky Schottky <br> nMOS |  | Low threshold n-MOS/Low Vf Schottky diode <br> Low Vf Schottky diode <br> From 0.4 V to 0.6 V <br> Low threshold n-MOS <br> Less than 2 V <br> More than 1.5 A <br> More than 12 V <br> Less than 100 Ohms <br> Less than 5 nF <br> Less than 50 ns <br> Less than 90 ns |
| LQH66SN2R2M03 | inductor | $2.2 \mathrm{uH}-3.2 \mathrm{~A}$ | muRata TM shielded coil, preferred $\mathrm{f}_{\max }>40 \mathrm{MHz}$ |
| C3225X7R1E106M | capacitor | $22 \mathrm{uF}-25 \mathrm{~V}$ | TDK high capacitance ceramic SMD (on VDD close to coil) |
| C3225X7R1E225K | capacitor | $\begin{aligned} & 2 \text { to } 6 \times 2.2 \mathrm{uF} \\ & -25 \mathrm{~V} \end{aligned}$ | TDK ceramic SMD (on VDD close to MCU) |
|  | capacitor | $\begin{gathered} 6 \times 0.1 u F \\ -20 \mathrm{~V} \end{gathered}$ | Ceramic -One capacitor for each VDD pin |
| C3225X7R1E106M | capacitor | $22 \mathrm{uF}-25 \mathrm{~V}$ | Supply decoupling cap-close to n-MOS drain |
|  | resistor | 20 K | Pull down for power n-MOS gate |

### 4.6 Power Up/Down Sequencing

There is no power sequencing required among power sources during power up and power down in order to operate within specification as long as the following two rules are met:

- When VDDREG is tied to a nominal 3.3V supply, VDD33 and VDDSYN must be both shorted to VDDREG.
- When VDDREG is tied to a 5V supply, VDD33 and VDDSYN must be tied together and shall be powered by the internal 3.3V regulator.

The recommended power supply behavior is as follows: Use $25 \mathrm{~V} /$ millisecond or slower rise time for all supplies. Power up each $V_{\text {DDE }} / V_{\text {DDEH }}$ first and then power up $V_{D D}$. For power down, drop $V_{D D}$ to 0 V first, and then drop all $V_{\text {DDE }} / V_{\text {DDEH }}$ supplies. There is no limit on the fall time for the power supplies.

Although there are no power up/down sequencing requirements to prevent issues like latch-up, excessive current spikes, etc., the state of the I/O pins during power up/down varies according to Table 11 and Table 12.

## Electrical Characteristics

Table 11. Power Sequence Pin States for MH and AE pads

| VDD | VDD33 | VDDE | MH Pad | MH+LVDS Pads ${ }^{1}$ | AE/up-down Pads |
| :---: | :---: | :---: | :---: | :---: | :---: |
| High | High | High | Normal operation | Normal operation | Normal operation |
| - | Low | High | Pin is tri-stated (output buffer, <br> input buffer, and weak pulls <br> disabled) | Outputs driven high | Pull-ups enabled, <br> pull-downs disabled |
| Low | High | Low | Output low, <br> pin unpowered | Outputs disabled | Output low, <br> pin unpowered |
| Low | High | High | Pin is tri-stated (output buffer, <br> input buffer, and weak pulls <br> disabled) | Outputs disabled | Pull-ups enabled, <br> pull-downs disabled |

${ }^{1} \mathrm{MH}+$ LVDS pads are output-only.

Table 12. Power Sequence Pin States for F and FS pads

| VDD | VDD33 | VDDE | F and FS pads |
| :---: | :---: | :---: | :---: |
| low | low | high | Outputs drive high |
| low | high | - | Outputs Disabled |
| high | low | low | Outputs Disabled |
| high | low | high | Outputs drive high |
| high | high | low | Normal operation - except no drive current <br> and input buffer output is unknown. ${ }^{1}$ |
| high | high | high | Normal Operation |

1 The pad pre-drive circuitry will function normally but since VDDE is unpowered the outputs will not drive high even though the output pmos can be enabled.

### 4.6.1 Power-Up

If $\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\mathrm{DDEH}}$ is powered up first, then a threshold detector tristates all drivers connected to $\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\mathrm{DDEH}}$. There is no limit to how long after $\mathrm{V}_{\text {DDE }} / \mathrm{V}_{\text {DDEH }}$ powers up before $\mathrm{V}_{\mathrm{DD}}$ must power up. If there are multiple $\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\text {DDEH }}$ supplies, they can be powered up in any order. For each $V_{\text {DDE }} / V_{\text {DDEH }}$ supply not powered up, the drivers in that $V_{\text {DDE }} / V_{\text {DDEH }}$ segment exhibit the characteristics described in the next paragraph.
If $\mathrm{V}_{\mathrm{DD}}$ is powered up first, then all pads are loaded through the drain diodes to $\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\mathrm{DDEH}}$. This presents a heavy load that pulls the pad down to a diode above $\mathrm{V}_{\mathrm{SS}}$. Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after $V_{D D}$ powers up before $V_{\text {DDE }} / V_{\text {DDEH }}$ must power up.
The rise times on the power supplies are to be no faster than $25 \mathrm{~V} /$ millisecond.

### 4.6.2 Power-Down

If $V_{D D}$ is powered down first, then all drivers are tristated. There is no limit to how long after $V_{D D}$ powers down before $\mathrm{V}_{\text {DDE }} / \mathrm{V}_{\text {DDEH }}$ must power down.
If $V_{\text {DDE }} / V_{\text {DDEH }}$ is powered down first, then all pads are loaded through the drain diodes to $V_{D D E} / V_{\text {DDEH }}$. This presents a heavy load that pulls the pad down to a diode above $\mathrm{V}_{\mathrm{SS}}$. Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after $\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\mathrm{DDEH}}$ powers down before $\mathrm{V}_{\mathrm{DD}}$ must power down.

There are no limits on the fall times for the power supplies.

### 4.6.3 Power Sequencing and POR Dependent on $V_{\text {DDA }}$

During power up or down, $\mathrm{V}_{\text {DDA }}$ can lag other supplies (of magnitude greater than $\mathrm{V}_{\mathrm{DDEH}} / 2$ ) within 1 V to prevent any forward-biasing of device diodes that causes leakage current and/or POR. If the voltage difference between $V_{\text {DDA }}$ and $V_{\text {DDEH }}$ is more than 1 V , the following will result:

- Triggers POR (ADC monitors on $V_{\text {DDEH1 }}$ segment which powers the RESET pin) if the leakage current path created, when $V_{\text {DDA }}$ is sufficiently low, causes sufficient voltage drop on $V_{\text {DDEH1 }}$ node monitored crosses low-voltage detect level.
- If $\mathrm{V}_{\mathrm{DDA}}$ is between $0-2 \mathrm{~V}$, powering all the other segments (especially $\mathrm{V}_{\mathrm{DDEH}}$ ) will not be sufficient to get the part out of reset.
- Each $\mathrm{V}_{\text {DDEH }}$ will have a leakage current to $\mathrm{V}_{\mathrm{DDA}}$ of a magnitude of $\left(\left(\mathrm{V}_{\mathrm{DDEH}}-\mathrm{V}_{\mathrm{DDA}}-1 \mathrm{~V}\right.\right.$ (diode drop)/200 KOhms) up to $\left(\mathrm{V}_{\mathrm{DDEH}} / 2=\mathrm{V}_{\mathrm{DDA}}+1 \mathrm{~V}\right)$. .
- Each $\mathrm{V}_{\mathrm{DD}}$ has the same behavior; however, the leakage will be small even though there is no current limiting resistor since $\mathrm{V}_{\mathrm{DD}}=1.32 \mathrm{~V}$ max.


### 4.7 DC Electrical Specifications

Table 13. DC Electrical Specifications ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Core Supply Voltage (External Regulation) | $V_{\text {DD }}$ | 1.14 | $1.32^{2,3}$ | V |
| 1 a | Core Supply Voltage (Internal Regulation) ${ }^{4}$ | $V_{\text {DD }}$ | 1.08 | 1.32 | V |
| 2 | I/O Supply Voltage (fast I/O pads) | $\mathrm{V}_{\text {DDE }}$ | 3.0 | $3.6{ }^{2}$ | V |
| 3 | I/O Supply Voltage (medium I/O pads) | $V_{\text {DDEH }}$ | 3.0 | $5.25^{2}$ | V |
| 4 | 3.3 V I/O Buffer Voltage | $V_{\text {DD33 }}$ | 3.0 | $3.6{ }^{2}$ | V |
| 5 | Analog Supply Voltage | $V_{\text {DDA }}$ | 4.75 | $5.25{ }^{2}$ | V |
| 6a | SRAM Standby Voltage low range | $V_{\text {STBY_LOW }}$ | $0.95{ }^{5}$ | 1.2 | V |
| 6b | SRAM Standby Voltage high range | $\mathrm{V}_{\text {STBY_HIGH }}$ | 2 | 6 | V |
| 7 | Voltage Regulator Control Input Voltage ${ }^{6}$ | $V_{\text {DDREG }}$ | $2.7^{7}$ | $5.5^{2}$ | V |
| 8 | Clock Synthesizer Operating Voltage ${ }^{8}$ | $V_{\text {DDSYN }}$ | 3.0 | $3.6{ }^{2}$ | V |
| 9 | Fast I/O Input High Voltage Hysteresis enabled Hysteresis disabled | $\mathrm{V}_{\text {IH_F }}$ | $\begin{aligned} & 0.65 \times V_{\mathrm{DDE}} \\ & 0.55 \times \mathrm{V}_{\mathrm{DDE}} \end{aligned}$ | $V_{\text {DDE }}+0.3$ | V |
| 10 | Fast I/O Input Low Voltage Hysteresis enabled Hysteresis disabled | VIL_F | $\mathrm{V}_{\text {SS }}-0.3$ | $\begin{aligned} & 0.35 \times V_{\text {DDE }} \\ & 0.40 \times V_{\text {DDE }} \end{aligned}$ | V |
| 11 | Medium I/O Input High Voltage Hysteresis enabled Hysteresis disabled | $\mathrm{V}_{\mathrm{IH} \text { _S }}$ | $\begin{aligned} & 0.65 \times V_{\text {DDEH }} \\ & 0.55 \times V_{\text {DDEH }} \end{aligned}$ | $\mathrm{V}_{\text {DDEH }}+0.3$ | V |

## Electrical Characteristics

Table 13. DC Electrical Specifications ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 12 | Medium I/O Input Low Voltage Hysteresis enabled Hysteresis disabled | $\mathrm{V}_{\text {IL_S }}$ | $\mathrm{V}_{\text {SS }}-0.3$ | $\begin{aligned} & 0.35 \times V_{\text {DDEH }} \\ & 0.40 \times V_{\text {DDEH }} \end{aligned}$ | V |
| 13 | Fast I/O Input Hysteresis | $\mathrm{V}_{\text {HYS_F }}$ | $0.1 \times \mathrm{V}_{\text {DDE }}$ | - | V |
| 14 | Medium I/O Input Hysteresis | $\mathrm{V}_{\text {HYS_S }}$ | $0.1 \times V_{\text {DDEH }}$ | - | V |
| 15 | Analog Input Voltage | $V_{\text {INDC }}$ | $\mathrm{V}_{\text {SSA }}-0.1$ | $\mathrm{V}_{\mathrm{DDA}}+0.1$ | V |
| 16 | Fast I/O Output High Voltage ${ }^{9}$ | $\mathrm{V}_{\text {OH_F }}$ | $0.8 \times V_{\text {DDE }}$ | - | V |
| 17 | Medium I/O Output High Voltage ${ }^{10}$ | $\mathrm{V}_{\mathrm{OH}+\mathrm{S}}$ | $0.8 \times \mathrm{V}_{\text {DDEH }}$ | - | V |
| 18 | Fast I/O Output Low Voltage ${ }^{9}$ | $\mathrm{V}_{\text {OL_F }}$ | - | $0.2 \times V_{\text {DDE }}$ | V |
| 19 | Medium I/O Output Low Voltage | $\mathrm{V}_{\text {OL_S }}$ | - | $\begin{gathered} 0.2 \times V_{0} V_{\text {DDEH }}{ }^{1} \\ 0.15 \times V_{\text {DDEH }} \end{gathered}$ | V |
| 20 |  | $\mathrm{C}_{\mathrm{L}}$ | - | $\begin{aligned} & 10 \\ & 20 \\ & 30 \\ & 50 \end{aligned}$ | $\begin{aligned} & \mathrm{pF} \\ & \mathrm{pF} \\ & \mathrm{pF} \\ & \mathrm{pF} \end{aligned}$ |
| 21 | Input Capacitance (Digital Pins) | $\mathrm{C}_{\text {IN }}$ | - | 7 | pF |
| 22 | Input Capacitance (Analog Pins) | $\mathrm{C}_{\text {IN_A }}$ | - | 10 | pF |
| 23 | Input Capacitance (Digital and Analog Pins ${ }^{13}$ ) | $\mathrm{C}_{\text {IN_M }}$ | - | 12 | pF |
| 24 | Operating Current 1.2 V Supplies @ $\mathrm{f}_{\text {sys }}=180 \mathrm{MHz}$ <br> $\mathrm{V}_{\mathrm{DD}}$ (including $\mathrm{V}_{\text {DDF }}$ current)@1.32 V <br> $\mathrm{V}_{\text {STBY }}{ }^{14} @ 1.2 \mathrm{~V}$ and $85^{\circ} \mathrm{C}$ <br> $\mathrm{V}_{\text {STBY }} @ 6.0 \mathrm{~V}$ and $85^{\circ} \mathrm{C}$ <br> $V_{D D F}{ }^{15}$ (P/E) <br> $\mathrm{V}_{\mathrm{DDF}}{ }^{15}$ (Read) <br> $\mathrm{V}_{\mathrm{DDF}^{15}}$ (RWW) <br> $\mathrm{V}_{\mathrm{DDF}}{ }^{15}$ (Standby) <br> $\mathrm{V}_{\mathrm{DDF}}{ }^{15}$ (Disabled) | $I_{D D}$ <br> $I_{\text {DDSTBY }}$ <br> ImDStBy6 <br> $l_{\text {DDFPE }}$ <br> I DDFREAD <br> IDDFRWW <br> IDDpITANDBY <br> I DDFDISABLED | - - - - - | $\begin{gathered} 1.0^{16} \\ 0.10 \\ 0.15 \\ 36^{17} \\ 50^{17} \\ 90^{17} \\ 0.20^{17} \\ 0.10^{17} \end{gathered}$ | A <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA |
| 25 | $\begin{aligned} & \text { Operating Current } 3.3 \mathrm{~V} \text { Supplies @ } \mathrm{f}_{\text {sys }}=180 \mathrm{MHz} \\ & \mathrm{~V}_{\mathrm{DD} 33}{ }^{18} \\ & \mathrm{~V}_{\mathrm{DDSYN}}{ }^{19}(\mathrm{P} / \mathrm{E}) \\ & \mathrm{V}_{\text {FLASH }}^{19} \\ & \mathrm{~V}_{\mathrm{FLASH}}^{19} \\ & \mathrm{~V}_{\mathrm{FLASH}}^{19} \\ & \mathrm{~V}_{\mathrm{FLASH}}(\mathrm{Read}) \\ & \mathrm{V}_{\mathrm{FLASH}}{ }^{19}(\text { Standby }) \\ & (\text { Disabled }) \end{aligned}$ | $I_{\text {DD33 }}$ <br> IDDSYN <br> IDDFLASHPE <br> IDDFLASHREADS <br> IDDFLASHRWw <br> I IDFLASHSTANDBY <br> IDDFLASHDISABLED | - - - | $\begin{aligned} & \text { note }^{18} \\ & 7^{20} \\ & 32^{21} \\ & 6.4^{21} \\ & 40^{21} \\ & 3.4^{21} \\ & 0.10^{21} \end{aligned}$ | mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA |
| 26 | Operating Current 5.0 V Supplies $@ \mathrm{f}_{\text {sys }}=180 \mathrm{MHz}$ <br> $V_{\text {DDA }}$ <br> Analog Reference Supply Current (Transient) <br> $V_{\text {DDREG }}$ | $\begin{aligned} & \mathrm{I}_{\mathrm{DDA}} \\ & \mathrm{I}_{\mathrm{REF}} \\ & \mathrm{I}_{\mathrm{REG}} \end{aligned}$ | - | $\begin{gathered} 50^{22} \\ 1.0 \\ 22 \end{gathered}$ | mA <br> mA <br> mA |

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Table 13. DC Electrical Specifications ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 27 | ```Operating Current \(\mathrm{V}_{\mathrm{DDE}} / \mathrm{V}_{\mathrm{DDEH}}{ }^{23}\) Supplies \(V_{\text {DDE2 }}\) \(V_{\text {DDEH1 }}\) \(V_{\text {DDEH3 }}\) \(V_{\text {DDEH4 }}\) \(V_{\text {DDEH5 }}\) \(V_{\text {DDEH6 }}\) \(V_{\text {DDEH7 }}\)``` | $I_{\text {DD2 }}$ <br> $I_{D D 1}$ <br> $I_{\text {DD3 }}$ <br> $I_{D D 4}$ <br> $I_{\text {DD5 }}$ <br> $\mathrm{I}_{\mathrm{DD6}}$ <br> $I_{\text {DD7 }}$ | - - - - - | note ${ }^{23}$ | mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA |
| 28 | Fast I/O Weak Pull Up/Down Current ${ }^{24}$ 3.0 V-3.6 V | $\mathrm{I}_{\text {ACT_F }}$ | 42 | 158 | $\mu \mathrm{A}$ |
| 29 | ```Medium I/O Weak Pull Up/Down Current }\mp@subsup{}{}{25 3.0 V-3.6 V 4.5 V-5.5 V``` | $\mathrm{I}_{\text {ACt_S }}$ | $\begin{aligned} & 15 \\ & 35 \end{aligned}$ | $\begin{gathered} 95 \\ 200 \end{gathered}$ | $\begin{aligned} & \mu \mathrm{A} \\ & \mu \mathrm{~A} \end{aligned}$ |
| 30 | I/O Input Leakage Current ${ }^{26}$ | $I_{\text {INACT_D }}$ | -2.5 | 2.5 | $\mu \mathrm{A}$ |
| 31 | DC Injection Current (per pin) | $l_{\text {IC }}$ | -1.0 | 1.0 | mA |
| 32 | Analog Input Current, Channel Off ${ }^{27}$, AN[0:7], AN38, AN39 <br> Analog Input Current, Channel Off, all other analog inputs $A N[x]=-/+150 n A$ | IINACT_A | $\begin{aligned} & -250 \\ & -150 \end{aligned}$ | $\begin{aligned} & 250 \\ & 150 \end{aligned}$ | nA <br> nA |
| 33 | $\mathrm{V}_{\text {SS }}$ Differential Voltage | $V_{S S}-V_{S S A}$ | -100 | 100 | mV |
| 34 | Analog Reference Low Voltage | $\mathrm{V}_{\mathrm{RL}}$ | $\mathrm{V}_{\text {SSA }}$ | $V_{S S A}+100$ | mV |
| 35 | $\mathrm{V}_{\mathrm{RL}}$ Differential Voltage | $\mathrm{V}_{\mathrm{RL}}-\mathrm{V}_{\mathrm{SSA}}$ | -100 | 100 | mV |
| 36 | Analog Reference High Voltage | $\mathrm{V}_{\mathrm{RH}}$ | $V_{\text {DDA }}-100$ | $V_{\text {DDA }}$ | mV |
| 37 | $\mathrm{V}_{\text {REF }}$ Differential Voltage | $\mathrm{V}_{\mathrm{RH}}-\mathrm{V}_{\mathrm{RL}}$ | 4.75 | 5.25 | V |
| 38 | $\mathrm{V}_{\text {SSSYN }}$ to $\mathrm{V}_{\text {SS }}$ Differential Voltage | $\mathrm{V}_{\text {SSSYN }}-\mathrm{V}_{\text {SS }}$ | -100 | 100 | mV |
| 39 | Operating Temperature Range—Ambient (Packaged) | $\mathrm{T}_{\mathrm{A}}\left(\mathrm{T}_{\mathrm{L}}\right.$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$ | -40.0 | 125.0 | ${ }^{\circ} \mathrm{C}$ |
| 40 | Slew rate on power supply pins | - | - | 25 | V/ms |
| 41 | Weak Pull-Up/Down Resistance ${ }^{28,29} 200 \mathrm{k} \Omega$ Option | $\mathrm{R}_{\text {PUPD200K }}$ | 130 | 280 | k $\Omega$ |
| 42 | Weak Pull-Up/Down Resistance ${ }^{28,29} 100 \mathrm{k} \Omega$ Option | $\mathrm{R}_{\text {PUPD100K }}$ | 65 | 140 | $\mathrm{k} \Omega$ |
| 43 | ```Weak Pull-Up/Down Resistance \({ }^{28}\) (5 k \(\Omega\) Option) \(5 \mathrm{~V} \pm 10 \%\) supply \(3.3 \mathrm{~V} \pm 10 \%\) supply``` | $\mathrm{R}_{\text {PUPD5K }}$ | $\begin{aligned} & 1.4 \\ & 1.7 \end{aligned}$ | $\begin{aligned} & 5.2 \\ & 7.7 \end{aligned}$ | $\mathrm{k} \Omega$ |
| 44 | Pull-Up/Down Resistance Matching Ratios (100K/200K) <br> (Pull-up and pull-down resistances both enabled and settings are equal) | R PUPDMATCH | -2.5 | 2.5 | \% |

1 These specifications are design targets and subject to change per device characterization.
2 Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.
32.0 V for 10 hours cumulative time, $1.2 \mathrm{~V}+10 \%$ for time remaining.

## Electrical Characteristics

4 Assumed with DC load.
${ }^{5} \mathrm{~V}_{\text {STBY }}$ below 0.95 V the RAM will not retain states, but will be operational. $\mathrm{V}_{\text {STBY }}$ can be 0 V when bypass standby mode.
${ }^{6}$ Regulator is functional with derated performance, with supply voltage down to 4.0 V for system with $V_{\text {DDREG }}=4.5 \mathrm{~V}(\mathrm{~min})$.
72.7 V minimum operating voltage allowed during vehicle crank for system with $\mathrm{V}_{\text {DDREG }}=3.0 \mathrm{~V}$ (min). Normal operating voltage should be either $\mathrm{V}_{\text {DDREG }}=3.0 \mathrm{~V}(\mathrm{~min})$ or $4.5 \mathrm{~V}(\mathrm{~min})$ depending on the user regulation voltage system selected.
8 Required to be supplied when 3.3 V regulator is disabled. See Section 4.5, "PMC/POR/LVI Electrical Specifications."
$9 \mathrm{I}_{\mathrm{OH} \text { F }}=\{12,20,30,40\} \mathrm{mA}$ and $\mathrm{I}_{\mathrm{OL} \_\mathrm{F}}=\{24,40,50,65\} \mathrm{mA}$ for $\{00,01,10,11\}$ drive mode with $\mathrm{V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$.
${ }^{10} \mathrm{I}_{\mathrm{OH} \text { _S }}=\{11.6\} \mathrm{mA}$ and $\mathrm{IOL} \mathrm{S}=\{17.7\} \mathrm{mA}$ for $\{$ medium $\} \mathrm{I} / \mathrm{O}$ with $\mathrm{V}_{\mathrm{DDEH}}=4.5 \mathrm{~V}$;
$\mathrm{I}_{\mathrm{OH} \_\mathrm{S}}=\{5.4\} \mathrm{mA}$ and $\mathrm{IOL} \_\mathrm{S}=\{8.1\} \mathrm{mA}$ for $\{$ medium $\} \mathrm{I} / \mathrm{O}$ with $\mathrm{V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$
${ }^{11} \mathrm{I}_{\mathrm{OL} \text { _s }}=2 \mathrm{~mA}$
${ }^{12}$ Applies to D_CLKOUT, external bus pins, and Nexus pins.
${ }^{13}$ Applies to the FCK, SDI, SDO, and SDS_B pins.
${ }^{14} \mathrm{~V}_{\text {STBY }}$ current specified at 1.0 V at a junction temperature of $85^{\circ} \mathrm{C}$. $\mathrm{V}_{\text {STBY }}$ current is $700 \mu \mathrm{~A}$ maximum at a junction temperature of $150^{\circ} \mathrm{C}$.
${ }^{15}$ VDDF pin is shorted to $V_{D D}$ on the package substrate.
${ }^{16}$ Preliminary. Specification pending typical and/or high-use Runidd pattern simulation as well as final silicon characterization. 1.0 A based on transistor count estimate at Worst Case (wcs) process and temperature condition.
${ }^{17}$ Typical values from the simulation.
${ }^{18}$ Power requirements for the $\mathrm{V}_{\mathrm{DD} 33}$ supply depend on the frequency of operation and load of all I/O pins, and the voltages on the I/O segments. See Section 4.7.2, "I/O Pad $\mathrm{V}_{\mathrm{DD} 33}$ Current Specifications," for information on both fast (F, FS) and medium $(\mathrm{MH})$ pads. Also refer to Table 15 for values to calculate power dissipation for specific operation.
${ }^{19} \mathrm{VFLSH}$ pin is shorted to $\mathrm{V}_{\text {DD33 }}$ on the package substrate.
${ }^{20}$ This value is a target that is subject to change.
${ }^{21}$ Typical values from the simulation.
${ }^{22}$ These value allows a 5 V 20 mA reference to supply ADC + REF.
${ }^{23}$ Power requirements for each I/O segment depend on the frequency of operation and load of the I/O pins on a particular I/O segment, and the voltage of the I/O segment. See Section 4.7.1, "I/O Pad Current Specifications," for information on I/O pad power. Also refer to Table 14 for values to calculate power dissipation for specific operation. The total power consumption of an I/O segment is the sum of the individual power consumptions for each pin on the segment.
${ }^{24}$ Absolute value of current, measured at $\mathrm{V}_{\mathrm{IL}}$ and $\mathrm{V}_{\mathrm{IH}}$.
${ }^{25}$ Absolute value of current, measured at $\mathrm{V}_{\mathrm{IL}}$ and $\mathrm{V}_{\mathrm{IH}}$.
${ }^{26}$ Weak pull up/down inactive. Measured at $\mathrm{V}_{\text {DDE }}=3.6 \mathrm{~V}$ and $\mathrm{V}_{\text {DDEH }}=5.25 \mathrm{~V}$. Applies to pad types F and MH .
${ }^{27}$ Maximum leakage occurs at maximum operating temperature. Leakage current decreases by approximately one-half for each 8 to $12{ }^{\circ} \mathrm{C}$, in the ambient temperature range of 50 to $125^{\circ} \mathrm{C}$. Applies to pad types AE and $\mathrm{AE} / \mathrm{up}$-down.
${ }^{28}$ This programmable option applies only to eQADC differential input channels and is used for biasing and sensor diagnostics.
${ }^{29}$ When the pull-up and pull-down of the same nominal $200 \mathrm{k} \Omega$ or $100 \mathrm{k} \Omega$ value are both enabled, assuming no interference from external devices, the resulting pad voltage will be $0.5^{*} \mathrm{~V}_{\text {DDEH }} \pm 2.5 \%$.

### 4.7.1 I/O Pad Current Specifications

The power consumption of an I/O segment is dependent on the usage of the pins on a particular segment. The power consumption is the sum of all output pin currents for a particular segment. The output pin current can be calculated from Table 14 based on the voltage, frequency, and load on the pin. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in Table 14.

The AC timing of these pads are described in the Section 4.11.2, "Pad AC Specifications."

Table 14. $\mathrm{V}_{\text {DDE }} / \mathrm{V}_{\text {DDEH }}$ I/O Pad Average DC Current ${ }^{1}$

| Spec | Pad Type | Symbol | Frequency (MHz) | $\begin{gathered} \text { Load }^{2} \\ (\mathrm{pF}) \end{gathered}$ | Voltage <br> (V) | Drive/Slew Rate Select | Current (mA) |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Medium | $\mathrm{I}_{\text {DRV_MH }}$ | 50 | 50 | 5.25 | 11 | 16.0 |
| 2 |  |  | 20 | 50 | 5.25 | 01 | 6.3 |
| 3 |  |  | 3.0 | 50 | 5.25 | 00 | 1.1 |
| 4 |  |  | 2.0 | 200 | 5.25 | 00 | 2.4 |
| 5 | Fast | I DRV_FC | 66 | 10 | 3.6 | 00 | 6.5 |
| 6 |  |  | 66 | 20 | 3.6 | 01 | 9.4 |
| 7 |  |  | 66 | 30 | 3.6 | 10 | 10.8 |
| 8 |  |  | 66 | 50 | 3.6 | 11 | 33.3 |
| 9 |  |  | 66 | 10 | 1.98 | 00 | 2.0 |
| 10 |  |  | 66 | 20 | 1.98 | 01 | 3.0 |
| 11 |  |  | 66 | 30 | 1.98 | 10 | 4.4 |
| 12 |  |  | 66 | 50 | 1.98 | 11 | 15.1 |
| 13 | Fast w/ Slew Control | I DRV_FSR | 66 | 50 | 3.6 | 11 | 12.0 |
| 14 |  |  | 50 | 50 | 3.6 | 10 | 6.2 |
| 15 |  |  | 33.33 | 50 | 3.6 | 01 | 4.0 |
| 16 |  |  | 20 | 50 | 3.6 | 00 | 2.4 |
| 17 |  |  | 20 | 200 | 3.6 | 00 | 8.9 |

1 These are average IDDE numbers for worst case PVT from simulation. Currents apply to output pins only.
2 All loads are lumped.

### 4.7.2 I/O Pad VDD33 Current Specifications

The power consumption of the $\mathrm{V}_{\mathrm{DD} 33}$ supply is dependent on the usage of the pins on all I/O segments. The power consumption is the sum of all input and output pin $\mathrm{V}_{\mathrm{DD33}}$ currents for all I/O segments. The $\mathrm{V}_{\mathrm{DD} 33}$ current draw on fast speed pads can be calculated from Table 15 dependent on the voltage, frequency, and load on all $F$ type pins. The $V_{\text {DD33 }}$ current draw on medium pads can be calculated from Table 15 dependent on voltage and independent on the frequency and load on all MH type pins. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in Table 15.

The AC timing of these pads are described in the Section 4.11.2, "Pad AC Specifications."

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Table 15. $\mathrm{V}_{\text {DD33 }}$ Pad Average DC Current ${ }^{1}$

| Spec | Pad Type | Symbol | Frequency (MHz) | $\begin{gathered} \mathrm{Load}^{2} \\ (\mathrm{pF}) \end{gathered}$ | $V_{\text {DD33 }}$ <br> (V) | $V_{\text {DDE }}$ <br> (V) | Drive/Slew Rate Select | Current (mA) |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Medium | $\mathrm{I}_{33} \mathrm{MH}$ | - | - | 3.6 | 5.5 | - | 0.0007 |
| 2 | Fast | $\mathrm{I}_{33}$ FC | 66 | 10 | 3.6 | 3.6 | 00 | 0.92 |
| 3 |  |  | 66 | 20 | 3.6 | 3.6 | 01 | 1.14 |
| 4 |  |  | 66 | 30 | 3.6 | 3.6 | 10 | 1.50 |
| 5 |  |  | 66 | 50 | 3.6 | 3.6 | 11 | 2.19 |
| 6 |  |  | 66 | 10 | 3.6 | 1.98 | 00 | 0.70 |
| 7 |  |  | 66 | 20 | 3.6 | 1.98 | 01 | 0.90 |
| 8 |  |  | 66 | 30 | 3.6 | 1.98 | 10 | 1.08 |
| 9 |  |  | 66 | 50 | 3.6 | 1.98 | 11 | 1.52 |
| 10 | Fast w/ Slew Control | I33_FSR | 66 | 50 | 3.6 | 3.6 | 11 | 0.74 |
| 11 |  |  | 50 | 50 | 3.6 | 3.6 | 10 | 0.52 |
| 12 |  |  | 33.33 | 50 | 3.6 | 3.6 | 01 | 0.36 |
| 13 |  |  | 20 | 50 | 3.6 | 3.6 | 00 | 0.19 |
| 14 |  |  | 20 | 200 | 3.6 | 3.6 | 00 | 0.19 |

1 These are average IDD33 for worst case PVT from simulation. Currents apply to output pins only for the fast pads and to input pins only for the medium pads.
2 All loads are lumped.

### 4.7.3 LVDS Pad Specifications

LVDS pads are implemented to support the MSC (Microsecond Channel) protocol, which is an enhanced feature of the DSPI module.

Table 16. DSPI LVDS Pad Specification ${ }^{1,2}$
$\left(\mathrm{V}_{\mathrm{DD} 33}=3.0 \mathrm{~V}\right.$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$

| Spec | Characteristic | Symbol | Min | Typical | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Data Rate |  |  |  |  |  |  |
| 1 | Data Frequency | $\mathrm{f}_{\text {LVDSCLK }}$ | - | - | 40 | MHz |
| Driver Specs |  |  |  |  |  |  |
| 2 | $\begin{aligned} & \text { Differential Output Voltage } \\ & \text { SRC=0b00 or 0b11 } \\ & \text { SRC=0b01 } \\ & \text { SRC=0b10 } \end{aligned}$ | $\mathrm{V}_{\mathrm{OD}}$ | $\begin{aligned} & 215 \\ & 170 \\ & 260 \end{aligned}$ | - | $\begin{aligned} & 400 \\ & 320 \\ & 480 \end{aligned}$ | mV |
| 3 | Common Mode Voltage (LVDS), VOS | $\mathrm{V}_{\mathrm{OS}}$ | 1.075 | 1.2 | 1.325 | V |
| 4 | Rise/Fall Time | $t_{R}$ or $t_{F}$ | - | - | 2.5 | ns |
| 5 | Delay, Z to Normal (High/Low) | $\mathrm{t}_{\mathrm{DZ}}$ | - | - | 100 | ns |

Table 16. DSPI LVDS Pad Specification ${ }^{1,2}$ (continued)
$\left(\mathrm{V}_{\mathrm{DD} 33}=3.0 \mathrm{~V}\right.$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$

| 6 | Differential Skew between Positive and Negative LVDS Pair $\mid t_{\text {phla }}-t_{\text {plhb }} I \text { or } I t_{\text {plhb }}-t_{\text {phla }} I$ | ${ }^{\text {Skew }}$ | - | - | 0.5 | ns |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Termination |  |  |  |  |  |  |
| 7 | Termination Resistance ${ }^{3}$ | $\mathrm{R}_{\text {Load }}$ | 95 | 100 | 105 | ohm |
| 8 | Load | - | - | - | 32 | pF |

1 These are typical values that are estimated from simulation.
2 These specifications are subject to change per device characterization.
3 The termination resistance spec is not meant to specify the receiver termination requirements. They are there to establish the measurement criteria for the specs in this table. As per the TIA/EIA-644A standard, the LVDS receiver termination resistance can vary from 90 to $132 \Omega$.

### 4.8 Oscillator and FMPLL Electrical Characteristics

> Table 17. FMPLL Electrical Specifications ${ }^{1}$
> $\left(\mathrm{~V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}\right.$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=\mathrm{V}_{\mathrm{SSSYN}}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | PLL Reference Frequency Range ${ }^{2}$ (Normal Mode) <br> Crystal Reference $($ PLLCFG2 $=0 b 0)$ <br> Crystal Reference (PLLCFG2 = 0b1) <br> External Reference (PLLCFG2 = 0b0) <br> External Reference (PLLCFG2 = 0b1) | $f_{\text {ref_crystal }}$ <br> $\mathrm{f}_{\text {ref_crystal }}$ $f_{\text {ref_ext }}$ $f_{\text {ref_ext }}$ | $\begin{gathered} 8 \\ 40 \\ 8 \\ 40 \end{gathered}$ | $\begin{gathered} 20 \\ 40^{3} \\ 20 \\ 40 \end{gathered}$ | MHz |
| 2 | PLL Frequency ${ }^{4}$ Enhanced Mode | $\mathrm{f}_{\mathrm{PLL}}$ | $\mathrm{f}_{\mathrm{vco}(\text { min })} \div 64$ | $\mathrm{f}_{\text {max }}$ | MHz |
| 3 | Loss of Reference Frequency ${ }^{5}$ | $\mathrm{f}_{\text {LOR }}$ | 100 | 1000 | kHz |
| 4 | Self Clocked Mode Frequency ${ }^{6}$ | $\mathrm{f}_{\text {SCM }}$ | 4 | 16 | MHz |
| 5 | PLL Lock Time ${ }^{7}$ | $\mathrm{t}_{\text {LPLL }}$ | - | <750 | $\mu \mathrm{S}$ |
| 6 | Duty Cycle of Reference ${ }^{\text {8, } 9}$ | $t_{\text {DC }}$ | 40 | 60 | \% |
| 7 | Frequency un-LOCK Range | $\mathrm{f}_{\mathrm{UL}}$ | -4.0 | 4.0 | \% $\mathrm{f}_{\text {sys }}$ |
| 8 | Frequency LOCK Range | $\mathrm{f}_{\text {LCK }}$ | -2.0 | 2.0 | \% $\mathrm{f}_{\text {sys }}$ |
| 9 | D_CLKOUT Period Jitter ${ }^{10,11}$ Measured at $\mathrm{f}_{\text {SYS }}$ Max Cycle-to-cycle Jitter | $\mathrm{C}_{\text {Jitter }}$ | -5 | 5 | $\begin{gathered} \text { \%f }_{\text {Clko }} \\ \text { ut } \end{gathered}$ |
| 10 | Peak-to-Peak Frequency Modulation Range Limit ${ }^{12,13}$ ( $\mathrm{f}_{\text {sys }}$ Max must not be exceeded) | $\mathrm{C}_{\text {mod }}$ | 0 | 4 | \%fsys |
| 11 | FM Depth Tolerance ${ }^{14}$ | $\mathrm{C}_{\text {mod_err }}$ | -0.25 | 0.25 | \%f sys |
| 12 | VCO Frequency | $\mathrm{f}_{\mathrm{Vco}}$ | 192 | 600 | MHz |
| 13 | Modulation Rate Limits ${ }^{15}$ | $\mathrm{f}_{\text {mod }}$ | 0.400 | 1 | MHz |
| 14 | Predivider Operating Frequency | $\mathrm{f}_{\text {prediv }}$ | 4 | 10 | MHz |

## Electrical Characteristics

1 All values given are initial design targets and subject to change.
2 Crystal and External reference frequency limits depend on device relying on PLL to lock prior to release of reset, default PREDIV/EPREDIV, MFD/EMFD default settings, and VCO frequency range. Absolute minimum loop frequency is 4 MHz .
3 Upper tolerance of less than $1 \%$ is allowed on 40 MHz crystal.
${ }^{4}$ All internal registers retain data at 0 Hz .
5 "Loss of Reference Frequency" is the reference frequency detected internally, which transitions the PLL into self clocked mode.
6 Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below f $\mathrm{f}_{\text {LOR }}$. This frequency is measured at D_CLKOUT with the divider set to divide-by-2 of the system clock. NOTE: in SCM, the PLL is running open loop at a centercode $0 \times 4$. The MFD has no effect and the RFD is bypassed.
7 This specification applies to the period required for the PLL to re-lock after changing the MFD frequency control bits in the synthesizer control register (SYNCR). From power up with crystal oscillator reference, lock time will be additive with crystal startup time.
8 For FlexRay operation, duty cycle requirements are higher.
9 Duty cycle can be $20-80 \%$ when PLL is used with a pre-divider greater than 1.
${ }^{10}$ Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum $f_{\text {sys }}$. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via $\mathrm{V}_{\text {DDSYN }}$ and $\mathrm{V}_{\text {SSSYN }}$ and variation in crystal oscillator frequency increase the Cjitter percentage for a given interval. D_CLKOUT divider set to divide-by-2.
${ }^{11}$ Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of $\mathrm{C}_{\mathrm{jitter}}+\mathrm{C}_{\text {mod }}$.
${ }^{12}$ Modulation depth selected must not result in $f_{\text {pll }}$ value greater than the $f_{\text {pll }}$ maximum specified value.
${ }^{13}$ Maximum and minimum variation from programmed modulation depth is pending characterization. Depth settings available in control register are: $1 \%, 2 \%, 3 \%$, and $4 \%$ peak-to-peak.
${ }^{14}$ Depth tolerance is the programmed modulation depth $\pm 0.25 \%$ of $\mathrm{F}_{\text {sys. }}$. Initial design target pending silicon evaluation.
${ }^{15}$ Modulation rates less than 400 kHz will result in exceedingly long FM calibration durations. Modulation rates greater than 1 MHz will result in reduced calibration accuracy.

Table 18. Oscillator Electrical Specifications ${ }^{1}$
$\left(\mathrm{V}_{\text {DDSYN }}=3.0 \mathrm{~V}\right.$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=\mathrm{V}_{\mathrm{SSSYN}}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Crystal Mode Differential Amplitude ${ }^{2}$ <br> (Min differential voltage between EXTAL and XTAL) | $\mathrm{V}_{\text {crystal_diff_amp }}$ | $\begin{gathered} \left\|V_{\text {extal }}-V_{x t a l}\right\| \\ >0.4 \mathrm{~V} \end{gathered}$ | - | V |
| 2 | Crystal Mode: Internal Differential Amplifier Noise Rejection | $\mathrm{V}_{\text {crystal_dift_amp_nr }}$ | - | $\begin{gathered} \left\|V_{\text {extal }}-V_{\text {xtal }}\right\| \\ <0.2 \mathrm{~V} \end{gathered}$ | V |
| 3 | EXTAL Input High Voltage Bypass mode, External Reference | $\mathrm{V}_{\text {IHEXT }}$ | $\left(\left(\mathrm{V}_{\mathrm{DD} 33} / 2\right)+0.4 \mathrm{~V}\right)$ | - | V |
| 4 | EXTAL Input Low Voltage Bypass mode, External Reference | $\mathrm{V}_{\text {ILEXT }}$ | - | $\left(\mathrm{V}_{\mathrm{DD} 33} / 2\right)-0.4 \mathrm{~V}$ | V |
| 5 | XTAL Current ${ }^{3}$ | $\mathrm{I}_{\text {XTAL }}$ | 1 | 3 | mA |
| 6 | Total On-chip stray capacitance on XTAL | $\mathrm{C}_{\text {S_XTAL }}$ | - | 1.5 | pF |

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Table 18. Oscillator Electrical Specifications ${ }^{1}$ (continued)
$\left(\mathrm{V}_{\text {DDSYN }}=3.0 \mathrm{~V}\right.$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{SS}}=\mathrm{V}_{\mathrm{SSSYN}}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\left.\mathrm{T}_{\mathrm{H}}\right)$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 7 | Total On-chip stray capacitance on EXTAL | $\mathrm{C}_{\text {S_EXTAL }}$ | - | 1.5 | pF |
| 8 | Crystal manufacturer's recommended capacitive load | $\mathrm{C}_{\mathrm{L}}$ | See crystal spec | See crystal spec | pF |
| 9 | Discrete load capacitance to be connected to EXTAL | $\mathrm{C}_{\mathrm{L}_{-} \mathrm{EXTAL}}$ | - | $\begin{gathered} \left(2 \times C_{L}-C_{S \_E X T A}\right. \\ L-C_{P C B} \text { EXTAL } \end{gathered}$ | pF |
| 10 | Discrete load capacitance to be connected to XTAL | $\mathrm{C}_{\text {L_XTAL }}$ | - | $\begin{gathered} \left(2 \times C_{L}-C_{S-X T A L}\right. \\ \left.-C_{P C B \_}{ }^{4} \text { TAL }\right) \end{gathered}$ | pF |

1 All values given are initial design targets and subject to change.
2 This parameter is meant for those who do not use quartz crystals or resonators, but instead use CAN oscillators in crystal mode. In that case, $\mathrm{V}_{\text {extal }}-\mathrm{V}_{\mathrm{xtal}} \geq 400 \mathrm{mV}$ criterion has to be met for oscillator's comparator to produce output clock.
$\mathrm{I}_{\mathrm{xtal}}$ is the oscillator bias current out of the XTAL pin with both EXTAL and XTAL pins grounded.
${ }^{4} \mathrm{C}_{\text {PCB_EXTAL }}$ and $\mathrm{C}_{\text {PCB_XTAL }}$ are the measured PCB stray capacitances on EXTAL and XTAL, respectively.

## 4.9 eQADC Electrical Characteristics

Table 19. eQADC Conversion Specifications (Operating)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | ADC Clock (ADCLK) Frequency | $\mathrm{f}_{\text {ADCLK }}$ | 2 | 16 | MHz |
| 2 | Conversion Cycles | CC | $2+13$ | $128+14$ | ADCLK cycles |
| 3 | Stop Mode Recovery Time ${ }^{1}$ | $\mathrm{T}_{\text {SR }}$ | 10 | - | $\mu \mathrm{S}$ |
| 4 | Resolution ${ }^{2}$ | - | 1.25 | - | mV |
| 5 | INL: 8 MHz ADC Clock $^{3}$ | INL8 | $-4^{4}$ | $4^{4}$ | $\mathrm{LSB}^{5}$ |
| 6 | INL: $16 \mathrm{MHz} \mathrm{ADC} \mathrm{Clock}{ }^{3}$ | INL16 | $-8^{4}$ | $8^{4}$ | LSB |
| 7 | DNL: $8 \mathrm{MHz} \mathrm{ADC} \mathrm{Clock}{ }^{3}$ | DNL8 | $-3^{4}$ | $3^{4}$ | LSB |
| 8 | DNL: 16 MHz ADC Clock ${ }^{3}$ | DNL16 | $-3^{4}$ | $3^{4}$ | LSB |
| 9 | Offset Error without Calibration | OFFNC | 04 | 1004 | LSB |
| 10 | Offset Error with Calibration | OFFWC | $-4^{4}$ | $4^{4}$ | LSB |
| 11 | Full Scale Gain Error without Calibration | GAINNC | $-120^{4}$ | $0^{4}$ | LSB |
| 12 | Full Scale Gain Error with Calibration | GAINWC | $-4^{4,6}$ | $4^{4,6}$ | LSB |
| 13 | Disruptive Input Injection Current ${ }^{\text {7, 8, 9, } 10}$ | $\mathrm{I}_{\text {INJ }}$ | -1 | 1 | mA |
| 14 | Incremental Error due to injection current ${ }^{11,12}$ | $\mathrm{E}_{\mathrm{INJ}}$ | - | $\pm 4^{4}$ | Counts |
| 15 | TUE value at $8 \mathrm{MHz}{ }^{13,14}$ (with calibration) | TUE8 | - | $\pm 4^{4,6}$ | Counts |

## Electrical Characteristics

Table 19. eQADC Conversion Specifications (Operating) (continued)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 16 | TUE value at $16 \mathrm{MHz}{ }^{13,14}$ (with calibration) | TUE16 | - | $\pm 8$ | Counts |
| 17 | Variable gain amplifier accuracy (gain=1) ${ }^{15}$ <br> INL, 8 MHz ADC <br> INL, 16 MHz ADC <br> DNL, 8 MHz ADC <br> DNL, 16 MHz ADC | GAINVGA1 | $\begin{gathered} -4 \\ -8 \\ -3^{16} \\ -3^{16} \end{gathered}$ | $\begin{gathered} 4 \\ 8 \\ 3^{16} \\ 3^{16} \end{gathered}$ | Counts ${ }^{17}$ |
| 18 | Variable gain amplifier accuracy (gain=2) ${ }^{15}$ <br> INL, 8 MHz ADC <br> INL, 16 MHz ADC <br> DNL, 8 MHz ADC <br> DNL, 16 MHz ADC | GAINVGA2 | $\begin{aligned} & -5 \\ & -8 \\ & -3 \\ & -3 \end{aligned}$ | $\begin{aligned} & 5 \\ & 8 \\ & 3 \\ & 3 \end{aligned}$ | Counts |
| 19 | Variable gain amplifier accuracy (gain=4) ${ }^{15}$ <br> INL, 8 MHz ADC <br> INL, 16 MHz ADC <br> DNL, 8 MHz ADC <br> DNL, 16 MHz ADC | GAINVGA4 | $\begin{aligned} & -7 \\ & -8 \\ & -4 \\ & -4 \end{aligned}$ | $\begin{aligned} & 7 \\ & 8 \\ & 4 \\ & 4 \end{aligned}$ | Counts |

${ }^{1}$ Stop mode recovery time is the time from the setting of either of the enable bits in the ADC Control Register to the time that the ADC is ready to perform conversions. Delay from power up to full accuracy $=8 \mathrm{~ms}$.
2 At $\mathrm{V}_{\mathrm{RH}}-\mathrm{V}_{\mathrm{RL}}=5.12 \mathrm{~V}$, one count $=1.25 \mathrm{mV}$ without using pregain.
3 INL and DNL are tested from $V_{R L}+50$ LSB to $V_{R H}-50$ LSB.
4 New design target. Actual specification will change following characterization. Margin for manufacturing has not been fully included.
${ }^{5}$ At $\mathrm{V}_{\mathrm{RH}}-\mathrm{V}_{\mathrm{RL}}=5.12 \mathrm{~V}$, one $\mathrm{LSB}=1.25 \mathrm{mV}$.
6 The value is valid at 8 MHz , it is $\pm 8$ counts at 16 Mhz .
7 Below disruptive current conditions, the channel being stressed has conversion values of \$3FF for analog inputs greater than $\mathrm{V}_{\mathrm{RH}}$ and $\$ 000$ for values less than $\mathrm{V}_{\mathrm{RL}}$. Other channels are not affected by non-disruptive conditions.
8 Exceeding limit may cause conversion error on stressed channels and on unstressed channels. Transitions within the limit do not affect device reliability or cause permanent damage.
9 Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values using $\mathrm{V}_{\text {POSCLAMP }}=\mathrm{V}_{\mathrm{DDA}}+0.5 \mathrm{~V}$ and $\mathrm{V}_{\text {NEGCLAMP }}=-0.3 \mathrm{~V}$, then use the larger of the calculated values.
${ }^{10}$ Condition applies to two adjacent pins at injection limits.
${ }^{11}$ Performance expected with production silicon.
12 All channels have same $10 \mathrm{k} \Omega<\mathrm{Rs}<100 \mathrm{k} \Omega$ Channel under test has $R s=10 \mathrm{k} \Omega, \mathrm{I}_{\text {INJ }}=\underline{I}_{\text {INJMAX }}, I_{\text {INJMIN }}$.
${ }^{13}$ The TUE specification is always less than the sum of the INL, DNL, offset, and gain errors due to cancelling errors.
${ }^{14}$ TUE does not apply to differential conversions.
${ }^{15}$ Variable gain is controlled by setting the PRE_GAIN bits in the ADC_ACR1-8 registers to select a gain factor of $\times 1, \times 2$, or $\times 4$. Settings are for differential input only. Tested at $\times 1$ gain. Values for other settings are guaranteed by as indicated.
${ }^{16}$ Guaranteed 10-bit mono tonicity.
${ }^{17}$ At $\mathrm{V}_{\mathrm{RH}}-\mathrm{V}_{\mathrm{RL}}=5.12 \mathrm{~V}$, one $\mathrm{LSB}=1.25 \mathrm{mV}$.

### 4.9.1 ADC Internal Resource Measurements

Table 20. Power Management Control (PMC) Specification

| Spec | Characteristic | Symbol | Min | Typical | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| PMC Normal Mode |  |  |  |  |  |  |
| 1 | Bandgap 0.62 V ADC0 channel 145 | $\mathrm{V}_{\text {ADC145 }}$ | 0.59 | 0.62 | 0.65 | V |
| 2 | Bandgap 1.2 V ADC0 channel 146 | $\mathrm{V}_{\text {ADC146 }}$ | 1.10 | 1.22 | 1.34 | V |
| 3 | Vreg1p2 Feedback ADC0 channel 147 | $\mathrm{V}_{\text {ADC147 }}$ | $\mathrm{V}_{\mathrm{DD}} / 2.147$ | $\mathrm{V}_{\mathrm{DD}} / 2.045$ | $\mathrm{V}_{\mathrm{DD}} / 1.943$ | V |
| 4 | LVD 1.2 V <br> ADCO channel 180 | $\mathrm{V}_{\text {ADC180 }}$ | $\mathrm{V}_{\mathrm{DD}} / 1.863$ | $\mathrm{V}_{\mathrm{DD}} / 1.774$ | $\mathrm{V}_{\mathrm{DD}} / 1.685$ | V |
| 5 | Vreg3p3 Feedback ADCO channel 181 | $\mathrm{V}_{\text {ADC181 }}$ | $\begin{gathered} \text { Vreg3p3 / } \\ 5.733- \end{gathered}$ | Vreg3p3 / 5.460 | Vreg3p3 / 5.187 | V |
| 6 | LVD 3.3 V <br> ADCO channel 182 | $\mathrm{V}_{\text {ADC182 }}$ | Vreg3p3 / 4.996 | Vreg3p3 / 4.758 | Vreg3p3 / 4.520 | V |
| 7 | LVD 5.0 V <br> ADCO channel 183 <br> - LDO mode <br> - SMPS mode | $\mathrm{V}_{\text {ADC183 }}$ | $V_{\text {DDREG }} / 4.996$ <br> $V_{\text {DDREG }} / 7.384$ | $V_{\text {DDREG }} / 4.758$ <br> $V_{\text {DDREG }} / 7.032$ | $V_{\text {DDREG }} / 4.520$ <br> $V_{\text {DDREG }} / 6.680$ | V |

Table 21. Standby RAM Regulator Electrical Specifications

| Spec | Characteristic | Symbol | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Normal Mode |  |  |  |  |  |  |
| 1 | Standby Regulator Output <br> ADC1 channel 194 | $V_{\text {ADC194 }}$ | - | 1.2 | - | V |
| 2 | Standby Source Bias <br> ADC1 channel 195 | $V_{\text {ADC195 }}$ | 150 | - | 360 | mV |

Table 22. ADC Band Gap Reference / LVI Electrical Specifications

| Spec | Characteristic | Symbol | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | 4.75 LVD (from $V_{\text {DDA }}$ <br> ADC1 channel 196 | $\mathrm{~V}_{\text {ADC196 }}$ | - | 4.75 | - | V |
| 2 | ADC Bandgap <br> ADC0 channel 45 <br> ADC1 channel 45 | $\mathrm{V}_{\text {ADC45 }}$ | - | 1.220 | - | V |

## Electrical Characteristics

Table 23. Temperature Sensor Electrical Specifications

| Spec | Characteristic | Symbol | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Slope <br> $-40^{\circ} \mathrm{C}$ to $100^{\circ} \mathrm{C} \pm 1.0^{\circ} \mathrm{C}$ <br> $100^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C} \pm 1.6^{\circ} \mathrm{C}$ <br> ADC0 chanel 128 <br> ADC1 channel 128 | $\mathrm{~V}_{\text {SADC128 }}{ }^{1}$ | - | 5.8 | - | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| 2 | Accuracy <br> $-40^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ <br> ADCO channel 128 <br> ADC1 channel 128 | - | -20 | - | +20 | ${ }^{\circ} \mathrm{C}$ |

1 Slope is the measured voltage change per ${ }^{\circ} \mathrm{C}$.

### 4.10 C90 Flash Memory Electrical Characteristics

Table 24. Flash Program and Erase Specifications (Pending Si characterization)

| Spec | Characteristic | Symbol | Typ $^{\mathbf{1}}$ | Initial <br> Max $^{\mathbf{2}}$ | Lifetime <br> Max $^{\mathbf{3}}$ | Unit |
| :---: | :--- | :--- | :---: | :---: | :---: | :---: |
| 1 | Double Word (64 bits) Program Time ${ }^{4}$ | $\mathrm{t}_{\text {dwprogram }}$ | 38 | - | 500 | $\mu \mathrm{~s}$ |
| 2 | Page (128 bits) Program Time ${ }^{4}$ | $\mathrm{t}_{\text {pprogram }}$ | 45 | 160 | 500 | $\mu \mathrm{~s}$ |
| 3 | 16 KB Block Pre-program and Erase Time | $\mathrm{t}_{16 \mathrm{kpperase}}$ | 270 | 1000 | 5000 | ms |
| 4 | 48 KB Block Pre-program and Erase Time | $\mathrm{t}_{48 \mathrm{kpperase}}$ | 625 | 1500 | 5000 | ms |
| 5 | 64 KB Block Pre-program and Erase Time | $\mathrm{t}_{64 k p p e r a s e}$ | 800 | 1800 | 5000 | ms |
| 6 | 128 KB Block Pre-program and Erase Time | $\mathrm{t}_{128 \mathrm{kpperase}}$ | 1500 | 2600 | 7500 | ms |
| 7 | 256 KB Block Pre-program and Erase Time | $\mathrm{t}_{256 \mathrm{kpperase}}$ | 3000 | 5200 | 15000 | ms |

${ }^{1}$ Typical program and erase times represent the median performance and assume nominal supply values and operation at $25^{\circ} \mathrm{C}$. These values are characterized, but not tested.
2 Initial Max program and erase times provide guidance for time-out limits used in the factory and apply for < 100 program/erase cycles, nominal supply values and operation at $25^{\circ} \mathrm{C}$. These values are verified at production test.
${ }^{3}$ Lifetime Max program and erase times apply across the voltage, temperature, and cycling range of product life. These values are characterized, but not tested.
${ }^{4}$ Program times are actual hardware programming times and do not include software overhead.

## NOTE

The low, mid, and high address blocks of the flash arrays are erased (all bits set to 1 ) before leaving the factory.

Table 25. Flash Memory AC Timing Specifications ${ }^{1}$

| Symbol | Parameter | Value |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max |  |
| $\mathrm{T}_{\text {RES }}$ | Time from clearing the MCR-ESUS or PSUS bit with EHV = 1 until DONE goes low | - | - | 100 | ns |
| $\mathrm{T}_{\text {DONE }}$ | Time from 0 to 1 transition on the MCR-EHV bit initiating a program/erase until the MCR-DONE bit is cleared | - | - | 5 | ns |
| $\mathrm{T}_{\text {PSRT }}$ | Time between program suspend resume and the next program suspend request. ${ }^{2}$ | 100 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{T}_{\text {ESRT }}$ | Time between erase suspend resume and the next erase suspend request. ${ }^{3}$ | 10 | - | - | ms |

1 This parameter is guaranteed by characterization before qualification rather than $100 \%$ tested.
${ }^{2}$ Repeated suspends at a high frequency may result in the operation timing out, and the flash module will respond by completing the operation with a fail code ( $\mathrm{MCR}[\mathrm{PEG}]=0$ ), or the operation not able to finish ( $\mathrm{MCR}[\mathrm{DONE}]=1$ during Program operation). The minimum time between suspends to ensure this does notoccur is $\mathrm{T}_{\text {PSRT }}$.
3 If Erase suspend rate is less than $T_{E S R T}$, an increase of slope voltage ramp occurs during erase pulse. This improves erase time but reduces cycling figure due to overstress.

Table 26. Flash EEPROM Module Life

| Spec | Characteristic | Symbol | Min | Typical ${ }^{1}$ | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Number of Program/Erase cycles per block for 16 KB and 64 KB blocks over the operating temperature range ( $\mathrm{T}_{\mathrm{J}}$ ) | P/E | 100,000 | - | cycles |
| 2 | Number of Program/Erase cycles per block for 128 KB and 256 KB blocks over the operating temperature range ( $\mathrm{T}_{\mathrm{J}}$ ) | P/E | 1,000 | 100,000 | cycles |
| 3 | Minimum Data Retention at $85^{\circ} \mathrm{C}$ ambient temperature ${ }^{2}$ <br> Blocks with 0-1,000 P/E cycles <br> Blocks with 1,001-10,000 P/E cycles <br> Blocks with 10,001-100,000 P/E cycles | Retention | $\begin{gathered} 20 \\ 10 \\ 1-5 \end{gathered}$ | - | years |

[^0]
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Table 27. BIUCR1/BIUCR3 Settings

| Spec | Maximum Frequency (MHz) |  | APC = RWSC | WWSC | DPFEN ${ }^{1}$ | IPFEN ${ }^{1}$ | PFLIM ${ }^{2}$ | BFEN ${ }^{3}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | Core <br> $f_{\text {sys }}$ | Platform $f_{\text {platf }}$ |  |  |  |  |  |  |
| 1 | 180 MHz | 90 MHz | Ob010 | Ob01 | $\begin{aligned} & \text { Ob0 } \\ & \text { Ob1 } \end{aligned}$ | $\begin{aligned} & \text { Ob0 } \\ & \text { Ob1 } \end{aligned}$ | $\begin{aligned} & \text { Ob00 } \\ & \text { Ob01 } \\ & \text { Ob1x } \end{aligned}$ | $\begin{aligned} & \text { Ob0 } \\ & \text { Ob1 } \end{aligned}$ |
| Default setting after reset: |  |  | Ob111 | Ob11 | Ob00 | Ob00 | Ob00 | Ob0 |

1 For maximum flash performance, set to 0b1.
2 For maximum flash performance, set to 0b10.
3 For maximum flash performance, set to Ob1.

### 4.11 AC Specifications

### 4.11.1 Clocking Modes

There are two main modes of operating frequency settings:

- Double 2:1 (Core:Platform) Mode-the core is running at the system frequency setting while the platform and eTPU are running at half the core frequency (system frequency divided by 2 ).
- eTPU Mode-the core and eTPU are running at the system frequency setting while the platform is running at half the core frequency (system frequency divided by 2 ).

Table 28 shows the operating frequencies of various blocks depending on the device's clocking mode configuration settings.
Table 28. MPC5676R Block Operating Frequency ${ }^{1,2}$

| Spec | Blocks | Symbol | Double Mode Freq <br> $(\mathbf{M H z})$ | eTPU Mode Freq <br> $(\mathbf{M H z})$ |
| :---: | :--- | :---: | :---: | :---: |
| 1 | Cores | $\mathrm{f}_{\text {sys }}$ <br> $\left(\mathrm{t}_{\text {cycsys }}=1 / \mathrm{f}_{\text {sys }}\right)$ | $\mathrm{f}_{\text {sys }}=180$ | $\mathrm{f}_{\text {sys }}=180$ |
| 2 | Platform | $\mathrm{f}_{\text {platf }}$ <br> $\left(\mathrm{t}_{\text {cyc }}=1 / \mathrm{f}_{\text {platf }}\right)$ | $\mathrm{f}_{\text {sys }} / 2$ | $\mathrm{f}_{\text {sys }} / 2$ |
| 3 | eTPU | $\mathrm{f}_{\text {eTPU }}$ | $\mathrm{f}_{\text {sys }} / 2$ | $\mathrm{f}_{\text {sys }}$ |
| 4 | EBI | $\mathrm{f}_{\text {ebi }}$ | $\mathrm{f}_{\text {sys }} / 4$ | $\mathrm{f}_{\text {sys }} / 4$ |

1 The values in the table are specified at $\mathrm{V}_{\mathrm{DD}}=1.02 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=4.5 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$.
2 Up to the maximum frequency rating of the device (refer to Table 1). The $f_{\text {sys }}$ speed is the nominal maximum frequency.

### 4.11.2 Pad AC Specifications

Table 29. Pad AC Specifications ( $\left.\mathrm{V}_{\text {DDEH }}=5.0 \mathrm{~V}, \mathrm{~V}_{\text {DDE }}=3.3 \mathrm{~V}\right)^{1}$

| Spec | Pad | SRC/DSC | $\begin{gathered} \text { Out Delay }{ }^{2,4} \\ \mathrm{~L} \rightarrow \mathrm{H} / \mathrm{H} \rightarrow \mathrm{~L}(\mathrm{~ns}) \end{gathered}$ | Rise/Fall ${ }^{3,4}$ (ns) | Load Drive (pF) |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Medium ${ }^{5}$ | 00 | 152/165 | 70/74 | 50 |
| 2 |  |  | 205/220 | 96/96 | 200 |
| 3 |  | 01 | 28/34 | 12/15 | 50 |
| 4 |  |  | 52/59 | 28/31 | 200 |
| 5 |  | 11 | 12/12 | 5.3/5.9 | 50 |
| 6 |  |  | 32/32 | 22/22 | 200 |
| 7 | Fast ${ }^{6}$ | 00 | 2.5 | 1.2 | 10 |
| 8 |  | 01 |  |  | 20 |
| 9 |  | 10 |  |  | 30 |
| 10 |  | 11 |  |  | 50 |
| 11 | Fast with Slew Rate | 00 | 40/40 | 16/16 | 50 |
| 12 |  |  | 50/50 | 21/21 | 200 |
| 13 |  | 01 | 13/13 | 5/5 | 50 |
| 14 |  |  | 19/19 | 8/8 | 200 |
| 15 |  | 10 | 8/8 | 2.4/2.4 | 50 |
| 16 |  |  | 12/12 | 5/5 | 200 |
| 17 |  | 11 | 5/5 | 1.1/1/1 | 50 |
| 18 |  |  | 8/8 | 2.6 | 200 |
| 19 | Pull Up/Down (3.6 V max) | - | - | 7500 | 50 |
| 20 | Pull Up/Down (5.25 V max) | - | 6000 | 5000/5000 | 50 |

1 These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at $\mathrm{V}_{\mathrm{DD}}=1.02 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$.
2 This parameter is supplied for reference and is not guaranteed by design and not tested.
3 This parameter is guaranteed by characterization before qualification rather than $100 \%$ tested.
4 Delay and rise/fall are measured to $20 \%$ or $80 \%$ of the respective signal.
5 Out delay is shown in Figure 7. Add a maximum of one system clock to the output delay for delay with respect to system clock.
6 Out delay is shown in Figure 7. Add a maximum of one system clock to the output delay for delay with respect to system clock.
Table 30. Derated Pad AC Specifications ( $\left.\mathrm{V}_{\text {DDEH }}=3.3 \mathrm{~V}\right)^{1}$

| Spec | Pad | SRCIDSC | $\begin{aligned} & \text { Out Delay }{ }^{2,3} \\ & \mathrm{~L} \rightarrow \mathrm{H} / \mathrm{H} \rightarrow \mathrm{~L} \text { (ns) } \end{aligned}$ | $\begin{gathered} \text { Rise/Falll, }{ }^{4,3} \\ \text { (ns) } \end{gathered}$ | Load Drive (pF) |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | Medium ${ }^{5}$ | 00 | 200/210 | 86/86 | 50 |
| 2 |  |  | 270/285 | 120/120 | 200 |
| 3 |  | 01 | 37/45 | 15.5/19 | 50 |
| 4 |  |  | 69/82 | 38/43 | 200 |
| 5 |  | 11 | 18/17 | 7.6/8.5 | 50 |
| 6 |  |  | 46/49 | 30/34 | 200 |

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1 These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$.
2 This parameter is supplied for reference and is not guaranteed by design and not tested.
3 Delay and rise/fall are measured to $20 \%$ or $80 \%$ of the respective signal.
4 This parameter is guaranteed by characterization before qualification rather than $100 \%$ tested.
5 Out delay is shown in Figure 7. Add a maximum of one system clock to the output delay for delay with respect to system clock.


Figure 7. Pad Output Delay

### 4.12 AC Timing

### 4.12.1 Generic Timing Diagrams

The generic timing diagrams in Figure 8 and Figure 9 apply to all I/O pins with pad types F and MH. See Table 39 for the pad type for each pin.


Figure 8. Generic Output Delay/Hold Timing


A - Minimum Input Setup Time B - Minimum Input Hold Time
Figure 9. Generic Input Setup/Hold Timing

### 4.12.2 Reset and Configuration Pin Timing

Table 31. Reset and Configuration Pin Timing ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 1 | $\overline{\text { RESET Pulse Width }}$ | $\mathrm{t}_{\mathrm{RPW}}$ | 10 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |
| 2 | RESET Glitch Detect Pulse Width | $\mathrm{t}_{\mathrm{GPW}}$ | 2 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |
| 3 | PLLCFG, BOOTCFG, WKPCFG Setup Time to $\overline{\text { RSTOUT Valid }}$ | $\mathrm{t}_{\mathrm{RCSU}}$ | 10 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |
| 4 | PLLCFG, BOOTCFG, WKPCFG Hold Time to $\overline{\text { RSTOUT Valid }}$ | $\mathrm{t}_{\mathrm{RCH}}$ | 0 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |

${ }^{1}$ Reset timing specified at: $\mathrm{V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$.

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${ }^{2}$ See Notes on $\mathrm{t}_{\mathrm{cyc}}$ on Table 28.


Figure 10. Reset and Configuration Pin Timing

### 4.12.3 IEEE 1149.1 Interface Timing

Table 32. JTAG Pin AC Electrical Characteristics ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 1 | TCK Cycle Time | $\mathrm{t}_{\text {JCYC }}$ | 100 | - | ns |
| 2 | TCK Clock Pulse Width (Measured at $\left.V_{\text {DDE }} / 2\right)$ | $\mathrm{t}_{\text {JDC }}$ | 40 | 60 | ns |
| 3 | TCK Rise and Fall Times (40\%-70\%) | $\mathrm{t}_{\text {TCKRISE }}$ | - | 3 | ns |
| 4 | TMS, TDI Data Setup Time | $\mathrm{t}_{\text {TMSS }} \mathrm{t}_{\text {TDIS }}$ | 5 | - | ns |
| 5 | TMS, TDI Data Hold Time | $\mathrm{t}_{\text {TMSH }}, \mathrm{t}_{\text {TDIH }}$ | 25 | - | ns |
| 6 | TCK Low to TDO Data Valid | $\mathrm{t}_{\text {TDOV }}$ | - | 10 | ns |
| 7 | TCK Low to TDO Data Invalid | $\mathrm{t}_{\text {TDOI }}$ | 0 | - | ns |
| 8 | TCK Low to TDO High Impedance | $\mathrm{t}_{\text {TDOHZ }}$ | - | 20 | ns |
| 9 | JCOMP Assertion Time | $\mathrm{t}_{\text {JCMPPW }}$ | 100 | - | ns |
| 10 | JCOMP Setup Time to TCK Low | $\mathrm{t}_{\text {JCMPS }}$ | 40 | - | ns |
| 11 | TCK Falling Edge to Output Valid | $\mathrm{t}_{\text {BSDV }}$ | - | 50 | ns |

Table 32. JTAG Pin AC Electrical Characteristics ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 12 | TCK Falling Edge to Output Valid out of High Impedance | $\mathrm{t}_{\mathrm{BSDVZ}}$ | - | 50 | ns |
| 13 | TCK Falling Edge to Output High Impedance | $\mathrm{t}_{\mathrm{BSDHZ}}$ | - | 50 | ns |
| 14 | Boundary Scan Input Valid to TCK Rising Edge | $\mathrm{t}_{\text {BSDST }}$ | 50 | - | ns |
| 15 | TCK Rising Edge to Boundary Scan Input Invalid | $\mathrm{t}_{\text {BSDHT }}$ | 50 | - | ns |

${ }^{1}$ JTAG timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$, and $C_{L}=30 \mathrm{pF}$ with DSC $=0 \mathrm{~b} 10, \mathrm{SRC}=0 \mathrm{~b} 00$. These specifications apply to JTAG boundary scan only. See Table 33 for functional specifications.


Figure 11. JTAG Test Clock Input Timing

## Electrical Characteristics



Figure 12. JTAG Test Access Port Timing


Figure 13. JTAG JCOMP Timing


Figure 14. JTAG Boundary Scan Timing

### 4.12.4 Nexus Timing

Table 33. Nexus Debug Port Timing ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | MCKO Cycle Time | $\mathrm{t}_{\mathrm{MCYC}}$ | $2^{2}$ | 8 | $\mathrm{t}_{\mathrm{CYC}}$ |
| 2 | MCKO Duty Cycle | $\mathrm{t}_{\text {MDC }}$ | 40 | 60 | \% |
| 3 | MCKO Low to MDO Data Valid ${ }^{3}$ | $\mathrm{t}_{\text {MDOV }}$ | -0.1 | 0.2 | $\mathrm{t}_{\text {MCYC }}$ |
| 4 | MCKO Low to MSEO Data Valid ${ }^{3}$ | $\mathrm{t}_{\text {MSEOV }}$ | -0.1 | 0.2 | $\mathrm{t}_{\mathrm{MCYC}}$ |
| 5 | MCKO Low to $\overline{\text { EVTO }}$ Data Valid ${ }^{3}$ | $\mathrm{t}_{\text {EVToV }}$ | -0.1 | 0.2 | $\mathrm{t}_{\text {MCYC }}$ |
| 6 | $\overline{\text { EVTI }}$ Pulse Width | $\mathrm{t}_{\text {EVTIPW }}$ | 4.0 | - | ${ }_{\text {t }}{ }_{\text {TCYC }}$ |
| 7 | $\overline{\text { EVTO }}$ Pulse Width | $\mathrm{t}_{\text {EVTOPW }}$ | 1 | - | $\mathrm{t}_{\text {MCYC }}$ |
| 8 | TCK Cycle Time | $\mathrm{t}_{\text {TCYC }}$ | $4^{4}$ | - | $\mathrm{t}_{\mathrm{CYC}}$ |
| 9 | TCK Duty Cycle | $\mathrm{t}_{\text {TDC }}$ | 40 | 60 | \% |
| 10 | TDI, TMS Data Setup Time | $\mathrm{t}_{\text {NTDIS, }} \mathrm{t}_{\text {NTMSS }}$ | 8 | - | ns |

## Electrical Characteristics

Table 33. Nexus Debug Port Timing ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 11 | TDI, TMS Data Hold Time | $\mathrm{T}_{\text {NTDIH, }} \mathrm{t}_{\mathrm{NTMSH}}$ | 5 | - | ns |
| 12 | TCK Low to TDO Data Valid | $\mathrm{t}_{\mathrm{NTDOV}}$ | 0 | 10 | ns |
| 13 | $\overline{\text { RDY }}$ Valid to MCKO $^{5}$ | - | - | - | - |
| 14 | TDO hold time after TCLK low | $\mathrm{t}_{\text {NTDOH }}$ | 1 | - | ns |

1 All Nexus timing relative to MCKO is measured from $50 \%$ of MCKO and $50 \%$ of the respective signal. Nexus timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$, and $\mathrm{C}_{\mathrm{L}}=30 \mathrm{pF}$ with DSC = 0b10.
2 The Nexus AUX port runs up to 82 MHz (pending characterization). Set NPC_PCR[MKCO_DIV] to correct division depending on the system frequency, not to exceed maximum Nexus AUX port frequency.
3 MDO, $\overline{\mathrm{MSEO}}$, and $\overline{\mathrm{EVTO}}$ data is held valid until next MCKO low cycle.
${ }^{4}$ Lower frequency is required to be fully compliant to standard.
5 The $\overline{\mathrm{RDY}}$ pin timing is asynchronous to MCKO. The timing is guaranteed by design to function correctly.


Figure 15. Nexus Timings


Figure 16. Nexus TCK, TDI, TMS, TDO Timing

### 4.12.5 External Bus Interface (EBI) Timing

Table 34. Bus Operation Timing ${ }^{1}$

| Spec | Characteristic | Symbol | 66 MHz (Ext. Bus Freq) ${ }^{\mathbf{2}} \mathbf{}$ |  | Unit | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Max |  |  |
| 1 | D_CLKOUT Period | $\mathrm{t}_{\mathrm{C}}$ | 15.2 | - | ns | Signals are measured at $50 \% \mathrm{~V}_{\text {DDE }}$. |

## Electrical Characteristics

Table 34. Bus Operation Timing ${ }^{1}$ (continued)

| Spec | Characteristic | Symbol | 66 MHz (Ext. Bus Freq) ${ }^{\mathbf{2}}$ |  | Unit | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Max |  |  |
| 2 | D_CLKOUT Duty Cycle | $\mathrm{t}_{\text {CDC }}$ | 45\% | 55\% | ${ }^{\text {t }}$ C |  |
| 3 | D_CLKOUT Rise Time | $\mathrm{t}_{\mathrm{CRT}}$ | - | -4 | ns |  |
| 4 | D_CLKOUT Fall Time | $\mathrm{t}_{\text {CFT }}$ | - | - ${ }^{4}$ | ns |  |
| 5 | D_CLKOUT Posedge to Output Signal Invalid or High Z (Hold Time) $\begin{aligned} & \text { D_ADD[9:30] } \\ & \text { D_BDIP } \\ & \text { D_CS[0:3] } \\ & \text { D_DAT[0:15] } \\ & \text { D_OE } \\ & \hline \text { D_RD_WR } \\ & \text { D_TA } \\ & \left.\frac{\text { D_TS }}{\text { D_WE }} 0: 3\right] / \overline{D_{B}} \mathrm{BE}[0: 3] \end{aligned}$ | ${ }^{\text {t }} \mathrm{COH}$ | 1.0/1.5 | - | ns | Hold time selectable via SIU_ECCR[EBTS] bit: EBTS = 0: 1.0 ns EBTS = 1: 1.5 ns |
| 6 | D_CLKOUT Posedge to Output Signal Valid (Output Delay) $\begin{aligned} & \text { D_ADD[9:30] } \\ & \text { D_BDIP } \\ & \text { D_CS[0:3] } \\ & \text { D_DAT[0:15] } \\ & \text { D_OE } \\ & \hline \text { D_RD_WR } \\ & \text { D_TA } \\ & \frac{D_{1} \text { _TS }}{\text { D_WE }[0: 3] / \overline{D-B E ~}[0: 3]} \\ & \hline \end{aligned}$ | $\mathrm{t}_{\mathrm{cov}}$ | - | 8.5/9.0 | ns | Output valid time selectable via SIU_ECCR[EBTS] bit: <br> EBTS = 0: 8.5 ns <br> EBTS =1: 9.0 ns |
| 7 | ```Input Signal Valid to D_CLKOUT Posedge (Setup Time) D_ADD[9:30] D_DAT[0:15] D_RD_WR D_TA D_TS``` | $\mathrm{t}_{\text {CIS }}$ | 5.0/4.5 | - | ns | Input setup time selectable via SIU_ECCR[EBTS] bit: <br> EBTS $=0 ; 5.0 \mathrm{~ns}$ <br> EBTS $=1 ; 4.5 n s$ |
| 8 | D_CLKOUT Posedge to Input Signal Invalid (Hold Time) $\begin{aligned} & \text { D_ADD[9:30] } \\ & \text { D_DAT[0:15] } \\ & \hline \text { D_RD_WR } \\ & \text { D_TA } \\ & \text { D_TS } \end{aligned}$ | $\mathrm{t}_{\mathrm{CIH}}$ | 1.0 | - | ns |  |
| 9 | D_ALE Pulse Width | $\mathrm{t}_{\text {APW }}$ | 6.5 | - | ns | The timing is for Asynchronous external memory system. |
| 10 | D_ALE Negated to Address Invalid | $\mathrm{t}_{\text {AAI }}$ | $2.0 / 1.0^{5}$ | - | ns | The timing is for Asynchronous external memory system. <br> ALE is measured at $50 \%$ of VDDE. |

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${ }^{1} \mathrm{EBI}$ timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$, and $C_{L}=30 \mathrm{pF}$ with $\mathrm{DSC}=0 \mathrm{~b} 10$.
2 Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM).
${ }^{3}$ Depending on the internal bus speed, set the SIU_ECCR[EBDF] bits correctly not to exceed maximum external bus frequency. The maximum external bus frequency is 66 MHz .
4 Refer to Fast pad timing in Table 29 and Table 30.
5 ALE hold time spec is temperature dependant. 1.0ns spec applies for temperature range - 40 to 0 C .2 .0 ns spec applies to temperatures > 0 C. This spec has no dependency on SIU_ECCR[EBTS] bit.


Figure 17. D_CLKOUT Timing

## Electrical Characteristics



Figure 18. Synchronous Output Timing


Figure 19. Synchronous Input Timing


Figure 20. ALE Signal Timing

## Electrical Characteristics

### 4.12.6 External Interrupt Timing (IRQ Pin)

Table 35. External Interrupt Timing ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 1 | IRQ Pulse Width Low | $\mathrm{t}_{\mathrm{IPWL}}$ | 3 | - | $\mathrm{t}_{\mathrm{cyc}{ }^{2}}$ |
| 2 | IRQ Pulse Width High | $\mathrm{t}_{\mathrm{IPWH}}$ | 3 | - | $\mathrm{t}_{\mathrm{cyc}{ }^{2}}$ |
| 3 | IRQ Edge to Edge Time $^{3}$ | $\mathrm{t}_{\mathrm{ICYC}}$ | 6 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |

${ }^{1}$ IRQ timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$.
${ }^{2}$ See Notes on $\mathrm{t}_{\text {cyc }}$ Table 28.
3 Applies when IRQ pins are configured for rising edge or falling edge events, but not both.


Figure 21. External Interrupt Timing

### 4.12.7 eTPU Timing

Table 36. eTPU Timing ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 1 | eTPU Input Channel Pulse Width | $\mathrm{t}_{\mathrm{ICPW}}$ | 4 | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |
| 2 | eTPU Output Channel Pulse Width | $\mathrm{t}_{\mathrm{OCPW}}$ | $1^{3}$ | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |

${ }^{1}$ eTPU timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$, and $C_{L}=200 \mathrm{pF}$ with $\mathrm{SRC}=0 \mathrm{bOO}$.
2 See Notes on $t_{\text {cyc }}$ Table 28.
3 This specification does not include the rise and fall times. When calculating the minimum eTPU pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).


Figure 22. eTPU Timing

### 4.12.8 eMIOS Timing

Table 37. eMIOS Timing ${ }^{1}$

| Spec | Characteristic | Symbol | Min | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| 1 | eMIOS Input Pulse Width | $\mathrm{t}_{\text {MIPW }}$ | 4 | - | $\mathrm{t}_{\text {cyc }}{ }^{2}$ |
| 2 | eMIOS Output Pulse Width | $\mathrm{t}_{\text {MOPW }}$ | $1^{3}$ | - | $\mathrm{t}_{\mathrm{cyc}}{ }^{2}$ |

${ }^{1}$ eMIOS timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$, and $C_{L}=50 \mathrm{pF}$ with $\mathrm{SRC}=0 \mathrm{bOO}$.
2 See Notes on $\mathrm{t}_{\mathrm{cyc}}$ on Table 28.
3 This specification does not include the rise and fall times. When calculating the minimum eMIOS pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).

## Electrical Characteristics



Figure 23. eMIOS Timing

### 4.12.9 DSPI Timing

Table 38. DSPI Timing ${ }^{1,2}$

| Spec | Characteristic | Symbol | Peripheral Bus Freq:$92 \text { MHz }$ |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Max |  |
| 1 | DSPI Cycle Time ${ }^{3,4}$ <br> Master (MTFE $=0$ ) <br> Slave (MTFE = 0) <br> Master (MTFE = 1) <br> Slave (MTFE = 1) | ${ }^{\text {s SCK }}$ | 23.8 | 1800 | ns |
| 2 | PCS to SCK Delay ${ }^{5}$ | $\mathrm{t}_{\text {csc }}$ | 12 | - | ns |
| 3 | After SCK Delay ${ }^{6}$ | $\mathrm{t}_{\text {ASC }}$ | 12 | - | ns |
| 4 | SCK Duty Cycle | $t_{\text {SDC }}$ | 0.4 * tsck | 0.6 * tsck | ns |
| 5 | Slave Access Time (SS active to SOUT valid) | $\mathrm{t}_{\text {A }}$ | - | 25 | ns |
| 6 | Slave SOUT Disable Time <br> ( $\overline{\mathrm{SS}}$ inactive to SOUT High-Z or invalid) | $\mathrm{t}_{\text {DIS }}$ | - | 25 | ns |
| 7 | PCS $x$ to $\overline{\text { PCSS }}$ time | $t_{\text {PCSC }}$ | 4 | - | ns |
| 8 | $\overline{\text { PCSS }}$ to PCSx time | $t_{\text {PASC }}$ | 5 | - | ns |

Table 38. DSPI Timing ${ }^{1,2}$ (continued)

| Spec | Characteristic | Symbol | Peripheral Bus Freq: 92 MHz |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Max |  |
| 9 | Data Setup Time for Inputs <br> Master (MTFE = 0) <br> Slave <br> Master (MTFE $=1, \mathrm{CPHA}=0)^{7}$ <br> Master (MTFE = 1, CPHA = 1) | ${ }_{\text {t }}^{\text {SuI }}$ | $\begin{gathered} 27 \\ 10 \\ 7 \\ 27 \end{gathered}$ | $\begin{aligned} & - \\ & - \end{aligned}$ | ns ns ns ns |
| 10 | Data Hold Time for Inputs <br> Master $($ MTFE $=0)$ <br> Slave <br> Master (MTFE $=1, \mathrm{CPHA}=0)^{7}$ <br> Master (MTFE = 1, CPHA = 1) | $\mathrm{t}_{\mathrm{HI}}$ | $\begin{gathered} -3 \\ 7 \\ 12 \\ -3 \end{gathered}$ | - | $\begin{aligned} & \text { ns } \\ & \text { ns } \\ & \text { ns } \\ & \text { ns } \end{aligned}$ |
| 11 | Data Valid (after SCK edge) <br> Master (MTFE = 0) <br> Slave <br> Master (MTFE $=1, \mathrm{CPHA}=0)$ <br> Master (MTFE = 1, CPHA = 1) <br> Master (LVDS) | $\mathrm{t}_{\text {suo }}$ | - | $\begin{gathered} 10 \\ 30 \\ 20 \\ 10 \\ 5 \end{gathered}$ | $\begin{aligned} & \text { ns } \\ & \text { ns } \\ & \text { ns } \\ & \text { ns } \\ & \text { ns } \end{aligned}$ |
| 12 | Data Hold Time for Outputs <br> Master (MTFE = 0) <br> Slave <br> Master (MTFE $=1$, CPHA $=0$ ) <br> Master (MTFE = 1, CPHA = 1) <br> Master (LVDS) | $\mathrm{t}_{\mathrm{HO}}$ | $\begin{gathered} -6 \\ 2.5 \\ 3 \\ -7 \\ -5 \end{gathered}$ | $\begin{aligned} & - \\ & - \\ & - \end{aligned}$ |  |

1 DSPI timing specified at $\mathrm{V}_{\mathrm{DD}}=1.08 \mathrm{~V}$ to $1.32 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDEH}}=3.0 \mathrm{~V}$ to $5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD} 33}$ and $\mathrm{V}_{\mathrm{DDSYN}}=3.0 \mathrm{~V}$ to 3.6 V , and $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{H}}$
2 Speed is the nominal maximum frequency of platform clock ( $\mathrm{f}_{\text {platf }}$ ). Max speed is the maximum speed allowed including frequency modulation (FM).
3 The minimum DSPI Cycle Time restricts the baud rate selection for given system clock rate. These numbers are calculated based on two devices communicating over a DSPI link.
4 The actual minimum SCK cycle time is limited by pad performance.
5 The maximum value is programmable in DSPI_CTARn[PSSCK] and DSPI_CTARn[CSSCK].
6 The maximum value is programmable in DSPI_CTARn[PASC] and DSPI_CTARn[ASC].
7 This number is calculated assuming the SMPL_PT bit-field in DSPI_MCR is set to 0b10.

The DSPI in this device can be configured to serialize data to an external device that implements the Microsecond Bus protocol. DSPI pins support 5 V logic levels or Low Voltage Differential Signalling (LVDS) for data and clock signals to improve high speed operation.

## Electrical Characteristics



Figure 24. DSPI Classic SPI Timing - Master, CPHA $=0$


Figure 25. DSPI Classic SPI Timing - Master, CPHA = 1


Figure 26. DSPI Classic SPI Timing - Slave, CPHA = 0


Figure 27. DSPI Classic SPI Timing - Slave, CPHA = 1

## Electrical Characteristics



Figure 28. DSPI Modified Transfer Format Timing - Master, CPHA = 0


Figure 29. DSPI Modified Transfer Format Timing - Master, CPHA = 1


Figure 30. DSPI Modified Transfer Format Timing - Slave, CPHA = 0


Figure 31. DSPI Modified Transfer Format Timing - Slave, CPHA = 1

## Electrical Characteristics



Figure 32. DSPI PCS Strobe ( $\overline{\text { PCSS }}$ ) Timing

## 5 Package Information

## $5.1 \quad$ 416-Pin Package

The package drawings of the 416-pin TEPBGA package are shown in Figure 33 and Figure 34.


Figure 33. 416 TEPBGA Package (1 of 2)

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## Package Information

## NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.


Figure 34. 416 TEPBGA Package (2 of 2)

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## $5.2 \quad$ 516-Pin Package

The package drawings of the 516-pin TEPBGA package are shown in Figure 35 and Figure 36.


Figure 35. 516 TEPBGA Package (1 of 2)

## Package Information

NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PACKAGE CODES: $5193 \& 5198$.


Figure 36. 516 TEPBGA Package (2 of 2)

## 6 Product Documentation

This data sheet is labeled as a particular type: Product Preview, Advance Information, or Technical Data. Definitions of these types are available at: http://www.nxp.com.

The following documents are required for a complete description of the device and are necessary to design properly with the parts:

- MPC5676R RM Microprocessor Reference Manual (document number MPC5676RRM)
Appendix A Signal Properties and Muxing
The following table shows the signals properties for each pin on the MPC5676R. For each port pin that has an associated SIU_PCRn register to control its pin properties, the supported functions column lists the functions associated with the programming of the SIU_PCRn[PA] bit in the order: Primary function (P), Function 2 (F2), Function 3 (F3), and GPIO (G). See Figure 37.

Figure 37. Supported Functions Example

| 근0믕00 | Signal Name ${ }^{2}$ | $\frac{\mathrm{N}}{\mathbf{0}}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & 0 \\ & \mathbb{T} \\ & \frac{\pi}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{0}{7}$ | $\xrightarrow{0}$ |
| eTPU_A |  |  |  |  |  |  |  |  |  |  |  |
| 113 | TCRCLKA_IRQ7_ GPIO113 | P | TCRCLKA | eTPU A TCR clock | 1 | MH | $V_{\text {DDEH1 }}$ | -/Up | -/Up | L1 | K4 |
|  |  | A1 | IRQ7 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO113 | GPIO | I/O |  |  |  |  |  |  |
| 114 | ETPUAO_ETPUA12_ GPIO114 | P | ETPUAO | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | L2 | L6 |
|  |  | A1 | ETPUA12 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO114 | GPIO | I/O |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)

| $$ | Signal Name ${ }^{2}$ | $\begin{aligned} & \text { N } \\ & \vdots \\ & \vdots \\ & \vdots \end{aligned}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \frac{0}{0} \\ & \frac{\pi}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{\ominus}{7}$ | - |
| 115 | ETPUA1_ETPUA13_ GPIO115 | P | ETPUA1 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH } 1}$ | -/WKPCFG | -/WKPCFG | L3 | J1 |
|  |  | A1 | ETPUA13 | eTPU A channel (output only) | O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO115 | GPIO | I/O |  |  |  |  |  |  |
| 116 | ETPUA2_ETPUA14_ GPIO116 | P | ETPUA2 | eTPU A channel | I/O | MH | V DDEH1 | -/WKPCFG | -/WKPCFG | L4 | J2 |
|  |  | A1 | ETPUA14 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO116 | GPIO | I/O |  |  |  |  |  |  |
| 117 | ETPUA3_ETPUA15_ GPIO117 | P | ETPUA3 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | K1 | H4 |
|  |  | A1 | ETPUA15 | eTPU A channel (output only) | O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO117 | GPIO | I/O |  |  |  |  |  |  |
| 118 | ETPUA4_ETPUA16_ GPIO118 | P | ETPUA4 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH } 1}$ | -/WKPCFG | -/WKPCFG | K2 | J4 |
|  |  | A1 | ETPUA16 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO118 | GPIO | I/O |  |  |  |  |  |  |
| 119 | ETPUA5_ETPUA17_ GPIO119 | P | ETPUA5 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH } 1}$ | -/WKPCFG | -/WKPCFG | K3 | H1 |
|  |  | A1 | ETPUA17 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO119 | GPIO | I/O |  |  |  |  |  |  |
| 120 | $\begin{aligned} & \text { ETPUA6_ETPUA18_ } \\ & \text { GPIO120 } \end{aligned}$ | P | ETPUA6 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | K4 | K5 |
|  |  | A1 | ETPUA18 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO120 | GPIO | I/O |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ |  | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \mathbb{O} \\ & \frac{\pi}{0} \\ & \hline 8 \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{\ominus}{7}$ | 6 1 $i$ |
| 121 | ETPUA7_ETPUA19_ GPIO121 | P | ETPUA7 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | J1 | H2 |
|  |  | A1 | ETPUA19 | eTPU A channel (output only) | O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO121 | GPIO | I/O |  |  |  |  |  |  |
| 122 | ETPUA8_ETPUA20_ GPIO122 | P | ETPUA8 | eTPU A channel | I/O | MH | $V_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | J2 | H3 |
|  |  | A1 | ETPUA20 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO122 | GPIO | I/O |  |  |  |  |  |  |
| 123 | $\begin{aligned} & \text { ETPUA9_ETPUA21_ } \\ & \text { GPIO123 } \end{aligned}$ | P | ETPUA9 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | J3 | J3 |
|  |  | A1 | ETPUA21 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO123 | GPIO | I/O |  |  |  |  |  |  |
| 124 | $\begin{aligned} & \text { ETPUA10_ETPUA22_ } \\ & \text { GPIO124 } \end{aligned}$ | P | ETPUA10 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | J4 | K6 |
|  |  | A1 | ETPUA22 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO124 | GPIO | I/O |  |  |  |  |  |  |
| 125 | ETPUA11_ETPUA23_ GPIO125 | P | ETPUA11 | eTPU A channel | I/O | MH | $V_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | H1 | G1 |
|  |  | A1 | ETPUA23 | eTPU A channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO125 | GPIO | I/O |  |  |  |  |  |  |
| 126 | $\begin{aligned} & \text { ETPUA12_PCSB1_ } \\ & \text { GPIO126 } \end{aligned}$ | P | ETPUA12 | eTPU A channel | I/O | MH | $\mathrm{V}_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | H2 | J5 |
|  |  | A1 | PCSB1 | DSPI B peripheral chip select | O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO126 | GPIO | I/O |  |  |  |  |  |  |

MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39．Signal Properties and Muxing Summary（continued）

\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline \multirow[t]{2}{*}{} \& \multicolumn{4}{|l|}{N} \& \multicolumn{4}{|l|}{노} \& \multicolumn{4}{|l|}{O} \& \multicolumn{4}{|l|}{${ }^{\text {오 }}$} \& \multicolumn{4}{|l|}{$\pm$} \& \multicolumn{4}{|l|}{$\stackrel{\sim}{0}$} <br>
\hline \& \multicolumn{4}{|l|}{$\stackrel{ \pm}{ \pm}$} \& \multicolumn{4}{|l|}{$\stackrel{\text { m }}{\text { I }}$} \& \multicolumn{4}{|l|}{J} \& \multicolumn{4}{|l|}{N} \& \multicolumn{4}{|l|}{\％} \& \multicolumn{4}{|l|}{O} <br>
\hline  \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& \vdots \\
& \vdots \\
& \cline { 1 - 1 }
\end{aligned}
$$} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& 2 \\
& 2 \\
& 1
\end{aligned}
$$} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& \text { U } \\
& \text { U } \\
& 0 \\
& \sum_{1}^{2} \\
& y_{1}
\end{aligned}
$$} \& \multicolumn{4}{|l|}{$$
\begin{array}{|l|l}
0 \\
\text { U } \\
0 \\
0 \\
0 \\
\vdots \\
\vdots \\
\vdots
\end{array}
$$} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& 0 \\
& \vdots \\
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\end{aligned}
$$} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& \vdots \\
& 0 \\
& 0 \\
& 0 \\
& \vdots \\
& \sum_{1}
\end{aligned}
$$} <br>
\hline  \& \multicolumn{4}{|l|}{$$
\begin{array}{|l}
0 \\
U \\
U \\
0 \\
0 \\
\vdots \\
\vdots \\
\cline { 1 - 1 }
\end{array}
$$} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
& 0 \\
& \text { U } \\
& 0 \\
& 0 \\
& 2 \\
& y_{1}^{2}
\end{aligned}
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\begin{aligned}
& 0 \\
& 0 \\
& \text { U } \\
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& 0 \\
& \vdots \\
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\begin{aligned}
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& 0 \\
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& 0 \\
& \vdots \\
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& \cline { 1 - 1 }
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$$} \& \multicolumn{4}{|l|}{$$
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0 \\
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\sum_{1}
\end{array}
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$$} \& \multicolumn{4}{|l|}{} \& \multicolumn{4}{|l|}{} \& \multicolumn{4}{|l|}{$$
\begin{aligned}
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& \text { 10 } \\
& > \\
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\end{aligned}
$$} \& \multicolumn{4}{|l|}{$$
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& \stackrel{\rightharpoonup}{5} \\
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\end{aligned}
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\hline $\mathrm{g}^{\text {®d }} K_{\perp} \mathrm{pe} \mathrm{c}_{\mathrm{d}}$ \& \multicolumn{4}{|l|}{I} \& \multicolumn{4}{|l|}{I} \& \multicolumn{4}{|l|}{I} \& \multicolumn{4}{|l|}{I ${ }^{\text {I }}$} \& \multicolumn{4}{|l|}{I} \& \multicolumn{4}{|l|}{$\stackrel{\text { I }}{ }$} <br>
\hline ио！ฺэәл！ \& $\bigcirc$ \& $\bigcirc$ \& 1 \& $\bigcirc$ \& $\bigcirc$ \& $\bigcirc$ \& 1 \& $\bigcirc$ \& $\bigcirc$ \& $\bigcirc$ \& ｜ \& $\bigcirc$ \& $\bigcirc$ \& $\bigcirc$ \& 1 \& $\bigcirc$ \& $\bigcirc$ \& $\bigcirc$ \& 1 \& $\bigcirc$ \& $\bigcirc$ \& $\bigcirc$ \& I \& $\bigcirc$ <br>
\hline  \&  \&  \& 1 \& $$
\frac{\mathrm{O}}{\mathrm{O}}
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\frac{\mathrm{O}}{\mathrm{O}}
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\frac{\mathrm{O}}{\mathrm{O}}
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\begin{array}{|l}
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\hline \mathrm{O}
\end{array}
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\end{aligned}
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& \underset{O}{O} \\
&
\end{aligned}
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\begin{aligned}
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& 0 \\
& 0
\end{aligned}
$$ \& 1 \& $$
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& \underset{\sim}{\sim} \\
& \underset{0}{0} \\
& 0
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& 0
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& 0 \\
& 0
\end{aligned}
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\begin{aligned}
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& \underline{O} \\
& \underline{0} \\
& 0
\end{aligned}
$$ \&  \& N \& 1 \& N

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0 <br>
\hline $\varepsilon$ ¢ \& － \& 『 \& ※ \& $\bigcirc$ \& Q \& を \& § \& $\bigcirc$ \& － \& 『 \& ※ \& $\bigcirc$ \& Q \& を \& ※ \& 0 \& $\bigcirc$ \& 『 \& § \& $\bigcirc$ \& 0 \& 『 \& § \& $\bigcirc$ <br>
\hline N \&  \& \& \& \&  \& \& \& \&  \& \& \& \&  \& \& \& \&  \& \& \& \&  \& \& \& <br>
\hline ¢ ${ }^{\text {YOd／OId }}$ \& $\xrightarrow{\text { N}}$ \& \& \& \& $\stackrel{\sim}{\text { N}}$ \& \& \& \& － \& \& \& \& － \& \& \& \& $\stackrel{-}{7}$ \& \& \& \& N \& \& \& <br>
\hline
\end{tabular}

MPC5676R Microcontroller Data Sheet，Rev． 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ |  | Function ${ }^{4}$ | Function Summary |  | $\begin{aligned} & \text { n } \\ & \stackrel{0}{2} \\ & \frac{0}{\pi} \\ & \hline \end{aligned}$ | $\begin{aligned} & 0 \\ & \frac{0}{\mathbb{Z}} \\ & \frac{\pi}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{\ominus}{7}$ | -18 |
| 145 | $\begin{aligned} & \text { ETPUA31_PCSC4_ } \\ & \text { GPIO145 } \end{aligned}$ | P | ETPUA31 | eTPU A channel | I/O | MH | $V_{\text {DDEH1 }}$ | -/WKPCFG | -/WKPCFG | C2 | C2 |
|  |  | A1 | PCSC4 | DSPI C peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO145 | GPIO | 1/0 |  |  |  |  |  |  |
| eTPU_B |  |  |  |  |  |  |  |  |  |  |  |
| 146 | TCRCLKB_IRQ6_ GPIO146 | P | TCRCLKB | eTPU B TCR clock | 1 | MH | $V_{\text {DDEH6 }}$ | -/Up | -/Up | T23 | V25 |
|  |  | A1 | IRQ6 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO146 | GPIO | 1/0 |  |  |  |  |  |  |
| 147 | $\begin{aligned} & \text { ETPUBO_ETPUB16_ } \\ & \text { GPIO147 } \end{aligned}$ | P | ETPUB0 | eTPU B channel | 1/0 | MH | $\mathrm{V}_{\text {DDEH6 }}$ | -/WKPCFG | -/WKPCFG | T24 | V26 |
|  |  | A1 | ETPUB16 | eTPU B channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO147 | GPIO | 1/O |  |  |  |  |  |  |
| 148 | $\begin{aligned} & \text { ETPUB1_ETPUB17_- } \\ & \text { GPIO148 } \end{aligned}$ | P | ETPUB1 | eTPU B channel | I/O | MH | $V_{\text {DDEH6 }}$ | -/WKPCFG | -/WKPCFG | T25 | U22 |
|  |  | A1 | ETPUB17 | eTPU B channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO148 | GPIO | 1/0 |  |  |  |  |  |  |
| 149 | $\begin{array}{\|l} \text { ETPUB2_ETPUB18_ } \\ \text { GPIO149 } \end{array}$ | P | ETPUB2 | eTPU B channel | I/O | MH | $V_{\text {DDEH6 }}$ | -/WKPCFG | -/WKPCFG | T26 | U23 |
|  |  | A1 | ETPUB18 | eTPU B channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO149 | GPIO | 1/O |  |  |  |  |  |  |
| 150 | ```ETPUB3_ETPUB19_ GPIO150``` | P | ETPUB3 | eTPU B channel | 1/0 | MH | $\mathrm{V}_{\text {DDEH6 }}$ | -/WKPCFG | —/WKPCFG | R23 | T22 |
|  |  | A1 | ETPUB19 | eTPU B channel (output only) | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO150 | GPIO | 1/0 |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)


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Table 39．Signal Properties and Muxing Summary（continued）

|  | $\stackrel{\sim}{\sim}$ |  |  |  | $\stackrel{\stackrel{\rightharpoonup}{*}}{\sim}$ |  |  |  | $\underset{\sim}{\sim}$ |  |  |  | N |  |  |  | $\underset{\text { ¢ }}{\text { ¢ }}$ |  |  |  | $\underset{\text { ¢ }}{\text { ¢ }}$ |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | $\stackrel{\stackrel{\sim}{\mathrm{N}}}{ }$ |  |  |  | N |  |  |  | $\stackrel{N}{\mathrm{~N}}$ |  |  |  | $\stackrel{0}{\underset{Z}{z}}$ |  |  |  | $\stackrel{N}{N}$ |  |  |  | $\underset{\Sigma}{\text { N }}$ |  |  |  |
|  |  |  |  |  | $\begin{aligned} & 0 \\ & 1 \\ & u \\ & 0 \\ & 0 \\ & y_{1}^{2} \\ & \hline \end{aligned}$ |  |  |  | $\begin{aligned} & 0 \\ & 0 \\ & \text { U } \\ & 0 \\ & \sum_{1}^{2} \\ & \sum_{1} \end{aligned}$ |  |  |  | $\begin{aligned} & 0 \\ & 0 \\ & \text { U } \\ & 0 \\ & 0 \\ & \vdots \\ & \vdots \\ & \cline { 1 - 1 } \end{aligned}$ |  |  |  | $\begin{array}{\|l\|l} 0 \\ U \\ U \\ 0 \\ 0 \\ \vdots \\ \vdots \end{array}$ |  |  |  | $\begin{aligned} & 0 \\ & \text { U } \\ & \text { U } \\ & 0 \\ & \vdots \\ & \sum ⿰ 亻 ⿱ 丶 ⿻ 工 二 十 \end{aligned}$ |  |  |  |
|  | $\begin{aligned} & 0 \\ & 0 \\ & 0 \\ & 0 \\ & 0 \\ & y_{1}^{2} \\ & 1 \end{aligned}$ |  |  |  | $\begin{array}{\|l} 0 \\ 0 \\ \text { U } \\ 0 \\ 0 \\ \vdots \\ \vdots \\ \cline { 1 - 1 } \end{array}$ |  |  |  |  |  |  |  | $\begin{array}{\|l\|l} 0 \\ \text { U } \\ U \\ 0 \\ 0 \\ \vdots \\ \vdots \end{array}$ |  |  |  | $\begin{aligned} & 0 \\ & 0 \\ & 0 \\ & 0 \\ & 0 \\ & y_{1} \\ & 1 \end{aligned}$ |  |  |  | $\begin{aligned} & 0 \\ & 0 \\ & 0 \\ & 0 \\ & \vdots \\ & \sum_{1}^{2} \end{aligned}$ |  |  |  |
| ${ }_{9}$ әбеұо＾ | $\begin{array}{\|l\|l} \hline \stackrel{\circ}{1} \\ \text { 岩 } \\ > \end{array}$ |  |  |  | $\begin{array}{\|l\|l} \text { 운 } \\ \text { 1 } \\ \hline 0 \end{array}$ |  |  |  | $\begin{array}{\|l\|l} \hline \stackrel{\circ}{4} \\ \text { 1 } \\ \text { > } \end{array}$ |  |  |  | $\begin{array}{\|l\|l} \hline \stackrel{\circ}{1} \\ \text { 夏 } \end{array}$ |  |  |  | $\begin{aligned} & \text { 운 } \\ & \text { 咱 } \end{aligned}$ |  |  |  | ¢ |  |  |  |
| $\mathrm{g}^{\text {®d }} \mathrm{K}_{\perp} \mathrm{ped}$ | $\stackrel{\text { T }}{ }$ |  |  |  | I |  |  |  | 「 |  |  |  | \} |  |  |  | IT |  |  |  | ${ }^{\text {I }}$ |  |  |  |
| ио！ฺэәл！ | $\bigcirc$ | $\bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | I | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | I | $\bigcirc$ |
|  |  |  | 1 | $\begin{aligned} & \frac{0}{0} \\ & 0 \end{aligned}$ |  |  | 1 | $\begin{aligned} & \frac{0}{0} \\ & 0 \end{aligned}$ |  |  | 1 | $\frac{\mathrm{O}}{0}$ |  |  | 1 | $\frac{\mathrm{O}}{\mathrm{O}}$ |  |  |  | $\begin{aligned} & \frac{0}{0} \\ & 0 \end{aligned}$ |  |  | I | $\frac{0}{0}$ |
|  |  |  | 1 | $\begin{aligned} & 1 \\ & 0 \\ & 0 \\ & 0 \\ & 0 \\ & 0 \end{aligned}$ | $\begin{aligned} & \underset{7}{7} \\ & \stackrel{y}{2} \\ & \stackrel{\rightharpoonup}{2} \\ & \underset{\sim}{2} \end{aligned}$ |  | 1 | $\begin{aligned} & \infty \\ & \stackrel{n}{0} \\ & \stackrel{0}{n} \\ & 0 \end{aligned}$ |  | $\begin{aligned} & \stackrel{\sim}{N} \\ & \stackrel{\sim}{2} \\ & \stackrel{2}{\omega} \end{aligned}$ | 1 | 0 0 0 0 0 0 |  | $\begin{aligned} & \stackrel{8}{N} \\ & \stackrel{1}{2} \\ & \stackrel{2}{\Sigma} \end{aligned}$ | 1 | $\begin{aligned} & \mathrm{O} \\ & \underline{0} \\ & \underline{O} \\ & \hline 0 \end{aligned}$ |  |  | 1 | $\begin{aligned} & -1 \\ & 0 \\ & \underline{0} \\ & \underline{0} \end{aligned}$ |  |  | ｜ | N 0 0 0 0 0 0 |
| ع ${ }^{\text {O／V／d }}$ | Q | を | ※ | 0 | Q | を | ※ | $\bigcirc$ | － | を | ※ | $\bigcirc$ | Q | を | さ | 0 | $\bigcirc$ | を | さ | $\bigcirc$ | 0 | を | ホ | $\bigcirc$ |
|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| ¢ ${ }^{\text {UOd／OId }}$ | $\stackrel{\sim}{\square}$ |  |  |  | $\stackrel{\sim}{\sim}$ |  |  |  | 彔 |  |  |  | － |  |  |  | $\stackrel{\rightharpoonup}{0}$ |  |  |  | N |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ |  | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \stackrel{0}{0} \\ & \frac{\pi}{0} \\ & \hline \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & 0 \\ & \underset{F}{\prime} \end{aligned}$ | -1 |
| 454 | $\begin{aligned} & \text { ETPUC13_3_IRQ4_ } \\ & \text { GPIO454 } \end{aligned}$ | P | ETPUC13 | eTPU C channel | I/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | G25 | G24 |
|  |  | A1 | IRQ4 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO454 | GPIO | 1/0 |  |  |  |  |  |  |
| 455 | ETPUC14_4_IRQ5_ GPIO455 | P | ETPUC14 | eTPU C channel | I/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | G26 | G25 |
|  |  | A1 | IRQ5 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO455 | GPIO | 1/0 |  |  |  |  |  |  |
| 456 | $\begin{aligned} & \text { ETPUC15_- } \\ & \text { GPIO456 } \end{aligned}$ | P | ETPUC15 | eTPU C channel | 1/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | H23 | G26 |
|  |  | A1 | - | - | - |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO456 | GPIO | 1/0 |  |  |  |  |  |  |
| 457 | ETPUC16_FR_A_TX_GPIO457 | P | ETPUC16 | eTPU C channel | 1/0 | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | H24 | H22 |
|  |  | A1 | FR_A_TX | FlexRay A transfer | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO457 | GPIO | I/O |  |  |  |  |  |  |
| 458 | $\begin{aligned} & \text { ETPUC17_FR_A_RX_ } \\ & \text { GPIO458 } \end{aligned}$ | P | ETPUC17 | eTPU C channel | 1/O | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | H25 | H23 |
|  |  | A1 | FR_A_RX | FlexRay A receive | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO458 | GPIO | I/O |  |  |  |  |  |  |
| 459 | $\begin{aligned} & \text { ETPUC18_FR_A_TX_EN_ } \\ & \text { GPIO459 } \end{aligned}$ | P | ETPUC18 | eTPU C channel | 1/O | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | H26 | H24 |
|  |  | A1 | FR_A_TX_EN | FlexRay A transfer enable | $\bigcirc$ |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO459 | GPIO | 1/0 |  |  |  |  |  |  |

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Table 39. Signal Properties and Muxing Summary (continued)

| $\begin{aligned} & 7 \\ & \underline{\alpha} \\ & 0 \\ & 0 \\ & 0 \\ & 00 \\ & 0 \end{aligned}$ | Signal Name ${ }^{2}$ | $\begin{aligned} & \mathrm{N} \\ & \\ & \vdots \\ & \hline \end{aligned}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0_{\mathbb{Q}}^{\mathbf{O}} \\ & \frac{\mathbb{T}}{0} \\ & \hline \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{\ominus}{\underset{7}{7}}$ | 0 in |
| 460 | $\begin{aligned} & \text { ETPUC19_TXDA_ } \\ & \text { GPIO460 } \end{aligned}$ | P | ETPUC19 | eTPU C channel | I/O | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | J23 | H21 |
|  |  | A1 | TXDA | eSCI A transmit | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO460 | GPIO | I/O |  |  |  |  |  |  |
| 461 | $\begin{aligned} & \text { ETPUC20_RXDA _ } \\ & \text { GPIO461 } \end{aligned}$ | P | ETPUC20 | eTPU C channel | I/O | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | J24 | H25 |
|  |  | A1 | RXDA | eSCI A receive | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO461 | GPIO | I/O |  |  |  |  |  |  |
| 462 | $\begin{aligned} & \text { ETPUC21_TXDB_ } \\ & \text { GPIO462 } \end{aligned}$ | P | ETPUC21 | eTPU C channel | I/O | MH | $\mathrm{V}_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | J25 | H26 |
|  |  | A1 | TXDB | eSCI B transmit | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO462 | GPIO | I/O |  |  |  |  |  |  |
| 463 | $\begin{aligned} & \text { ETPUC22_RXDB_ } \\ & \text { GPIO463 } \end{aligned}$ | P | ETPUC22 | eTPU C channel | I/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | J26 | J22 |
|  |  | A1 | RXDB | eSCI B receive | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO463 | GPIO | 1/O |  |  |  |  |  |  |
| 464 | $\begin{aligned} & \text { ETPUC23_PCSD5_ } \\ & \text { GPIO464 } \end{aligned}$ | P | ETPUC23 | eTPU C channel | I/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | K23 | J23 |
|  |  | A1 | PCSD5 | DSPI D peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | MAAO | ADC A Mux Address 0 | 0 |  |  |  |  |  |  |
|  |  | A3 | MAB0 | ADC B Mux Address 0 | 0 |  |  |  |  |  |  |
|  |  | G | GPIO464 | GPIO | 1/O |  |  |  |  |  |  |
| 465 | $\begin{aligned} & \text { ETPUC24_PCSD4_ } \\ & \text { GPIO465 } \end{aligned}$ | P | ETPUC24 | eTPU C channel | I/O | MH | $V_{\text {DDEH7 }}$ | -/WKPCFG | -/WKPCFG | K24 | J24 |
|  |  | A1 | PCSD4 | DSPI D peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | MAA1 | ADC A Mux Address 1 | 0 |  |  |  |  |  |  |
|  |  | A4 | MAB1 | ADC B Mux Address 1 | 0 |  |  |  |  |  |  |
|  |  | G | GPIO465 | GPIO | 1/O |  |  |  |  |  |  |

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Table 39. Signal Properties and Muxing Summary (continued)


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Table 39. Signal Properties and Muxing Summary (continued)


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Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ | $\begin{aligned} & \text { M } \\ & \vdots \\ & \vdots \\ & \hline \end{aligned}$ | Function ${ }^{4}$ | Function Summary |  | $\begin{aligned} & \stackrel{0}{0} \\ & \stackrel{2}{2} \\ & \stackrel{0}{\pi} \\ & 0 \end{aligned}$ |  | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{0}{7}$ | 0 $n$ |
| 184 | $\begin{aligned} & \text { EMIOS5_ETPUA5_ } \\ & \text { GPIO184 } \end{aligned}$ | P | EMIOS5 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD12 | AF14 |
|  |  | A1 | ETPUA5 | eTPU A channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO184 | GPIO | 1/0 |  |  |  |  |  |  |
| 185 | $\begin{array}{\|l} \hline \text { EMIOS6_ETPUA6_ } \\ \text { GPIO185 } \end{array}$ | P | EMIOS6 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE12 | AE14 |
|  |  | A1 | ETPUA6 | eTPU A channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO185 | GPIO | I/O |  |  |  |  |  |  |
| 186 | $\begin{aligned} & \text { EMIOS7_ETPUA7_ } \\ & \text { GPIO186 } \end{aligned}$ | P | EMIOS7 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF12 | AD14 |
|  |  | A1 | ETPUA7 | eTPU A channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO186 | GPIO | I/O |  |  |  |  |  |  |
| 187 | $\begin{array}{\|l} \hline \text { EMIOS8_ETPUA8_ } \\ \text { GPIO187 } \end{array}$ | P | EMIOS8 | eMIOS channel | 1/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC13 | AC14 |
|  |  | A1 | ETPUA8 | eTPU A channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO187 | GPIO | I/O |  |  |  |  |  |  |
| 188 | $\begin{aligned} & \text { EMIOS9_ETPUA9_ } \\ & \text { GPIO188 } \end{aligned}$ | P | EMIOS9 | eMIOS channel | 1/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD13 | AF15 |
|  |  | A1 | ETPUA9 | eTPU A channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO188 | GPIO | I/O |  |  |  |  |  |  |
| 189 | $\begin{aligned} & \text { EMIOS10_SCKD_ } \\ & \text { GPIO189 } \end{aligned}$ | P | EMIOS10 | eMIOS channel | 1/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE13 | AE15 |
|  |  | A1 | SCKD | DSPI D clock | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO189 | GPIO | 1/0 |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ | $\stackrel{N}{\substack{\mathrm{O} \\ \vdots \\ \hline}}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \frac{0}{0} \\ & \frac{\pi}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & 9 \\ & 7 \end{aligned}$ | - |
| 190 | $\begin{aligned} & \text { EMIOS11_SIND_ } \\ & \text { GPIO190 } \end{aligned}$ | P | EMIOS11 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF13 | AB14 |
|  |  | A1 | SIND | DSPI D data input | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO190 | GPIO | I/O |  |  |  |  |  |  |
| 191 | EMIOS12_SOUTC_ GPIO191 | P | EMIOS12 | eMIOS channel | 0 | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -WKPCFFG | -/WKPCFG | AF14 | AD15 |
|  |  | A1 | SOUTC | DSPI C data output | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO191 | GPIO | I/O |  |  |  |  |  |  |
| 192 | $\begin{aligned} & \text { EMIOS13_SOUTD_ } \\ & \text { GPIO192 } \end{aligned}$ | P | EMIOS13 | eMIOS channel | O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE14 | AC15 |
|  |  | A1 | SOUTD | DSPI D data output | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO192 | GPIO | I/O |  |  |  |  |  |  |
| 193 | $\begin{aligned} & \text { EMIOS14_IRQO_ } \\ & \text { GPIO193 } \end{aligned}$ | P | EMIOS14 | eMIOS channel | 0 | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC14 | AF17 |
|  |  | A1 | IRQ0 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | CNTXD | FlexCAN D transmit | 0 |  |  |  |  |  |  |
|  |  | G | GPIO193 | GPIO | I/O |  |  |  |  |  |  |
| 194 | $\begin{aligned} & \text { EMIOS15_IRQ1_ } \\ & \text { GPIO194 } \end{aligned}$ | P | EMIOS15 | eMIOS channel | 0 | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD14 | AE16 |
|  |  | A1 | IRQ1 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | CNRXD | FlexCAN D receive | 1 |  |  |  |  |  |  |
|  |  | G | GPIO194 | GPIO | I/O |  |  |  |  |  |  |
| 195 | ```EMIOS16_ETPUB0_ GPIO195``` | P | EMIOS16 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF15 | AD16 |
|  |  | A1 | ETPUB0 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | FR_DBG[3] | FlexRay debug | O |  |  |  |  |  |  |
|  |  | G | GPIO195 | GPIO | I/O |  |  |  |  |  |  |

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Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ |  | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \mathbb{O} \\ & \frac{\pi}{0} \\ & \hline 8 \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{0}{7}$ | - |
| 196 | $\begin{aligned} & \text { EMIOS17_ETPUB1_ } \\ & \text { GPIO196 } \end{aligned}$ | P | EMIOS17 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE15 | AB15 |
|  |  | A1 | ETPUB1 | eTPU B channel | O |  |  |  |  |  |  |
|  |  | A2 | FR_DBG[2] | FlexRay debug | O |  |  |  |  |  |  |
|  |  | G | GPIO196 | GPIO | I/O |  |  |  |  |  |  |
| 197 | EMIOS18_ETPUB2_ GPIO197 | P | EMIOS18 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC15 | AD17 |
|  |  | A1 | ETPUB2 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | FR_DBG[1] | FlexRay debug | 0 |  |  |  |  |  |  |
|  |  | G | GPIO197 | GPIO | I/O |  |  |  |  |  |  |
| 198 | $\begin{aligned} & \text { EMIOS19_ETPUB3_ } \\ & \text { GPIO198 } \end{aligned}$ | P | EMIOS19 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD15 | AB16 |
|  |  | A1 | ETPUB3 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | FR_DBG[0] | FlexRay debug | 0 |  |  |  |  |  |  |
|  |  | G | GPIO198 | GPIO | I/O |  |  |  |  |  |  |
| 199 | $\begin{aligned} & \text { EMIOS20_ETPUB4_ } \\ & \text { GPIO199 } \end{aligned}$ | P | EMIOS20 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF16 | AF16 |
|  |  | A1 | ETPUB4 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO199 | GPIO | I/O |  |  |  |  |  |  |
| 200 | $\begin{aligned} & \text { EMIOS21_ETPUB5_ } \\ & \text { GPIO200 } \end{aligned}$ | P | EMIOS21 | eMIOS channel | I/O | MH | $V_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE16 | AE17 |
|  |  | A1 | ETPUB5 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO200 | GPIO | I/O |  |  |  |  |  |  |
| 201 | $\begin{aligned} & \text { EMIOS22_ETPUB6_ } \\ & \text { GPIO201 } \end{aligned}$ | P | EMIOS22 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC16 | AC16 |
|  |  | A1 | ETPUB6 | eTPU B channel | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO201 | GPIO | I/O |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)

| $$ | Signal Name ${ }^{2}$ | $\begin{aligned} & \text { N } \\ & \vdots \\ & \vdots \\ & \vdots \end{aligned}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \text { O } \\ & \text { IT } \\ & \hline 0 \end{aligned}$ | Stateduring RESET ${ }^{7}$ |  | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & 0 \\ & \underset{寸}{\prime} \end{aligned}$ | - |
| 202 | $\begin{aligned} & \text { EMIOS23_ETPUB7_ } \\ & \text { GPIO202 } \end{aligned}$ | P | EMIOS23 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD16 | AA16 |
|  |  | A1 | ETPUB7 | eTPU B channel | O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO202 | GPIO | I/O |  |  |  |  |  |  |
| 203 | $\begin{aligned} & \text { EMIOS24_PCSB0_ } \\ & \text { GPIO203 } \end{aligned}$ | P | EMIOS24 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF17 | AC17 |
|  |  | A1 | PCSB0 | DSPI B peripheral chip select | I/O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO203 | GPIO | I/O |  |  |  |  |  |  |
| 204 | $\begin{aligned} & \text { EMIOS25_PCSB1_ } \\ & \text { GPIO204 } \end{aligned}$ | P | EMIOS25 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE17 | AF18 |
|  |  | A1 | PCSB1 | DSPI B peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO204 | GPIO | I/O |  |  |  |  |  |  |
| 432 | $\begin{aligned} & \text { EMIOS26_PCSB2_ } \\ & \text { GPIO432 } \end{aligned}$ | P | EMIOS26 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AD17 | AE18 |
|  |  | A1 | PCSB2 | DSPI B peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO432 | GPIO | I/O |  |  |  |  |  |  |
| 433 | $\begin{aligned} & \text { EMIOS27_PCSB3_ } \\ & \text { GPIO433 } \end{aligned}$ | P | EMIOS27 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC17 | AD18 |
|  |  | A1 | PCSB3 | DSPI B peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO433 | GPIO | I/O |  |  |  |  |  |  |
| 434 | $\begin{aligned} & \text { EMIOS28_PCSCO_ } \\ & \text { GPIO434 } \end{aligned}$ | P | EMIOS28 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AF18 | AC18 |
|  |  | A1 | PCSC0 | DSPI C peripheral chip select | I/O |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO434 | GPIO | I/O |  |  |  |  |  |  |

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Table 39. Signal Properties and Muxing Summary (continued)

| $$ | Signal Name ${ }^{2}$ | $\begin{aligned} & \text { N } \\ & \vdots \\ & \vdots \\ & \vdots \end{aligned}$ | Function ${ }^{4}$ | Function Summary | $\begin{aligned} & \text { 들 } \\ & \text { U. } \\ & \text { U. } \end{aligned}$ |  | $\begin{aligned} & 0_{0} \\ & \text { O} \\ & \frac{\text { TH }}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package <br> Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & 0 \\ & 7 \end{aligned}$ | - |
| 435 | $\begin{aligned} & \text { EMIOS29_PCSC1_ } \\ & \text { GPIO435 } \end{aligned}$ | P | EMIOS29 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AE18 | AB17 |
|  |  | A1 | PCSC1 | DSPI C peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO435 | GPIO | I/O |  |  |  |  |  |  |
| 436 | $\begin{aligned} & \text { EMIOS30_PCSC2_ } \\ & \text { GPIO436 } \end{aligned}$ | P | EMIOS30 | eMIOS channel | I/O | MH | $V_{\text {DDEH } 4}$ | -/WKPCFG | -/WKPCFG | AD18 | AF19 |
|  |  | A1 | PCSC2 | DSPI C peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO436 | GPIO | I/O |  |  |  |  |  |  |
| 437 | $\begin{aligned} & \text { EMIOS31_PCSC5_ } \\ & \text { GPIO437 } \end{aligned}$ | P | EMIOS31 | eMIOS channel | I/O | MH | $\mathrm{V}_{\text {DDEH4 }}$ | -/WKPCFG | -/WKPCFG | AC18 | AA17 |
|  |  | A1 | PCSC5 | DSPI C peripheral chip select | 0 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO437 | GPIO | I/O |  |  |  |  |  |  |
| eQADC |  |  |  |  |  |  |  |  |  |  |  |
| - | ANAO | P | ANA0 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | V ${ }_{\text {DDA_A1 }}$ | ANAO | ANAO | A4 | A4 |
| - | ANA1 | P | ANA1 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA1 | ANA1 | B5 | B5 |
| - | ANA2 | P | ANA2 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA2 | ANA2 | C5 | C5 |
| - | ANA3 | P | ANA3 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | V DDA_A1 | ANA3 | ANA3 | D6 | D6 |
| - | ANA4 | P | ANA4 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA4 | ANA4 | A5 | A5 |
| - | ANA5 | P | ANA5 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA5 | ANA5 | B6 | B6 |
| - | ANA6 | P | ANA6 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA6 | ANA6 | C6 | C6 |
| - | ANA7 | P | ANA7 ${ }^{9}$ | eQADC A shared analog input | 1 | AE/updown | VDDA_A1 | ANA7 | ANA7 | D7 | C7 |

Table 39．Signal Properties and Muxing Summary（continued）

|  | へ | $\stackrel{\ominus}{4}$ | ¢ | « | $\stackrel{\infty}{\circ}$ | $\bigcirc$ | $\sim_{\propto}^{\infty}$ | $\stackrel{\infty}{¢}$ | 8 | 8 | $\begin{aligned} & \text { O} \\ & \hline 1 \end{aligned}$ | 엉 | $\underset{\Delta}{-7}$ | 거 | $\tilde{J}$ | $\underset{\sim}{\approx}$ | $\underset{\sim}{\infty}$ | $\underset{\sim}{0}$ | $\underset{\Delta}{m}$ | $\underset{\sim}{m}$ | $\underset{\underset{<}{4}}{\substack{2}}$ | $\underset{~}{\underset{\alpha}{d}}$ | $\underset{\sim}{\underset{\infty}{-1}}$ | $\underset{J}{J}$ | $\left\lvert\, \begin{aligned} & \stackrel{n}{0} \\ & \stackrel{1}{\infty} \end{aligned}\right.$ | $\stackrel{ \pm}{\square}$ | $\xrightarrow[\sim]{\sim}$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | \％ | ט̀ | ¢ | « | $\stackrel{\infty}{\circ}$ | $\bigcirc$ | ® | $\stackrel{\infty}{\text { ® }}$ | 8 | 8 | $\begin{aligned} & 0 \\ & 0 \end{aligned}$ | $0$ | $\stackrel{7}{2}$ | ت7 | $\underset{\sim}{7}$ | $\underset{\sim}{\sim}$ | $\underset{\sim}{\sim}$ | $\underset{\Delta}{m}$ | $\stackrel{m}{3}$ | $\underset{\infty}{m}$ | $\frac{m}{4}$ | $\underset{\sim}{\underset{\sim}{2}}$ | $\underset{J}{J}$ | $\underset{\Delta}{\Delta}$ | $\underset{~}{\underset{\pi}{~}}$ | $\stackrel{n}{\infty}$ | $\stackrel{\sim}{\sim}$ |
|  | $\sum_{<}^{\infty}$ | $\underset{<}{8}$ |  | $\underset{\substack{7 \\ \underset{<}{2} \\ \hline}}{ }$ | $\underset{\sim}{\underset{\sim}{c}}$ | $\begin{aligned} & \underset{\sim}{m} \\ & \underset{<}{2} \\ & \hline \end{aligned}$ | $\underset{\substack{~}}{\underset{~}{~}}$ | $\mid \stackrel{n}{\underset{\sim}{2}}$ | $\begin{array}{\|l\|l} 0 \\ \underset{y}{1} \\ \underset{<}{2} \end{array}$ |  | $\begin{aligned} & \infty \\ & \underset{\sim}{2} \\ & \underset{<}{2} \end{aligned}$ | $\underset{\substack{9 \\ \underset{<}{2} \\ \hline}}{ }$ |  | $\begin{aligned} & \underset{\sim}{\underset{N}{*}} \\ & \underset{y}{2} \end{aligned}$ | $\begin{aligned} & \underset{\sim}{N} \\ & \underset{\sim}{2} \end{aligned}$ | $\underset{\substack{\underset{\sim}{2} \\ \underset{\sim}{c}}}{ }$ | $\begin{aligned} & \underset{\sim}{N} \\ & \underset{<}{2} \end{aligned}$ | $\stackrel{\sim}{n}$ | $$ | $\stackrel{N}{N}$ | $\stackrel{\infty}{\underset{\sim}{\sim}}$ | $\begin{aligned} & \underset{N}{N} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & \text { O} \\ & \substack{2 \\ <~} \end{aligned}$ | $\stackrel{\substack{2 \\ \lll}}{ }$ | $\begin{aligned} & \tilde{N} \\ & \sum_{<}^{2} \end{aligned}$ | $\begin{gathered} m \\ \sum_{<}^{2} \\ \hline \end{gathered}$ | ¢ |
|  | $\sum_{\ll}^{\infty}$ | I | $\underset{\substack{0 \\ \underset{k}{\prime} \\ \hline}}{ }$ | $\begin{aligned} & \underset{\sim}{7} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & \underset{Z}{z} \\ & \underset{\sim}{4} \\ & \hline \end{aligned}$ |  |  | $\underset{\substack{n \\ \underset{\sim}{n} \\ \hline}}{ }$ |  | $\underset{\substack{\lambda \\ \underset{<}{2} \\ \hline}}{ }$ | $\underset{\substack{\infty \\ \underset{y}{c} \\ \underset{y}{c}}}{ }$ | $\underset{<}{\underset{\gamma}{7}}$ |  | $\underset{\substack{z}}{\underset{\sim}{\tilde{N}}}$ | $\underset{\substack{N \\ \underset{\sim}{N}\\}}{ }$ |  | $\underset{\substack{~ \\ \underset{\sim}{2} \\ \hline}}{ }$ | $\begin{array}{\|l} \stackrel{n}{N} \\ \underset{<}{2} \end{array}$ | $\begin{aligned} & 0 \\ & {\underset{\sim}{2}}^{N} \end{aligned}$ | $\stackrel{N}{\underset{\sim}{2}}$ | $\stackrel{\infty}{\infty}$ | 沗 | $\underset{\substack{\mathrm{m}}}{\substack{2}}$ | $\stackrel{\substack{n \\ \lll}}{ }$ | $\begin{aligned} & \mathbb{N} \\ & \underset{\sim}{2} \end{aligned}$ | $\sum_{<}^{\infty}$ | $\underset{\text { m }}{\substack{\text { m }}}$ |
|  | － | － |  |  |  |  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & \vec{x} \\ & \stackrel{\rightharpoonup}{\prime} \\ & > \\ & > \end{aligned}$ |  |  |  |  | $\begin{aligned} & \hline 8 \\ & \substack{1 \\ 0 \\ >\\ \hline} \end{aligned}$ |  | $\begin{array}{\|l\|l\|} \hline \stackrel{\rightharpoonup}{\infty} \\ \stackrel{1}{\prime} \\ 0 \\ \hline \end{array}$ |  | $\begin{array}{\|c\|} \hline \vec{m}_{1} \\ \hat{a}^{\prime} \\ > \end{array}$ |  | － |
| ${ }_{\mathrm{s}} \mathrm{Vd}^{\prime} K_{\perp} \mathrm{ped}$ | 亗 | 区 | щ | 㞤 | 㞤 | щ | 岸 | щ | 岸 | 区 | 㞤 | 亗 | щ | 亗 | 亗 | щ | 岂 | 亗 | щ | 岂 | 亗 | 亗 | 岂 | 亗 | 亗 | 岸 | щ |
| ио！ヤวə！！ | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － | － |
|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
|  | ${\underset{<}{c}}_{\substack{\infty \\ \hline}}$ | $\underset{<}{\underset{<}{2}}$ | $\underset{<}{\underset{\sim}{1}}$ | $\underset{\substack{7 \\ \underset{<}{2} \\ \hline}}{ }$ | $\underset{~}{\underset{Z}{2}}$ | $\begin{aligned} & m \\ & \underset{y}{c} \\ & \sum_{<} \end{aligned}$ | $\underset{\substack{~}}{\underset{~}{\lambda}}$ | $\underset{<}{\underset{\sim}{n}} \underset{\substack{n \\ \hline}}{ }$ | $\begin{aligned} & 0 \\ & \underset{\sim}{c} \\ & \underset{<}{2} \end{aligned}$ |  | $\begin{aligned} & \infty \\ & \underset{\sim}{2} \\ & \underset{<}{2} \end{aligned}$ | $\underset{<}{\underset{\sim}{7}}$ | $\underset{\substack{\mathrm{O} \\ \underset{<}{2} \\ \hline}}{ }$ | $\underset{\varangle}{\underset{\sim}{\underset{N}{2}}}$ | $\underset{\substack{N} \underset{\sim}{N}}{\substack{2}}$ |  | $\begin{aligned} & \underset{\sim}{~} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & n \\ & \underset{4}{2} \\ & \hline \end{aligned}$ | $\begin{aligned} & \stackrel{0}{N} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & N \\ & \underset{\sim}{2} \\ & \hline \end{aligned}$ | $\stackrel{\infty}{\sim}$ | $\begin{aligned} & \text { N} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & \text { O} \\ & \sum_{<}^{2} \end{aligned}$ | $\stackrel{\substack{m \\<\\<}}{ }$ | $\begin{aligned} & \underset{N}{N} \\ & \sum_{<} \end{aligned}$ | $\begin{gathered} \infty \\ \sum_{<}^{2} \end{gathered}$ |  |
| $\varepsilon$ ¢ ${ }^{\text {O／V／d }}$ | 0 | Q | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | Q | 0 | 0 | Q | 0 | 0 | 0 | Q | 0 | Q | 0 | 0 | Q | 0 | Q |
|  | $\underset{<}{\infty}$ | $\underset{<}{8}$ | $$ | $\underset{\substack{7 \\ \underset{<}{2} \\ \hline}}{ }$ | $\underset{\sim}{\tilde{y}}$ | $\underset{\substack{m \\ \underset{<}{4}}}{ }$ |  | $\underset{\substack{n \\ \underset{\alpha}{\prime} \\ \hline}}{ }$ | $\begin{aligned} & 0 \\ & \vdots \\ & \underset{~}{2} \\ & \ll \end{aligned}$ | $\underset{\substack{\lambda \\ \vec{y} \\ \gtrless}}{ }$ | $\underset{\substack{\infty \\ \underset{<}{1} \\ \hline \\ \hline}}{ }$ | $\underset{\substack{9 \\ \underset{<}{\prime} \\ \hline}}{ }$ |  |  | $\begin{array}{\|c} \underset{N}{N} \\ \underset{<}{2} \end{array}$ |  | $\begin{gathered} \underset{\sim}{N} \\ \underset{<}{2} \end{gathered}$ | $\begin{aligned} & n \\ & \underset{<}{2} \end{aligned}$ | $$ | $\stackrel{N}{N}$ | $\stackrel{\infty}{N}$ | $\begin{aligned} & \underset{N}{N} \\ & \underset{<}{2} \end{aligned}$ | $\begin{aligned} & 0 \\ & \sum_{4} \\ & \hline \end{aligned}$ | $\stackrel{\underset{\sim}{m}}{\substack{2}}$ | $\begin{aligned} & \tilde{N} \\ & \sum_{<}^{2} \end{aligned}$ | $\begin{gathered} \underset{\sim}{2} \\ \sum_{<} \end{gathered}$ | ¢ |
|  | 1 | ｜ | 1 | ｜ | 1 | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ | ｜ |

Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ | $\stackrel{N}{\substack{\mathrm{a}}}$ | Function ${ }^{4}$ | Function Summary |  | $\begin{aligned} & \text { n } \\ & \frac{0}{\lambda} \\ & \frac{0}{\pi} \end{aligned}$ | $\begin{aligned} & 0 \\ & \stackrel{0}{\pi} \\ & \frac{\pi}{0} \\ & \hline \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{\ominus}{7}$ | 0 <br>  |
| - | AN35 | P | AN35 | eQADC analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | AN35 | AN35 | D15 | D15 |
| - | AN36 | P | AN36 | eQADC analog input | 1 | AE | $V_{\text {DDA_B1 }}$ | AN36 | AN36 | A15 | A15 |
| - | AN37 | P | AN37 | eQADC analog input | 1 | AE | VDDA_B0 | AN37 | AN37 | C16 | C17 |
| - | AN38 | P | AN38 | eQADC analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | AN38 | AN38 | C17 | D16 |
| - | AN39 | P | AN39 | eQADC analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | AN39 | AN39 | D16 | C16 |
| - | ANB0 | P | ANB0 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B0 }}$ | ANB0 | ANB0 | C18 | C18 |
| - | ANB1 | P | ANB1 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B0 }}$ | ANB1 | ANB1 | D17 | D17 |
| - | ANB2 | P | ANB2 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B }}$ | ANB2 | ANB2 | D18 | D18 |
| - | ANB3 | P | ANB3 | eQADC B shared analog input | । | AE/updown | V ${ }_{\text {DDA_B }}$ | ANB3 | ANB3 | D19 | D19 |
| - | ANB4 | P | ANB4 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B }}$ | ANB4 | ANB4 | C19 | B19 |
| - | ANB5 | P | ANB5 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B }}$ | ANB5 | ANB5 | C20 | A20 |
| - | ANB6 | P | ANB6 | eQADC B shared analog input | 1 | AE/updown | $\mathrm{V}_{\text {DDA_B }}$ | ANB6 | ANB6 | B19 | C20 |
| - | ANB7 | P | ANB7 | eQADC B shared analog input | 1 | AE/updown | V ${ }_{\text {DDA_B }}$ | ANB7 | ANB7 | A20 | C19 |
| - | ANB8 | P | ANB8 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB8 | ANB8 | B20 | B20 |
| - | ANB9 | P | ANB9 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB9 | ANB9 | D20 | A21 |
| - | ANB10 | P | ANB10 | eQADC B analog input | 1 | AE | VDDA_B0 | ANB10 | ANB10 | B21 | B21 |
| - | ANB11 | P | ANB11 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB11 | ANB11 | A21 | C21 |
| - | ANB12 | P | ANB12 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB12 | ANB12 | C21 | A22 |
| - | ANB13 | P | ANB13 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | ANB13 | ANB13 | D21 | B22 |
| - | ANB14 | P | ANB14 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB14 | ANB14 | A22 | D20 |
| - | ANB15 | P | ANB15 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B }}$ | ANB15 | ANB15 | B22 | C22 |
| - | ANB16 | P | ANB16 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | ANB16 | ANB16 | C22 | D21 |

Table 39. Signal Properties and Muxing Summary (continued)

| $\begin{aligned} & \text { rax } \\ & \text { nun } \end{aligned}$ | Signal Name ${ }^{2}$ | $\begin{gathered} \text { NO } \\ \vdots \\ \vdots \end{gathered}$ | Function ${ }^{4}$ | Function Summary |  | $\begin{aligned} & n_{0}^{\circ} \\ & \stackrel{2}{\lambda} \\ & \frac{0}{0} \\ & \hline \end{aligned}$ |  | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\frac{0}{0}$ |  |  |  |  |  |  |  |  |  | $\stackrel{0}{7}$ | - |
| - | ANB17 | P | ANB17 | eQADC B analog input | 1 | AE | $\mathrm{V}_{\text {DDA_B }}$ | ANB17 | ANB17 | A23 | D22 |
| - | ANB18 | P | ANB18 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | ANB18 | ANB18 | B23 | A23 |
| - | ANB19 | P | ANB19 | eQADC B analog input | 1 | AE | $\mathrm{V}_{\text {DDA_B0 }}$ | ANB19 | ANB19 | C23 | B23 |
| - | ANB20 | P | ANB20 | eQADC B analog input | 1 | AE | $\mathrm{V}_{\text {DDA_B0 }}$ | ANB20 | ANB20 | D22 | C23 |
| - | ANB21 | P | ANB21 | eQADC B analog input | 1 | AE | V ${ }_{\text {DDA_B0 }}$ | ANB21 | ANB21 | A24 | A24 |
| - | ANB22 | P | ANB22 | eQADC B analog input | 1 | AE | $V_{\text {DDA_B0 }}$ | ANB22 | ANB22 | B24 | B24 |
| - | ANB23 | P | ANB23 | eQADC B analog input | 1 | AE | $\mathrm{V}_{\text {DDA_B }}$ | ANB23 | ANB23 | A25 | E20 |
| - | VRH_A | P | VRH_A | ADC A Voltage reference high | 1 | VDDINT | $\mathrm{V}_{\text {RH_A }}$ | VRH_A | VRH_A | A12 | A12 |
| - | VRL_A | P | VRL_A | ADC A Voltage reference low | 1 | VSSINT | $\mathrm{V}_{\text {RL_A }}$ | VRL_A | VRL_A | A11 | A11 |
| - | VRH_B | P | VRH_B | ADC B Voltage reference high | 1 | VDDINT | $\mathrm{V}_{\text {RH_B }}$ | VRH_B | VRH_B | A19 | A19 |
| - | VRL_B | P | VRL_B | ADC B Voltage reference low | 1 | VSSINT | $\mathrm{V}_{\text {RL_B }}$ | VRL_B | VRL_B | A18 | A18 |
| - | REFBYPCB | P | REFBYPCB | ADC B Reference bypass capacitor | 1 | AE | $\mathrm{V}_{\text {DDA_B0 }}$ | REFBYPCB | REFBYPCB | B18 | B18 |
| - | REFBYPCA | P | REFBYPCA | ADC A Reference bypass capacitor | 1 | AE | $V_{\text {DDA_A1 }}$ | REFBYPCA | REFBYPCA | B11 | B11 |
| - | VDDA_A0 | P | VDDA_A | Internal logic supply input | 1 | VDDE | V ${ }_{\text {DDA_A }}$ | VDDA_A0 | VDDA_A0 | A9 | A9 |
| - | VDDA_A1 | P | VDDA_A | Internal logic supply input | 1 | VDDE | $V_{\text {DDA_A1 }}$ | VDDA_A1 | VDDA_A1 | B9 | B9 |
| - | REFBYPCA1 | P | REFBYPCA1 | ADC A Reference bypass capacitor | 1 | AE | VDDA_A1 | REFBYPCA1 | REFBYPCA1 | A10 | A10 |
| - | VSSA_A1 | P | VSSA_A | Ground | 1 | VSSE | $\mathrm{V}_{\text {SSA_A1 }}$ | VSSA_A1 | VSSA_A1 | B10 | B10 |
| - | VDDA_B0 | P | VDDA_B | Internal logic supply input | 1 | VDDE | $V_{\text {DDA_B }}$ | VDDA_B0 | VDDA_B0 | A16 | A16 |
| - | VDDA_B1 | P | VDDA_B | Internal logic supply input | 1 | VDDE | $V_{\text {DDA_B1 }}$ | VDDA_B1 | VDDA_B1 | B16 | B16 |
| - | VSSA_B0 | P | VSSA_B | Ground | 1 | VSSE | $\mathrm{V}_{\text {SSA_B }}$ | VSSA_B0 | VSSA_B0 | B17 | B17 |
| - | REFBYPCB1 | P | REFBYPCB1 | ADC B Reference bypass capacitor | 1 | AE | V ${ }_{\text {DDA_B0 }}$ | REFBYPCB1 | REFBYPCB1 | A17 | A17 |
| FlexRay |  |  |  |  |  |  |  |  |  |  |  |
| 248 | $\begin{aligned} & \text { FR_A_TX } \\ & \text { GPIO248 } \end{aligned}$ | P | FR_A_TX | FlexRay A transfer | 0 | FS | $\mathrm{V}_{\text {DDE2 }}$ | $\begin{aligned} & \text {-/Up } \\ & \text { (-/- for Rev. } 1 \\ & \text { of the device) } \end{aligned}$ | $\begin{aligned} & \text {-/Up } \\ & \text { (-/- for Rev. } 1 \\ & \text { of the device) } \end{aligned}$ | AD4 | AD4 |
|  |  | A1 | - | - | - |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO248 | GPIO | I/O |  |  |  |  |  |  |

Table 39. Signal Properties and Muxing Summary (continued)


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Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39．Signal Properties and Muxing Summary（continued）

|  | $\begin{aligned} & \underset{\sim}{\sim} \\ & \underset{\sim}{\alpha} \end{aligned}$ |  |  | $$ |  |  |  | $\stackrel{\text { N }}{\text { N }}$ |  |  |  | N0® |  |  |  | さ |  |  |  | $\stackrel{\text { N }}{\text { N }}$ |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | I |  |  | I |  |  |  | ｜ |  |  |  | I |  |  |  | I |  |  |  | 1 |  |  |  |
|  | $\stackrel{2}{2}$ |  |  | $\stackrel{\varrho}{\imath}$ |  |  |  | $\stackrel{2}{1}$ |  |  |  | $\frac{2}{1}$ |  |  |  | $\stackrel{2}{1}$ |  |  |  | $\stackrel{\varrho}{\imath}$ |  |  |  |
|  | $\stackrel{\varrho}{1}$ |  |  | $\stackrel{2}{1}$ |  |  |  | $\stackrel{\varrho}{1}$ |  |  |  |  |  |  |  | $\xlongequal{\imath}$ |  |  |  | $\stackrel{\varrho}{\imath}$ |  |  |  |
| ${ }_{9}$ әберо＾ | $\begin{array}{l\|l\|} \hline \stackrel{0}{0} \\ 0 \\ > \end{array}$ |  |  | $\left\lvert\, \begin{gathered} \text { 亗 } \\ \text { > } \end{gathered}\right.$ |  |  |  | $\begin{array}{\|l} 0 \\ \text { 岂 } \\ 0 \\ > \end{array}$ |  |  |  | $\begin{array}{\|l\|} \hline 0 \\ \text { 岂 } \\ 0 \\ > \end{array}$ |  |  |  | $\begin{array}{\|c} 0 \\ \stackrel{3}{u} \\ 0 \\ > \end{array}$ |  |  |  | $\begin{array}{\|l\|l\|} 0 \\ \text { 夏 } \end{array}$ |  |  |  |
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| ио！̣эəハ！ | $\bigcirc \bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | 1 | $\bigcirc$ | $\bigcirc$ | I | 1 | $\bigcirc$ | $\bigcirc$ | 1 | ｜ | $\bigcirc$ | $\bigcirc$ | 1 | 1 | $\bigcirc$ | $\bigcirc$ | ｜ | ｜ | $\bigcirc$ |
|  |  | 1 | $\frac{0}{0}$ |  | Address and data in mux mode． | ｜ | $\frac{\mathrm{O}}{\mathrm{O}}$ |  | 1 | 1 | $\frac{\mathrm{O}}{0}$ |  | 1 | ｜ | $\frac{\mathrm{O}}{\mathrm{O}}$ |  | 1 | 1 | $\begin{array}{\|l} \mathrm{O} \\ \hline 0 \end{array}$ |  | ｜ | ｜ | $\bigcirc$ |
|  |  | 1 | $\begin{aligned} & 0 \\ & \stackrel{0}{N} \\ & \frac{0}{n} \\ & 0 \end{aligned}$ | $\left\lvert\, \begin{aligned} & 0 \\ & 0 \\ & 0 \\ & \underset{ष}{4} \\ & 0 \\ & 0 \end{aligned}\right.$ |  | 1 | $\begin{aligned} & \text { N } \\ & \text { N } \\ & \underline{O} \\ & 0 \end{aligned}$ |  | 1 | ｜ | $\begin{aligned} & \infty \\ & \stackrel{\sim}{N} \\ & \underset{0}{0} \\ & 0 \end{aligned}$ | $\begin{aligned} & \stackrel{\rightharpoonup}{\mid} \\ & \stackrel{\rightharpoonup}{4} \\ & \vdots \\ & \vdots \\ & \stackrel{1}{4} \\ & 0 \end{aligned}$ | 1 | 1 |  |  | 1 | 1 | O |  | 1 | ｜ | （1） |
| $\varepsilon$ ¢ ${ }^{\text {P／V／d }}$ | －を | ※ | $\bigcirc$ | － | を | § | $\bigcirc$ | Q | を | ※ | $\bigcirc$ | － | 『 | ※ | $\bigcirc$ | Q | を | さ | $\bigcirc$ | Q | を | ※ | $\bigcirc$ |
|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| ¿ ${ }^{\text {cod／Old }}$ | $\stackrel{0}{N}$ |  |  | $\underset{N}{N}$ |  |  |  | $\stackrel{\infty}{\sim}$ |  |  |  | $\stackrel{\stackrel{\rightharpoonup}{N}}{\sim}$ |  |  |  | $\underset{\sim}{\infty}$ |  |  |  | $\underset{\sim}{\infty}$ |  |  |  |

MPC5676R Microcontroller Data Sheet，Rev． 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)


MPC5676R Microcontroller Data Sheet, Rev. 4
Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ | $\frac{N}{\vdots}$ | Function ${ }^{4}$ | Function Summary |  |  | $\begin{aligned} & 0 \\ & \text { O } \\ & \frac{\mathbb{T}}{0} \\ & 8 \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{aligned} & \text { State } \\ & \text { after } \\ & \text { RESET }^{8} \end{aligned}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\stackrel{O}{7}$ | - |
| 212 | $\begin{aligned} & \text { BOOTCFG1_IRQ3_ } \\ & \text { GPIO212 } \end{aligned}$ | P | BOOTCFG1 | Boot configuration | 1 | MH | $\mathrm{V}_{\text {DDEH1 }}$ | BOOTCFG/ Down | -/Down | N2 | L3 |
|  |  | A1 | IRQ3 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO212 | GPIO | I/O |  |  |  |  |  |  |
| 213 | $\begin{aligned} & \text { WKPCFG_NMI_ } \\ & \text { GPIO213 }{ }^{10} \end{aligned}$ | P | WKPCFG | Weak pull configuration input | 1 | MH | $V_{\text {DDEH1 }}$ | WKPCFG/Up | -/Up | N3 | M5 |
|  |  | A1 |  |  |  |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO213 | GPIO | 1 |  |  |  |  |  |  |
| 208 | $\begin{aligned} & \text { PLLCFGO_IRQ4_ } \\ & \text { GPIO208 } \end{aligned}$ | P | PLLCFG0 | FMPLL mode configuration input | 1 | MH | $\mathrm{V}_{\text {DDEH } 1}$ | PLLCFG/Up | -IUp | R3 | M3 |
|  |  | A1 | IRQ4 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | - | - | - |  |  |  |  |  |  |
|  |  | G | GPIO208 | GPIO | I/O |  |  |  |  |  |  |
| 209 | PLLCFG1_IRQ5_GPIO209 | P | PLLCFG1 | FMPLL mode configuration input | 1 | MH | $\mathrm{V}_{\text {DDEH1 }}$ | PLLCFG/Up | -/Up | P2 | L1 |
|  |  | A1 | IRQ5 | External interrupt request | 1 |  |  |  |  |  |  |
|  |  | A2 | SOUTD | DSPI D data output | 0 |  |  |  |  |  |  |
|  |  | G | GPIO209 | GPIO | I/O |  |  |  |  |  |  |
| - | PLLCFG2 | P | PLLCFG2 | FMPLL mode configuration input | I | MH | $V_{\text {DDEH } 1}$ | PLLCFG/ <br> Down | $\begin{gathered} -1 \\ \text { Down } \end{gathered}$ | P3 | L2 |
| - | XTAL | P | XTAL | Crystal oscillator output | O | AE | $\mathrm{V}_{\text {DD33 }}$ | XTAL | XTAL | AC26 | AC26 |
| - | EXTAL | P | EXTAL | Crystal oscillator input | 1 | AE | $\mathrm{V}_{\text {DD33 }}$ | EXTAL | EXTAL | AB26 | AB26 |
| 229 | D_CLKOUT | P | D_CLKOUT | EBI system clock output | 0 | F | $\mathrm{V}_{\text {DDE9 }}$ | CLKOUT/ Enabled | CLKOUT/ <br> Enabled | - | AF12 |
| 214 | ENGCLK | P | ENGCLK | EBI engineering clock output Note: EXTCLK (External clock input) selected through SIU register) | O | F | $\mathrm{V}_{\text {DDE2 }}$ | ENGCLK/ <br> Enabled | ENGCLK/ <br> Enabled | AD1 | AD1 |
| JTAG and Nexus (see footnote ${ }^{11}$ about resets) |  |  |  |  |  |  |  |  |  |  |  |
| - | EVTI | - ${ }^{12}$ | EVTI | Nexus event in | 1 | F | $V_{\text {DDE2 }}$ | -/Up | EVTI/Up | T4 | V1 |

Table 39. Signal Properties and Muxing Summary (continued)

Table 39. Signal Properties and Muxing Summary (continued)

Table 39．Signal Properties and Muxing Summary（continued）

| ¢ ¢ 9 9 | $\pm$ |  |  |  | $\stackrel{\text { ® }}{ }$ |  |  |  | $\underset{4}{4}$ |  |  |  | $\underset{\mathbb{Z}}{\mathbb{Z}}$ |  |  |  | $\stackrel{m}{4}$ |  |  |  | 9 | $\stackrel{1}{9}$ | $\stackrel{9}{3}$ | $\underset{\sim}{\underset{\alpha}{<}}$ | N | 蓠 | 毎 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ®ั | $\stackrel{\sim}{\sim}$ |  |  |  | $\overrightarrow{\mathbb{K}}$ |  |  |  | $\underset{\mathbb{K}}{N}$ |  |  |  | $\underset{\mathbb{Z}}{\mathbb{K}}$ |  |  |  | $\pm$ |  |  |  | N | $\stackrel{\sim}{\bullet}$ | 枵 | $\begin{array}{\|l\|l\|} \stackrel{\sim}{<} \\ \hline \end{array}$ | $\underset{\sim}{\tilde{\alpha}}$ | 安 | 癷 |
|  | $\underset{\uparrow}{\substack{0 \\ 0}}$ |  |  |  | $\begin{aligned} & \text { n } \\ & 0 \\ & 0 \\ & \hline \end{aligned}$ |  |  |  | $\left\lvert\, \begin{aligned} & \stackrel{y}{c} \\ & 0 \\ & \end{aligned}\right.$ |  |  |  | $\begin{aligned} & \text { n } \\ & 0 \\ & \\ & \end{aligned}$ |  |  |  |  |  |  |  | $\begin{aligned} & \overline{1} \\ & 0 \\ & \underset{\sim}{u} \\ & \underline{n} \end{aligned}$ |  | $\begin{aligned} & \stackrel{\rightharpoonup}{x} \\ & \underset{\sim}{\text { 人}} \end{aligned}$ | $\begin{aligned} & \frac{1}{u} \\ & 0 \\ & \vdots \\ & \vdots \\ & \end{aligned}$ | $\frac{\stackrel{\circ}{2}}{\stackrel{\rightharpoonup}{\ominus}}$ | $\begin{aligned} & \mathrm{O} \\ & \stackrel{\rightharpoonup}{\mathrm{O}} \\ & \mathrm{O} \end{aligned}$ | $\stackrel{\circ}{\sum}$ |
|  | $\stackrel{3}{0}$ |  |  |  | $\begin{aligned} & 3 \\ & 0 \\ & 0 \\ & 0 \end{aligned}$ |  |  |  | $\begin{aligned} & 30 \\ & \\ & \hline 1 \end{aligned}$ |  |  |  | $\stackrel{3}{0}$ |  |  |  |  |  |  |  | $\begin{aligned} & 3 \\ & 0 \\ & 0 \\ & 0 \end{aligned}$ | $\stackrel{3}{0}$ | $\begin{aligned} & 30 \\ & 0 \\ & \frac{3}{0} \end{aligned}$ |  | $\stackrel{\cap}{\stackrel{\rightharpoonup}{2}}$ | $\begin{aligned} & \mathrm{O} \\ & \stackrel{\rightharpoonup}{\mathrm{O}} \\ & \mathrm{O} \end{aligned}$ | $\sum_{i}^{\stackrel{N}{N}}$ |
|  | $\begin{aligned} & \text { ั̈ } \\ & \text { > } \end{aligned}$ |  |  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & \text { జ̈ } \\ & \text { خ } \end{aligned}$ |  |  |  | $\begin{gathered} \text { జ̈ } \\ \text { > } \end{gathered}$ |  |  |  | ＞ | ＞ | ＞ | ＞ | ） | ＞ | ＞ |
| $\mathrm{g}^{\text {əd }} K_{\perp} \mathrm{pe}_{\text {d }}$ | น |  |  |  | เ |  |  |  | น |  |  |  | ц |  |  |  | น |  |  |  | น | ц ц |  | ц | ц и |  | น |
| ио！ฺэə！】 | 0 | 1 | 1 | $\bigcirc$ | 0 | 1 | ｜ | $\bigcirc$ | 0 | 1 | ｜ | $\bigcirc$ | $\bigcirc$ | 1 | 1 | $\bigcirc$ | $\bigcirc$ | 1 | ｜ | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | $\bigcirc$ | － | － | $\bigcirc$ | － |
|  |  | 1 | 1 | $\frac{0}{0}$ |  | 1 | I | $\frac{0}{0}$ |  | 1 | 1 | $\frac{\mathrm{O}}{\mathrm{O}}$ |  | 1 | 1 | $\frac{0}{0}$ |  | ｜ | ｜ | $\frac{0}{0}$ |  |  |  |  |  |  |  |
|  |  | 1 | 1 | $\begin{aligned} & \text { N } \\ & \underline{O} \\ & \end{aligned}$ | $\begin{aligned} & \underset{\sim}{I} \\ & \underset{\sim}{O} \\ & \underset{\Sigma}{n} \end{aligned}$ | 1 | \｜ | $\begin{aligned} & \underset{N}{N} \\ & \underline{0} \\ & 0 \end{aligned}$ | $\begin{array}{\|l} { }_{2}^{7} \\ 0 \\ 0 \\ 0 \\ 0 \\ \end{array}$ | 1 | 1 | $\begin{aligned} & \mathbb{N} \\ & \underset{N}{0} \\ & \underline{0} \\ & 0 \end{aligned}$ |  | 1 | 1 |  | O | 1 | ｜ | $\begin{aligned} & \text { H } \\ & \underset{N}{0} \\ & \underline{0} \\ & 0 \end{aligned}$ |  | $\begin{aligned} & \underset{A}{A} \\ & \underset{\sim}{3} \\ & \underset{\Sigma}{n} \end{aligned}$ | $\begin{aligned} & \stackrel{\rightharpoonup}{\text { 人̀ }} \end{aligned}$ | $\stackrel{\stackrel{\rightharpoonup}{\mathrm{U}}}{ }$ | $\stackrel{\bar{O}}{\vdash}$ | $\stackrel{\mathrm{O}}{\mathrm{O}}$ | $\sum_{1}^{\infty}$ |
| $\varepsilon$ ¢ ${ }^{\text {O／V／d }}$ | ${ }_{1}$ | を | ※ | $\bigcirc$ | ${ }_{7}$ | を | ๕ | $\bigcirc$ | $\underset{1}{1}$ | を | さ | $\bigcirc$ | ${ }_{1}$ | を | ๕ | $\bigcirc$ | ${ }_{1}$ | 『 | ※ | $\bigcirc$ | $\overbrace{1}$ | $\overbrace{1}$ | $\overbrace{1}$ | $\overbrace{1}$ | $\overbrace{1}$ | ${ }_{1}$ | $\overbrace{1}$ |
|  |  |  |  |  | $\begin{aligned} & \underset{\sim}{N} \\ & \underline{N} \\ & \underline{0} \\ & 0 \\ & \tilde{N}^{\prime} \\ & 0 \\ & \end{aligned}$ |  |  |  | $\begin{aligned} & \tilde{N} \\ & 0 \\ & 0 \\ & 0 \\ & 0 \\ & N_{1} \\ & 0 \\ & 0 \\ & \end{aligned}$ |  |  |  |  |  |  |  | H 0 0 0 0 0 10 0 0 2 |  |  |  | $\left\lvert\, \begin{gathered} 8 \\ \underset{\sim}{u} \\ \underset{n}{n} \\ \hline \end{gathered}\right.$ | $\\| \begin{aligned} & -1 \\ & \underset{\sim}{u} \\ & \sum_{n} \end{aligned}$ | $\begin{aligned} & \stackrel{\rightharpoonup}{\mathrm{a}} \end{aligned}$ | $\underset{\sim}{\mathrm{U}}$ | $\bar{\square}$ | $\stackrel{\mathrm{O}}{\mathrm{O}}$ | $\sum_{1}^{\infty}$ |
| ¢ ${ }^{\text {yOd／Old }}$ | ～ |  |  |  | $\underset{\sim}{\sim}$ |  |  |  | $\underset{\sim}{\sim}$ |  |  |  | $\underset{\sim}{N}$ |  |  |  | $\underset{\sim}{\text { N }}$ |  |  |  | $\underset{\sim}{\underset{N}{2}}$ | $\stackrel{\sim}{N}$ | $\stackrel{\sim}{N}$ | 1 | ｜ | $\stackrel{\sim}{\sim}$ | 1 |

Table 39. Signal Properties and Muxing Summary (continued)

|  | Signal Name ${ }^{2}$ | $\begin{aligned} & \text { M } \\ & \vdots \\ & \vdots \\ & \hline \end{aligned}$ | Function ${ }^{4}$ | Function Summary |  | $\begin{aligned} & \text { n } \\ & \frac{0}{\lambda} \\ & \frac{0}{\pi} \\ & \hline \end{aligned}$ | $\begin{aligned} & 0_{0}^{0} \\ & \frac{\pi}{0} \\ & \frac{0}{0} \end{aligned}$ | Stateduring RESET ${ }^{7}$ | $\begin{gathered} \text { State } \\ \text { after } \\ \text { RESET }{ }^{8} \end{gathered}$ | Package Location |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  | $\begin{aligned} & 9 \\ & \underset{\gamma}{2} \end{aligned}$ | $$ |
| - | JCOMP | -12 | JCOMP | JTAG TAP controller enable | 1 | F | $V_{\text {DDE2 }}$ | JCOMP/Down | JCOMP/Down | R1 | U2 |
| - | TEST | - | TEST | Test mode select (not for customer use) | 1 | F | $V_{\text {DDEH1 }}$ | TEST/Down | TEST/Down | B4 | B4 |
| - | VDDSYN | - | VDDSYN | Clock synthesizer power input | 1/O | VDDE | $\mathrm{V}_{\text {DDSYN }}$ | VDDSYN | VDDSYN | AD26 | AD26 |
| - | VSSSYN | - | VSSSYN | Clock synthesizer ground input | 1 | VSSE | $\mathrm{V}_{\text {DDSYN }}$ | VSSSYN | VSSSYN | AA26 | AA26 |
| - | VSTBY | - | VSTBY | SRAM standby power input | 1 | VHV | $V_{\text {DDEH1 }}$ | VSTBY | VSTBY | M4 | M4 |
| - | REGSEL | - | REGSEL | Selects regulator mode (Linear/Switch mode) | I | AE | $V_{\text {DDREG }}$ | REGSEL | REGSEL | W23 | W23 |
| - | REGCTL | - | REGCTL | Regulator controller output to base/gate of power transistor | O | AE | $\mathrm{V}_{\text {DDREG }}$ | REGCTL | REGCTL | Y26 | Y26 |
| - | VSSFL | - | VSSFL | Tie to $\mathrm{V}_{\text {SS }}$ | 1 | VSS | $V_{\text {DDREG }}$ | VSSFL | VSSFL | AB25 | AB25 |
| - | VDDREG | - | VDDREG | Source voltage for on-chip regulators and Low voltage detect circuits | 1 | VDDINT | $V_{\text {DDREG }}$ | VDDREG | VDDREG | AA25 | AA25 |

The GPIO number is the same as the corresponding pad configuration register (SIU_PCRn) number in pins that have GPIO functionality. For pins that do not have GPIO functionality, this number is the PCR number.
2 The primary signal name is used as the pin label on the BGA map for identification purposes. However, the primary signal function is not available on all devices and is indicated by a dash in the following table columns: Signal Functions, P/F/G, and I/O Type.
3 P/A/G stands for Primary/Alternate/GPIO . This column indicates which function on a pin is Primary, Alternate 1, Alternate 2, (Alternate $n$ ) and GPIO.
4 Each line in the Function column corresponds to a separate signal function on the pin. For all device I/O pins, the primary, alternate, or GPIO signal functions are designated in the PA field of the SIU_PCRn registers except where explicitly noted
$5 \mathrm{MH}=$ High voltage, medium speed
F = Fast speed
AE A Alog with ESD protection circuitry (up/down = pull up and pull down circuits included in the pad)
VHV = Very high voltage
6 VDDE (fast I/O) and VDDEH (slow I/O) power supply inputs are grouped into segments. Each segment of VDDEH pins can connect to a separate $3.3-5.0 \mathrm{~V}$ $(+5 \% /-10 \%)$ power supply input. Each segment of VDDE pins can connect to a separate $1.8-3.3 \mathrm{~V}( \pm 10 \%)$ power supply.
7 All pins are sampled after the internal POR is negated. The terminology used in this column is: O-output, I - input, Up - weak pull up enabled, Down - weak pulldown enabled, Low - output driven low, High - output driven high, ABS - Auto Baud Select (during Reset or until JCOMP assertion). A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin. The signal name to the left or right of the slash indicates the pin is enabled.
8 The Function After Reset of a GPI function is general purpose input. A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin.
9 During and just after POR negates, internal pull resistors can be enabled, resulting in as much as 4 mA of current draw. The pull resistors are disabled when the system clock propagates through the device

[^1]
## Appendix B Revision History

Table 40 describes the changes made to this document between revisions.
Table 40. Revision History

| Revision | Date | Description |
| :---: | :---: | :---: |
| Rev 1 | 5 Aug 2011 | Initial customer release |
| Rev 2 | 21 Dec 2011 | Added information about specs 1a through 1d in the PMC Electrical Specifications table. <br> Updated the footnote reference (changed from ${ }^{13}$ to ${ }^{14}$ ) of spec 18 of the PMC Electrical Specifications table. <br> Updated the Operating Current 5.0 V Supplies @ fsys $=180 \mathrm{MHz}$ VDDA Max value (changed from 30 to 50). <br> Updated footnote ${ }^{1}$ of the VDD33 Pad Average DC Current table (changed IDDE to IDD33). <br> Updated the pF value of 11 SRC/DSC Fast with Slew Rate (changed from 2.6 to 200) in the Pad AC Specifications (VDDEH $=5.0 \mathrm{~V}$, VDDE $=3.3 \mathrm{~V}$ ) table. <br> Added a footnote for ANAO-ANA7 $\left({ }^{9}\right)$ functions in the "Signal Properties and Muxing Summary" table. <br> Added a footnote for MDO0-MDO15 $\left({ }^{14}\right)$ and MSEOO functions in the "Signal Properties and Muxing Summary" table. <br> Updated figure numbers $25,27,29$, and 31 : Added specs 1-4. <br> Changed the title of the "PFCPR1 Settings" table to "BIUCR1/BIUCR3". <br> Added a new row "Load" under "Termination" in the "DSPI LVDS Pad Specification" table. <br> Updated the "Max" and "Typical" values of "Delay, Z to Normal", "Rise/Fall Time", and "Data Frequency" in the "DSPI LVDS Pad Specification" table. <br> Changed " $V_{\text {DDE }}$ " to " $V_{\text {DDEH" }}$ in footnote ${ }^{10}$ of the "DC Electrical Specifications" table. <br> Made the following changes in the "DSPI Timing" table: <br> - Update the minimum peripheral bus frequencies for "Data Setup Time for Inputs" and "Data Hold Time for Outputs". <br> - Updated the maximum peripheral bus frequencies for "Data Valid (after SCK edge)". <br> - Added "Master (LVDS)" information for "Data Valid (after SCK edge)" and "Data Hold Time for Outputs". <br> Changed the minimum voltage value of the "I/O Supply Voltage (fast I/O pads)" from "1.62 V" to "3.0 V" in the "DC Electrical Specifications" table. <br> Changed " $\mathrm{V}_{\text {DDE }}$ " values from "1.62 V to 1.98 V " to "3.0 V to 3.6 V " in footnote ${ }^{1}$ of the "Pad AC Specifications ( $\left.\mathrm{V}_{\mathrm{DDEH}}=5.0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DDE}}=3.3 \mathrm{~V}\right)$ " table. <br> Removed voltage ranges "1.62 V-1.98 V" and "2.25 V-2.75 V" from "Fast I/O Weak Pull Up/Down Current" in the "DC Electrical Specifications" table. |

## Revision History

Table 40. Revision History (continued)

| Revision | Date | Description |
| :---: | :---: | :---: |
| Rev 3 | 10 August 2012 | Added minimum and maximum "Nominal bandgap reference voltage" values in the "PMC Electrical Specifications" table. <br> Updated the maximum "Medium I/O Output Low Voltage" value (changed from $0.2 \times \mathrm{V}_{\text {DDEH }}$ to $0.2 \times \mathrm{V}_{\text {DDEH }}$ and $0.15 \times \mathrm{VDDEH}$ ) in the "DC Electrical Specifications" table, moved reference to the footnote ${ }^{10}\left(\mathrm{I}_{\mathrm{OH}} \mathrm{s}=\{11.6\} \mathrm{mA}\right.$ and $\mathrm{I}_{\mathrm{OL} \_\mathrm{S}}=\{17.7\} \mathrm{mA}$ for $\{$ medium $\mathrm{I} / \mathrm{O}$ with $\mathrm{V}_{\text {DDEH }}=4.5 \mathrm{~V}$; $\mathrm{IOH}_{\mathrm{S}}=\{5.4\} \mathrm{mA}$ and $\mathrm{I}_{\mathrm{OL} \text { S }}=\{8.1\} \mathrm{mA}$ for \{medium $\mathrm{I} / \mathrm{O}$ with VDDEH $=3.0 \mathrm{~V})$ to " $0.2 \times \mathrm{V}_{\text {DDEH }}-$ ", and added a new footnote ${ }^{11}(\mathrm{IOL}$ S $=2 \mathrm{~mA})$ to " $0.15 \times \mathrm{V}_{\text {DDEH }}$ ". Updated footnote ${ }^{9}\left(\mathrm{I}_{\mathrm{OH}_{-} \mathrm{F}}=\{12,20,30,40\} \mathrm{mA}\right.$ and $\mathrm{I}_{\mathrm{OL}} \mathrm{F}=\{24,40,50,65\} \mathrm{mA}$ for $\{00,01,10,11\}$ drive mode with $\mathrm{V}_{\text {DDE }}=3.0 \mathrm{~V}$ ): Removed " $\mathrm{IOH}_{-F}=\{7,13,18,25\} \mathrm{mA}$ and $\mathrm{I}_{\text {OL_F }}=\{18,30,35,50\} \mathrm{mA}$ for $\{00,01,10,11\}$ drive mode with $\bar{V}_{\text {DDE }}=2.25 \mathrm{~V}$; <br> $\mathrm{I}_{\mathrm{OH}=\mathrm{F}}=\{3,7,10,16\} \mathrm{mA}$ and $\mathrm{I}_{\mathrm{OL}-\mathrm{F}}=\{12,20,27,35\} \mathrm{mA}$ for $\{00,01,10,11\}$ drive mode with $V_{D D E}=1.62 \mathrm{~V}^{\prime \prime}$. <br> Added minimum and maximum values to all rows of the "Power Management Control (PMC) Specification" table. <br> Updated the "Accuracy" temperature values in the "Temperature Sensor Electrical Specifications" table: Changed "-40 C to 100 C to 40 C to 150 C, removed the correspnding "Typ" value, removed "100 C to 150 C, and added minimum (10) and maximum ( +10 ) values. <br> Added a new section "ADC Internal Resource Measurements" and moved "Power Management Control (PMC) Specification", "Standby RAM Regulator Electrical Specifications", "ADC Band Gap Reference / LVI Electrical Specifications", and "Temperature Sensor Electrical Specifications" tables to the section. <br> Changed "Minimum Data Retention at $25^{\circ} \mathrm{C}$ ambient temperature" to "Minimum Data Retention at $85^{\circ} \mathrm{C}$ ambient temperature" in the "Flash EEPROM Module Life" table. <br> Added the following note after "Flash Program and Erase Specifications (Pending Si characterization)" table in the "C90 Flash Memory Electrical Characteristics" section: "The low, mid, and high address blocks of the flash arrays are erased (all bits set to 1) before leaving the factory. <br> Updated the "DSPI LVDS Pad Specification" table: Changed maximum "Load" value from " 25 " to " 32 "; minimum values for "Differential Output Voltage SRC=0b00 or 0b11, SRC=0b01, SRC=0b10" from "150, 90, 160" to "215, 170, 260"; "Transmission lines (Differential) to "Termination Resistance"; "Zc" to "RLoad"; and added the following footnote: "The termination resistance spec is not meant to specify the receiver termination requirements. They are there to establish the measurement criteria for the specs in this table. As per the TIA/EIA-644A standard, the LVDS receiver termination resistance can vary from 90 to $132 \Omega$. |
| Rev 4 | 21 January 2016 | Added a table "Flash Memory AC Timing Specifications". Updated the min and max values from -10 and +10 to -20 and +20 for "Accuracy" in the "Temperature Sensor Electrical Specifications" table. |

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[^0]:    1 Typical endurance is evaluated at $25^{\circ} \mathrm{C}$. Product qualification is performed to the minimum specification. For additional information on the NXP definition of Typical Endurance, please refer to Engineering Bulletin EB619, Typical Endurance for Nonvolatile Memory.
    2 Ambient temperature averaged over duration of application, not to exceed product operating temperature range.

[^1]:    ${ }^{11}$ Nexus reset is different than system reset; MDOO-11 are enabled in RPM or FPM trace modes, while MDO12-15 are enabled in FPM trace mode only. MSEO and MCKO are also dependent on trace (RPM or FPM) being enabled.
    ${ }^{12}$ The Nexus pins don't have a "primary" function as they are not configured by the SIU. The pins are selected by asserting JCOMP and configuring the NPC. SIU values have no effect on the function of these pins once enabled.
    ${ }^{13}$ MCKO is disabled from reset; it can be enabled from the tool (controlled by Nexus NPC_PCR register).
    ${ }^{14}$ Do not connect pin directly to a power supply or ground.
    ${ }^{15}$ While JCOMP is negated, the MDOO pad is pulled up because of the default values in its SIU PCR. When JCOMP is asserted, the MDOO pad is enabled as an output and goes low when the system clock is present.

